

X-RAY MIRROR POINT SPREAD FUNCTION COMPUTATION: IMPACT OF DIFFERENT SPATIAL WAVELENGTHS

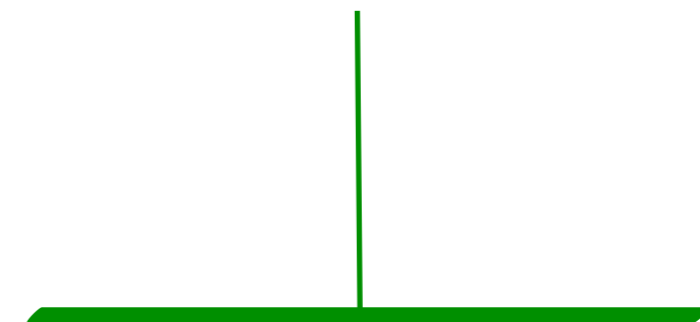
**Lorenzo Raimondi
& Daniele Spiga**

**Università degli Studi dell'Insubria
Osservatorio Astronomico di Brera**

PSF WITH FRESNEL DIFFRACTION

- ✦ PSF computation from surface metrology (not only HEW)
- ✦ At any energy
- ✦ Without any separation between figure errors and microroughness

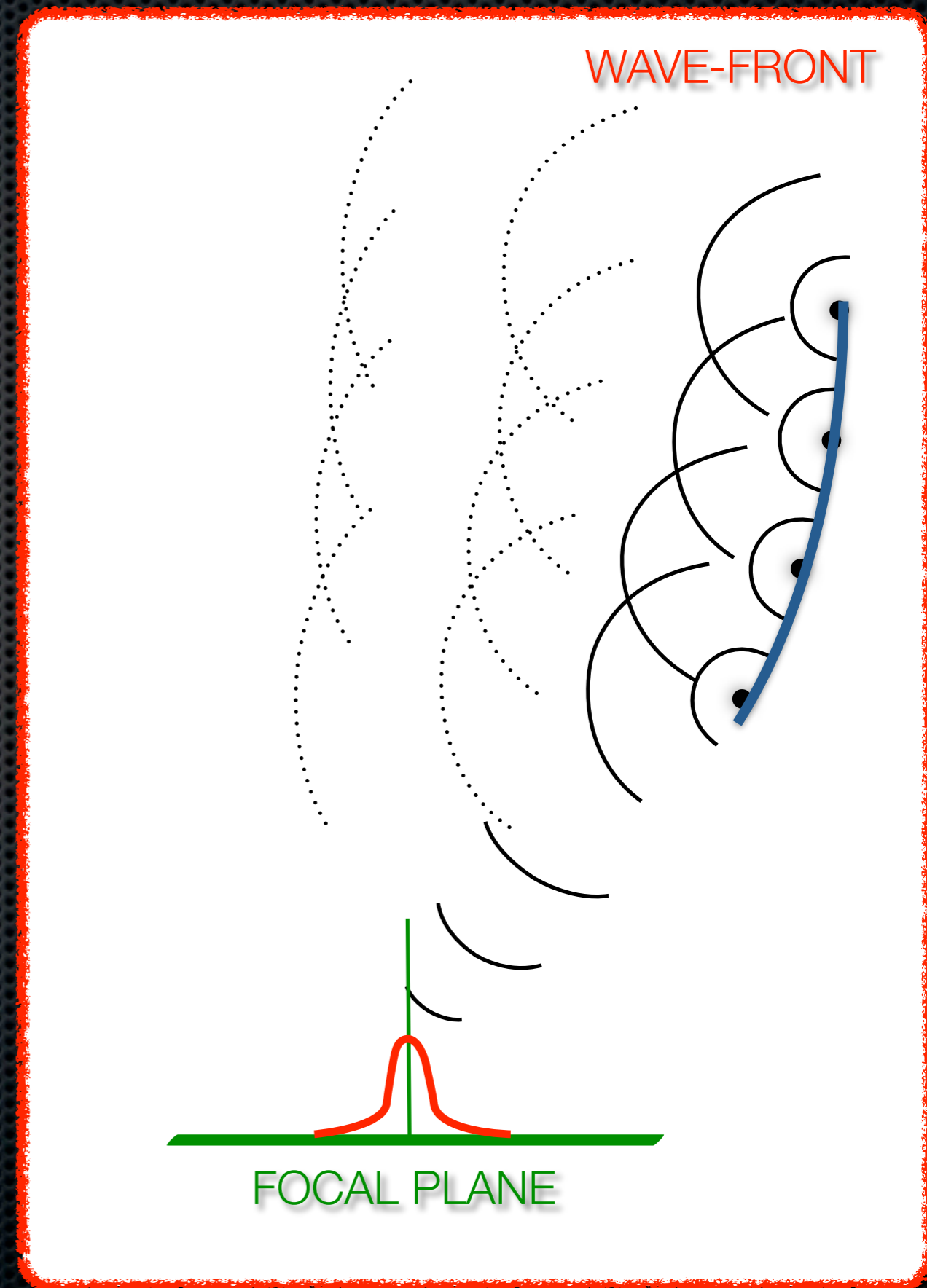
WAVE-FRONT



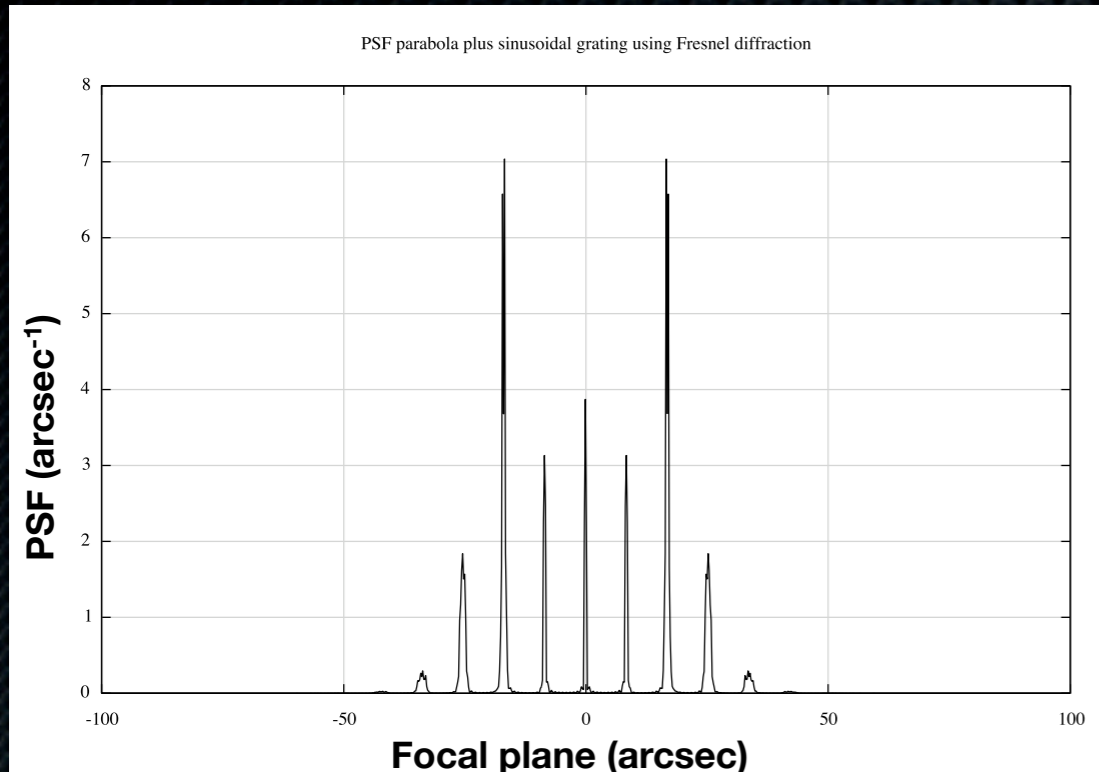
FOCAL PLANE

PSF WITH FRESNEL DIFFRACTION

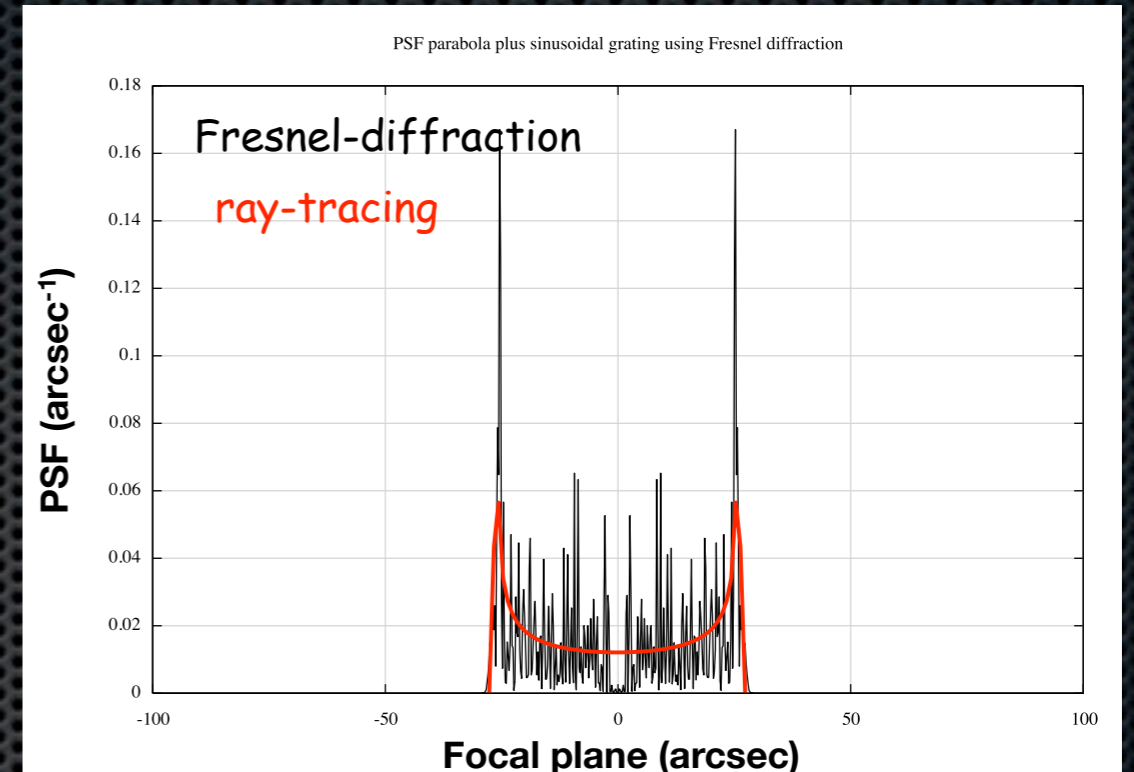
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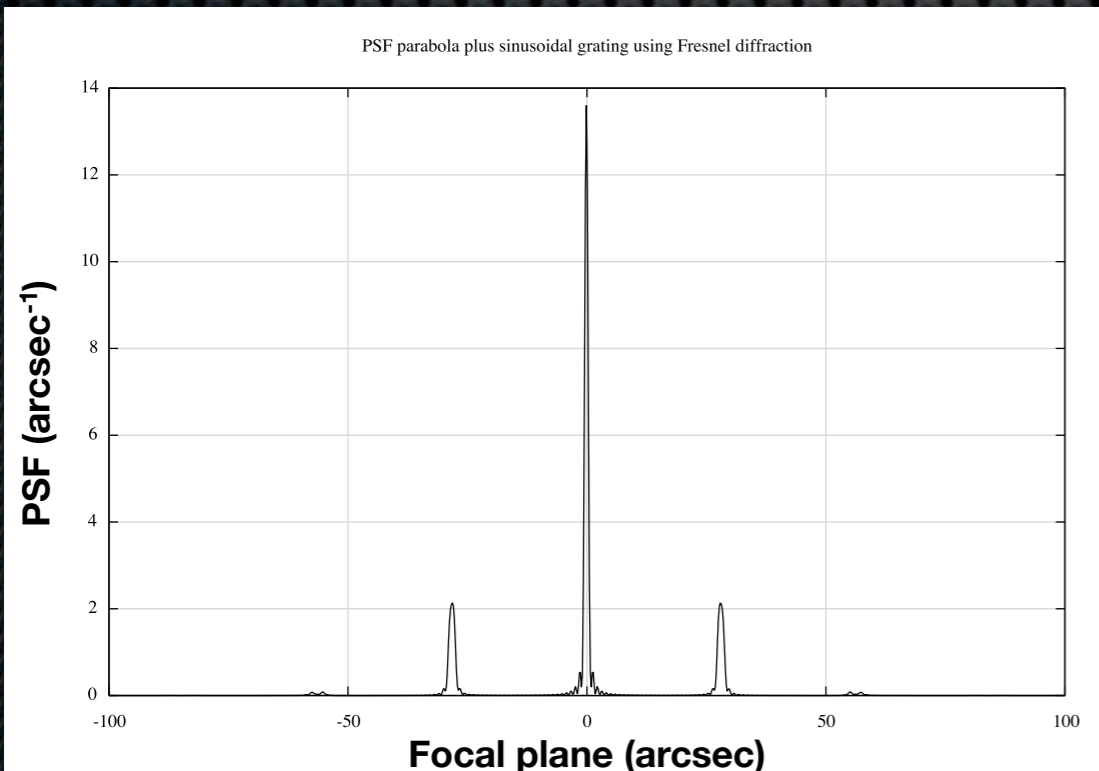
SCATTERING: SINUSOIDAL GRATING



$\lambda = 30 \text{ \AA}$



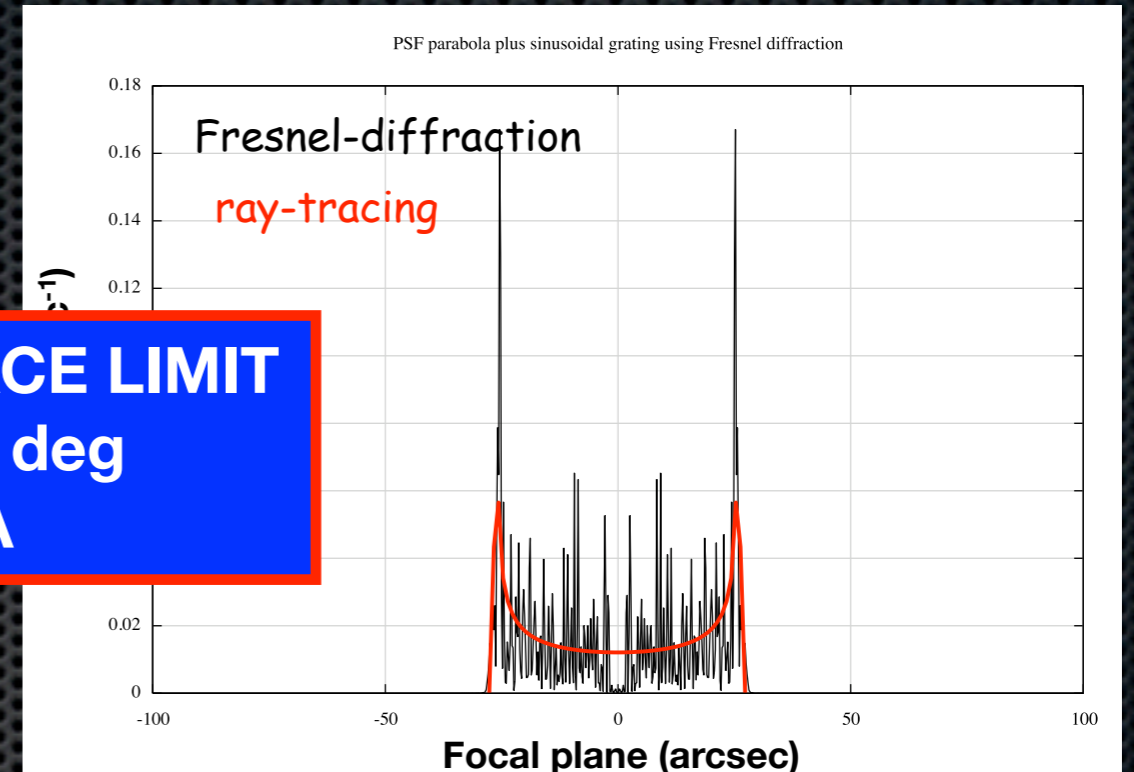
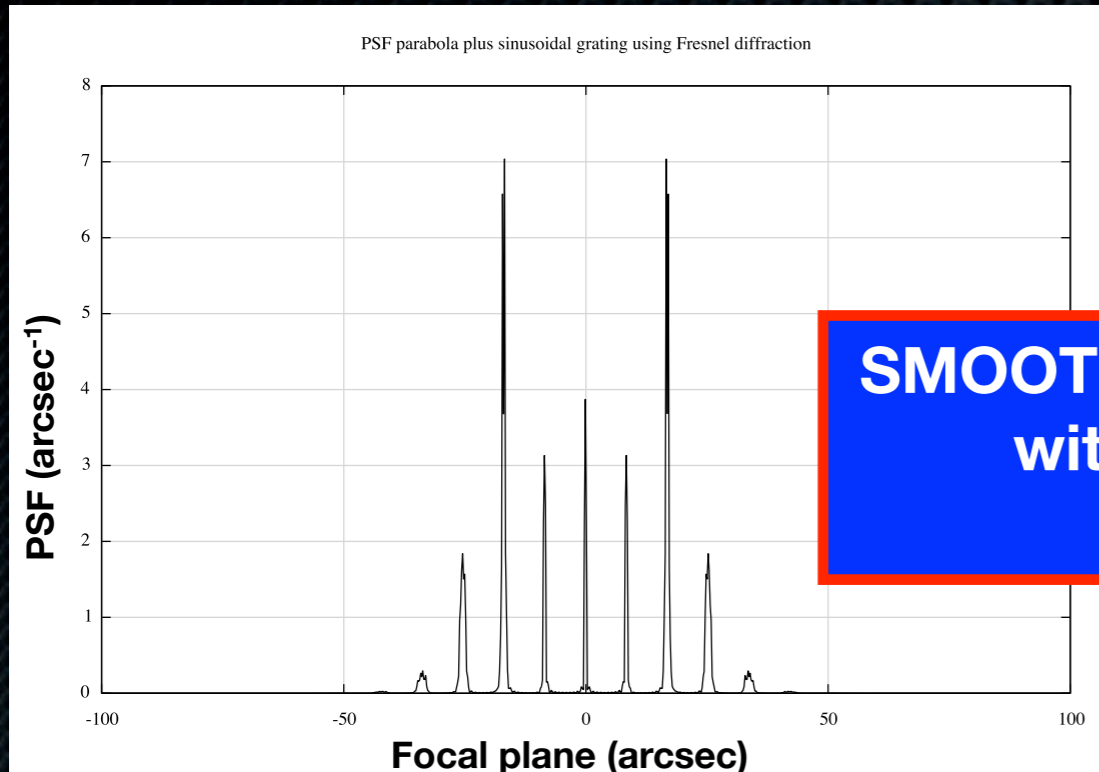
$\lambda = 1 \text{ \AA}$ Vs. ray-tracing



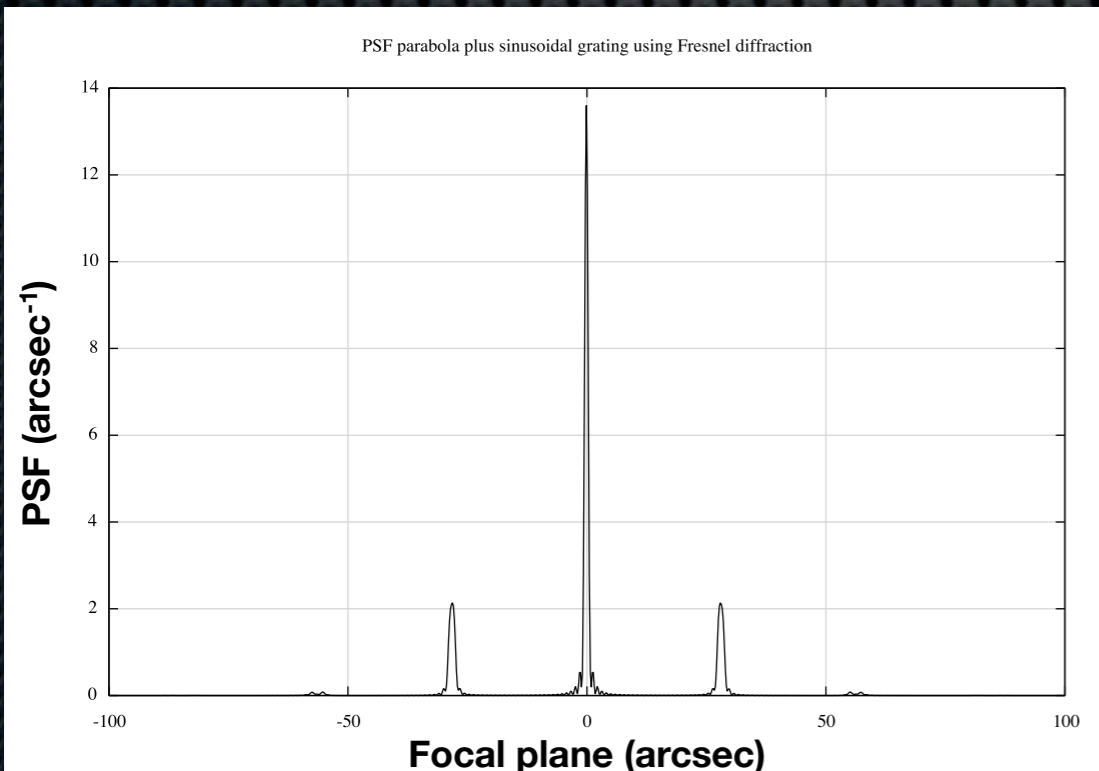
$\lambda = 100 \text{ \AA}$

- ✦ SINUSOIDAL GRATING:
 $I = A \sin(2\pi X/\Phi)$ where $A = 0.1 \text{ \mu m}$ $\Phi = 1 \text{ cm}$
- ✦ PREDICTED PEAK POSITIONS:
 $\Phi = N \lambda / (\cos\theta_i - \cos\theta_s)$
- ✦ PREDICTED PEAK HEIGHTS:
 $I = J_N^2[(2\pi A/\lambda)(\sin\theta_i + \sin\theta_s)]$

SCATTERING: SINUSOIDAL GRATING

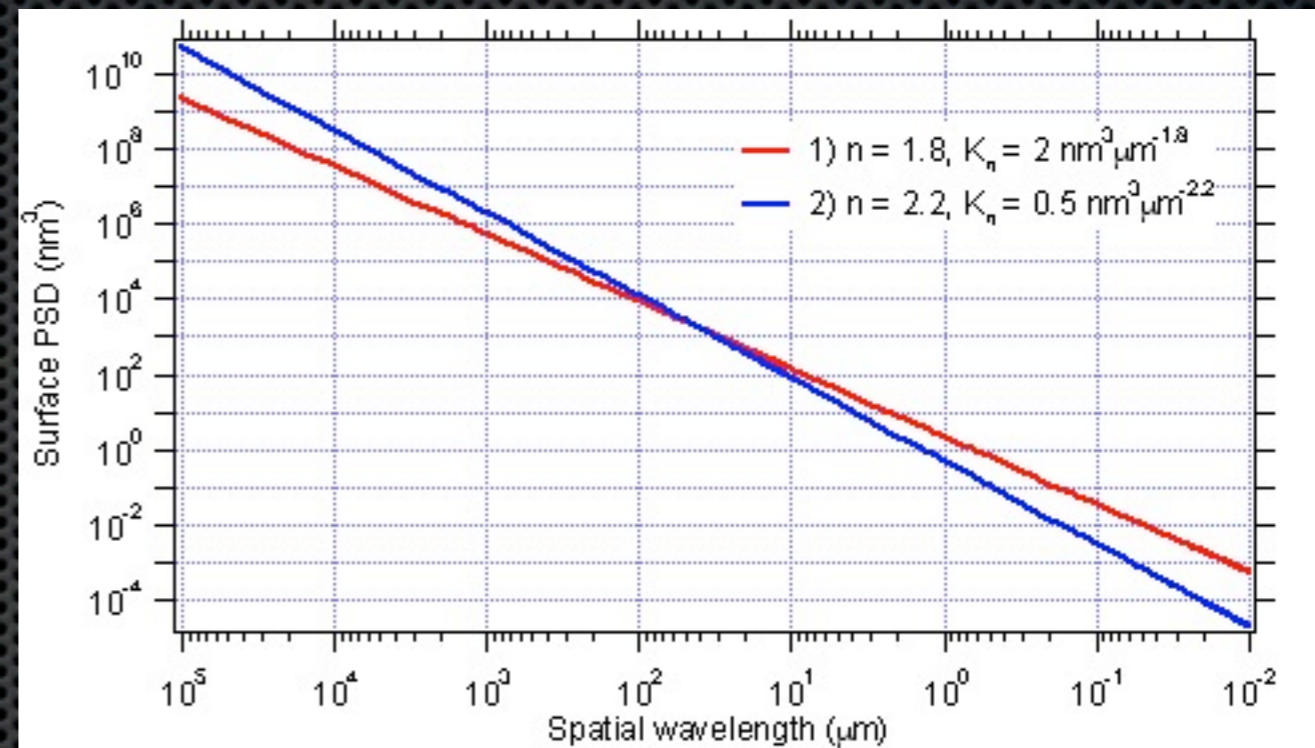
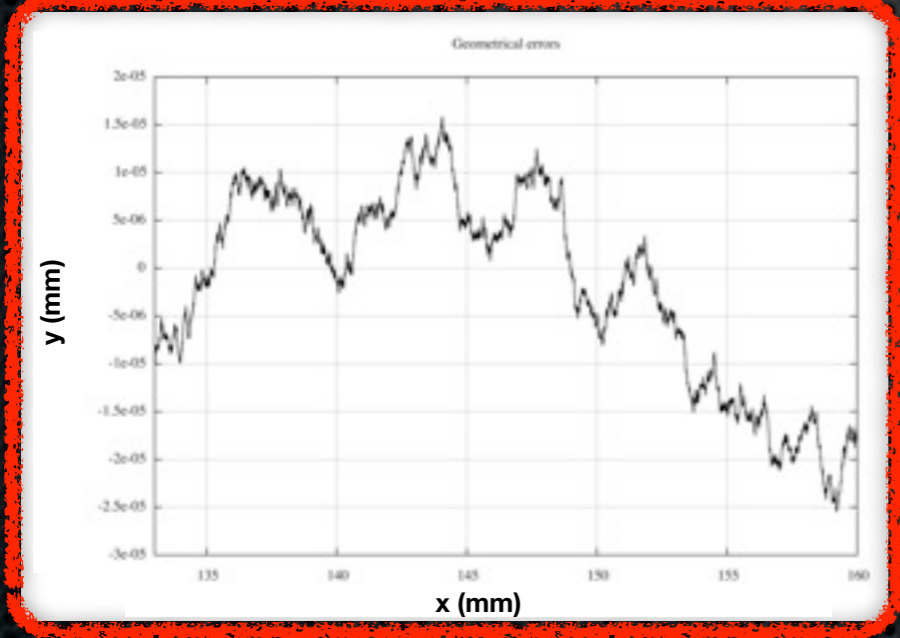
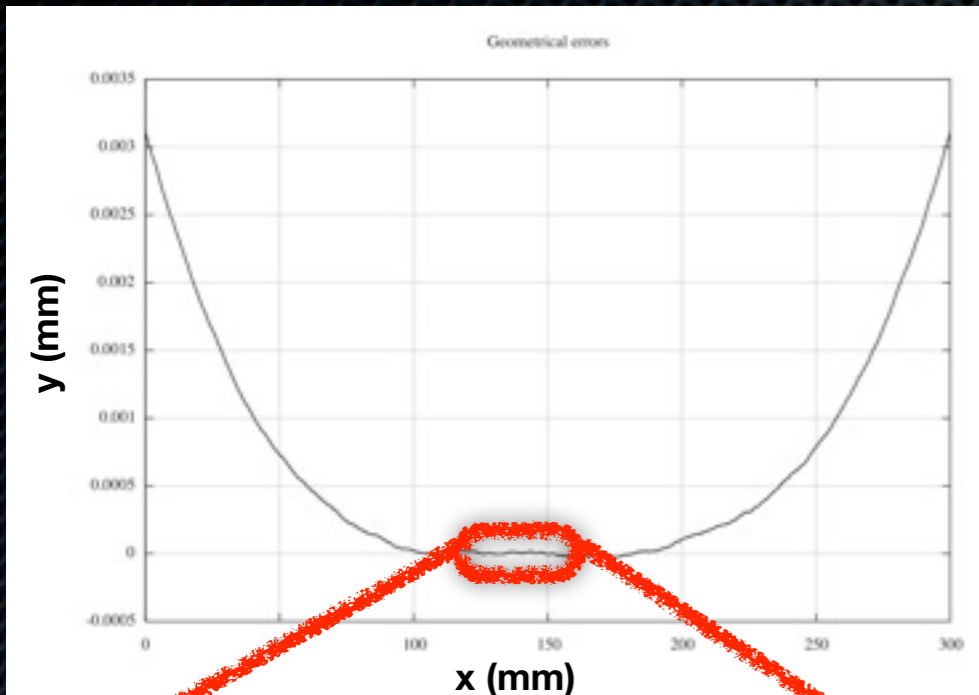


SMOOTH SURFACE LIMIT
with $\alpha = 0.4 \text{ deg}$
 $\lambda > 62 \text{ \AA}$



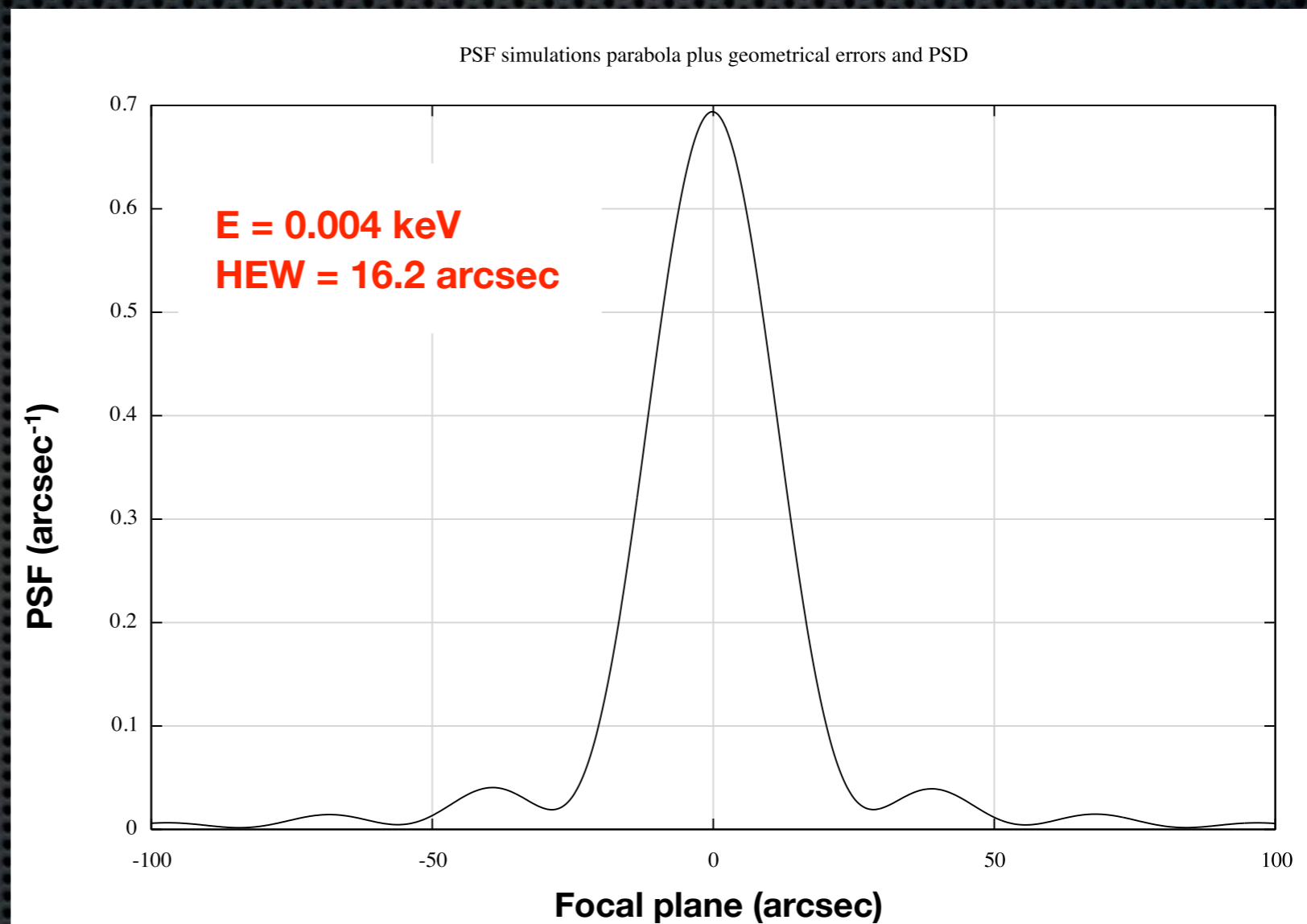
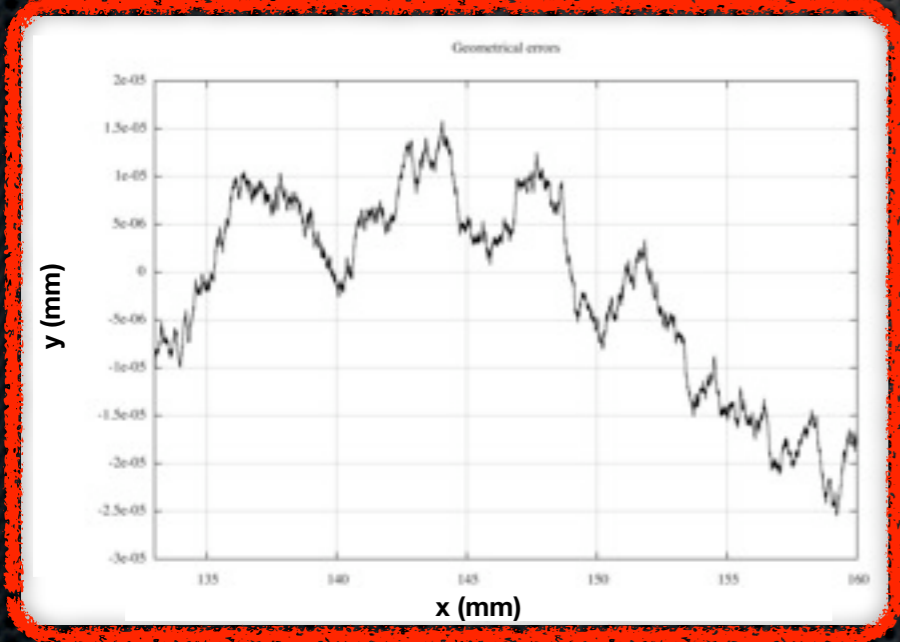
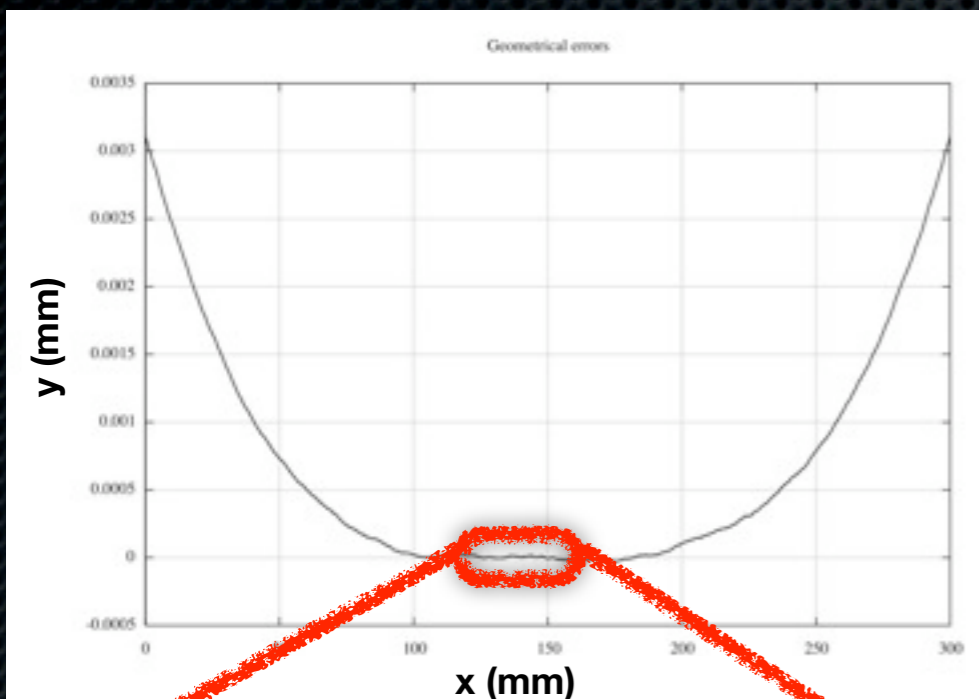
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PSF COMPUTATION FOR A TYPICAL MIRROR PROFILE

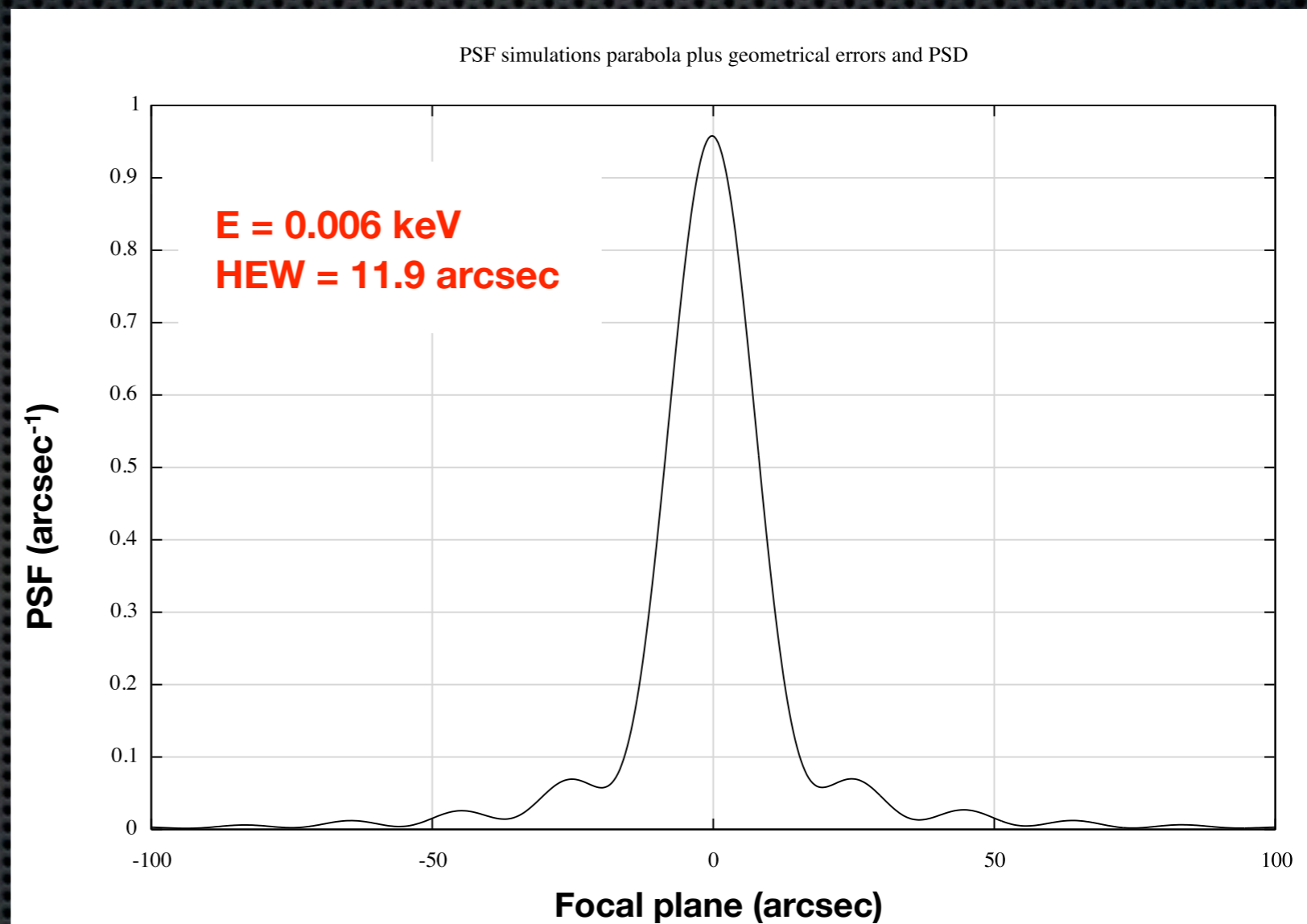
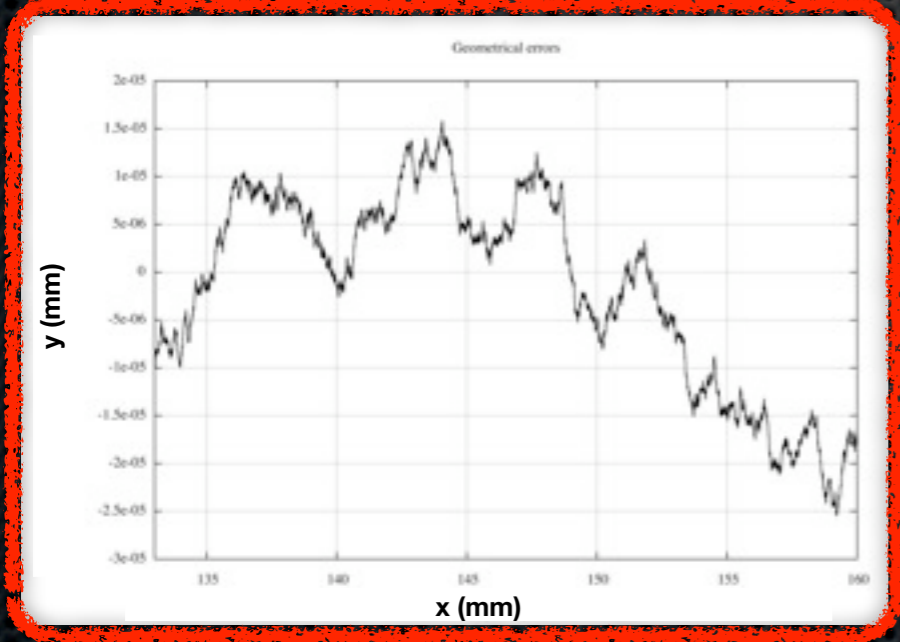
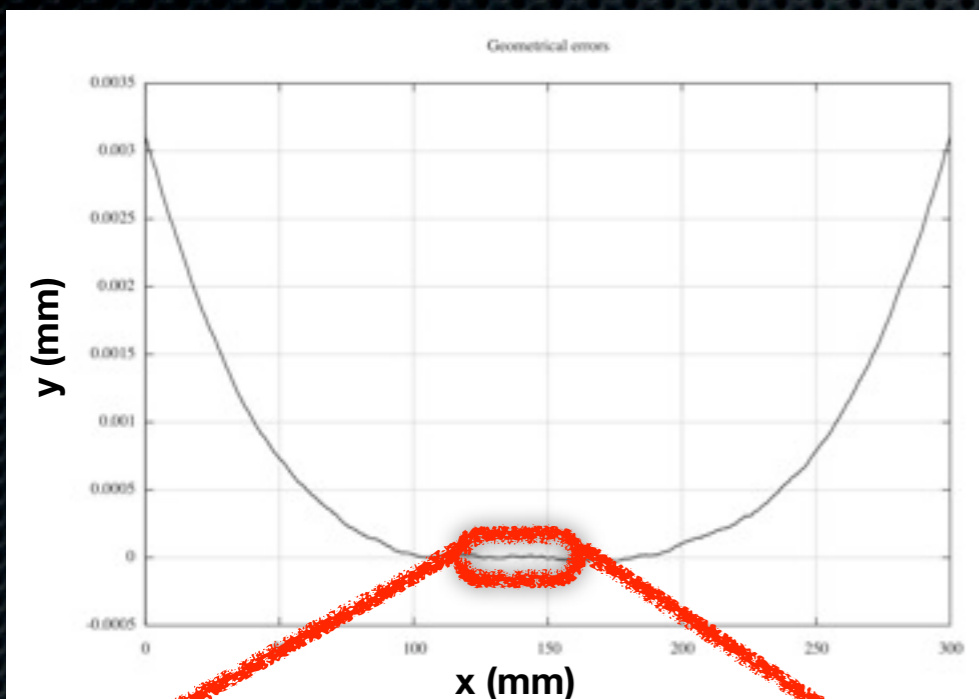


$$\text{PSD} = K_n / f^n$$

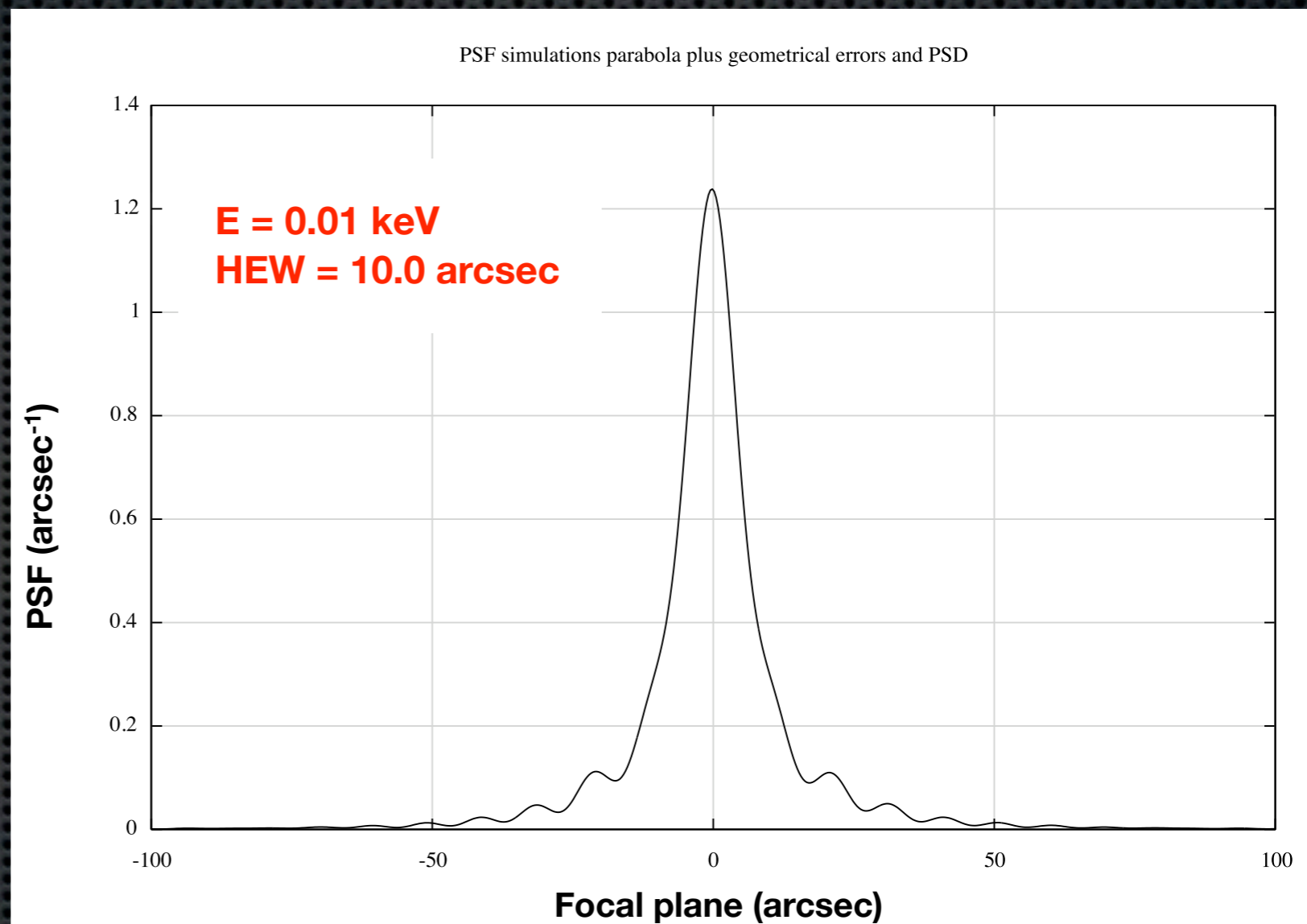
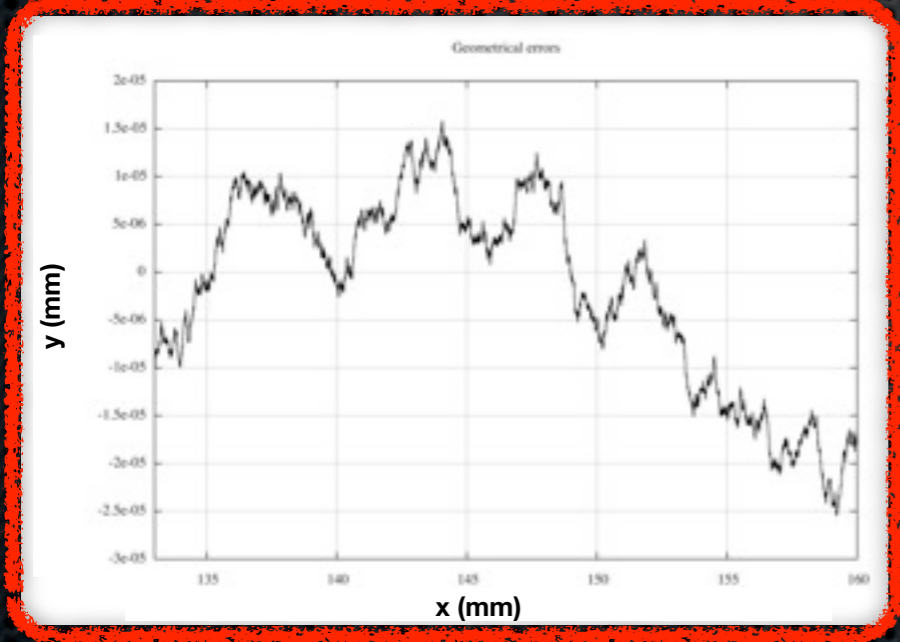
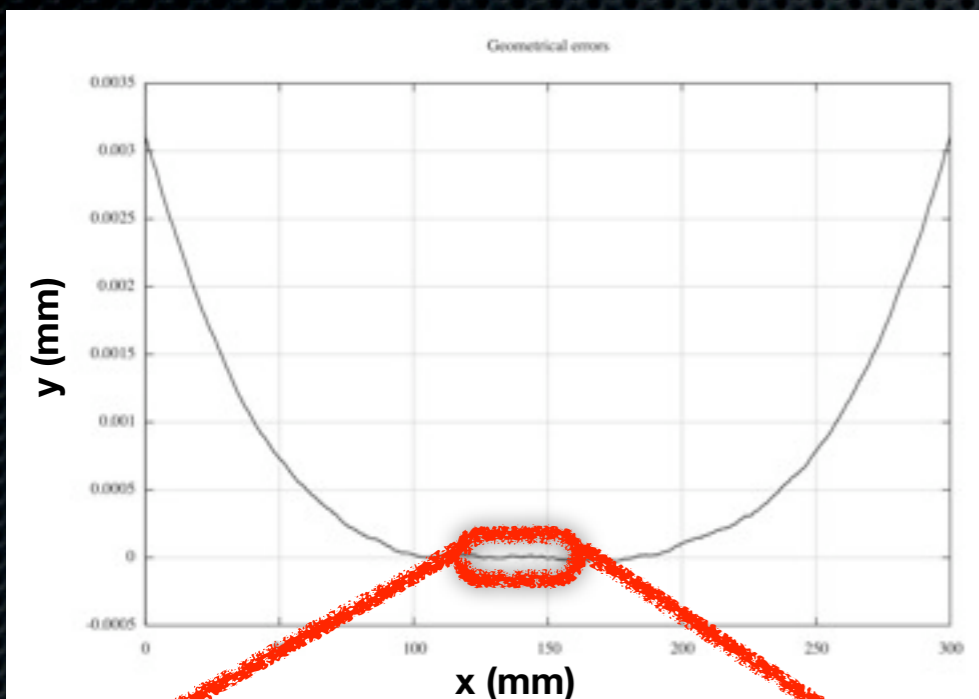
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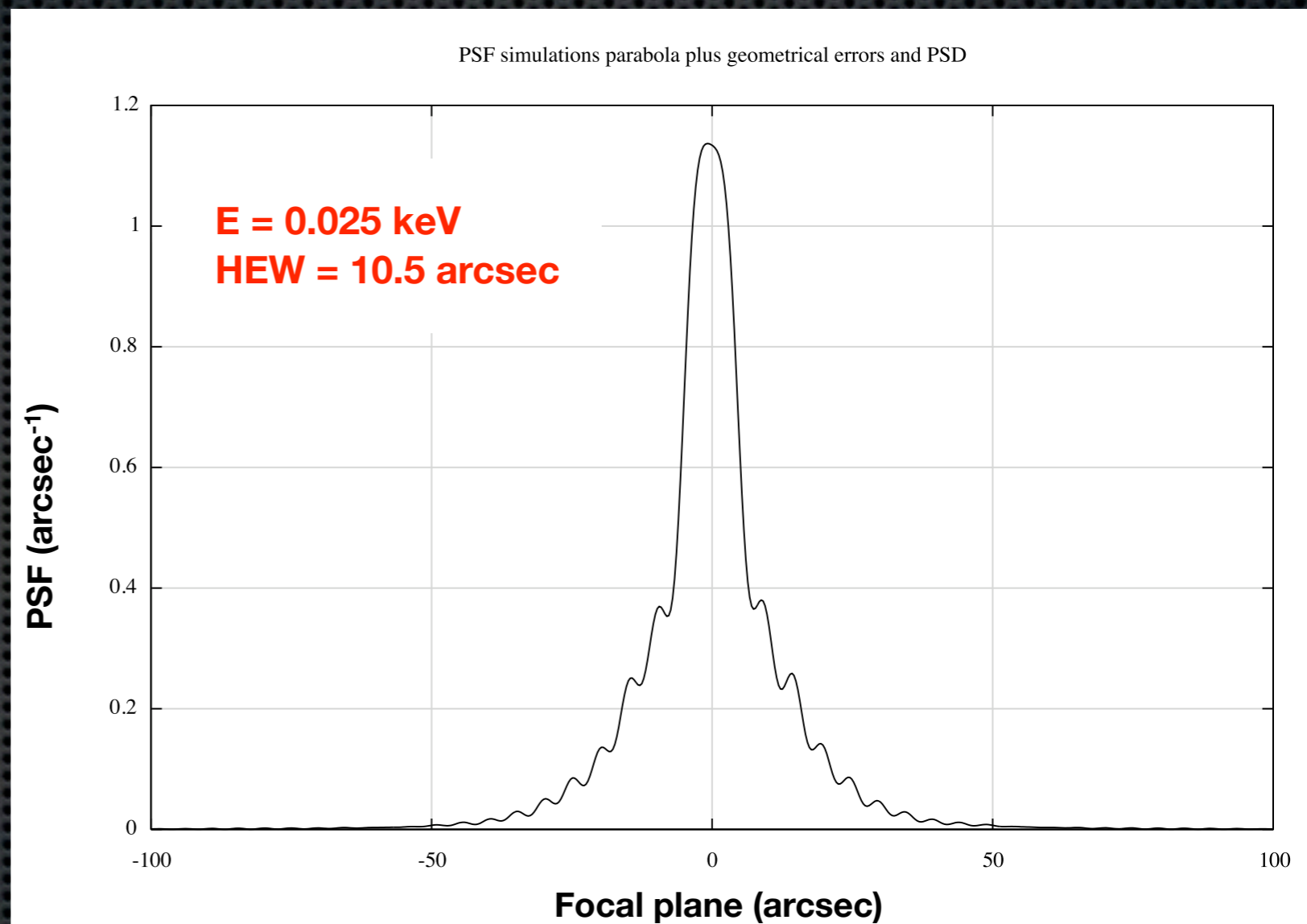
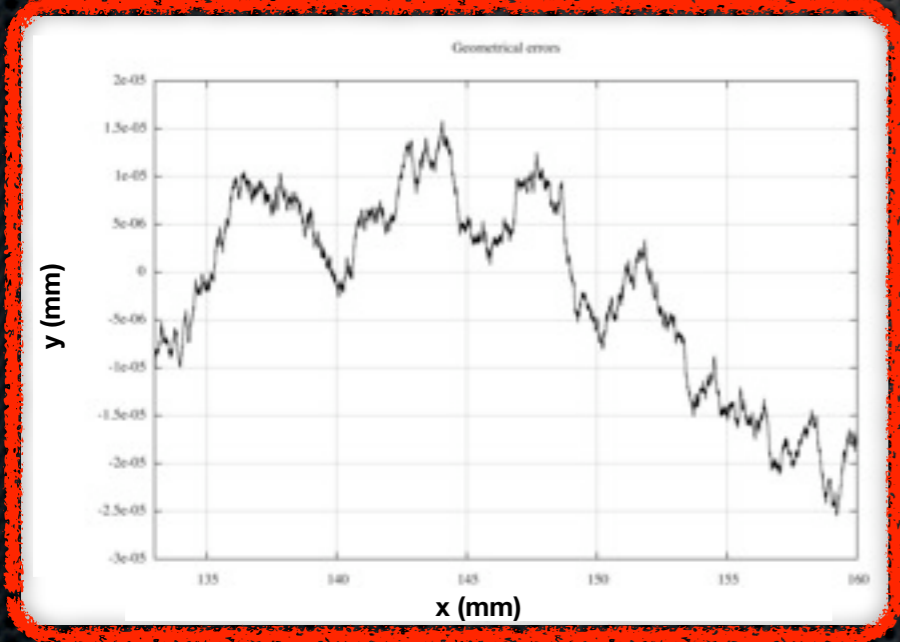
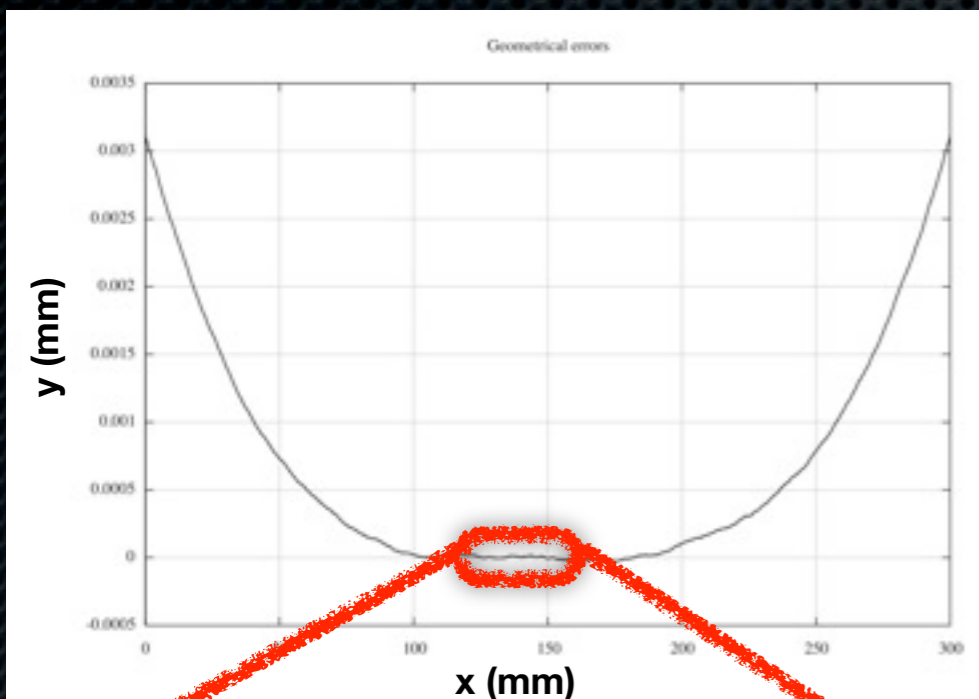
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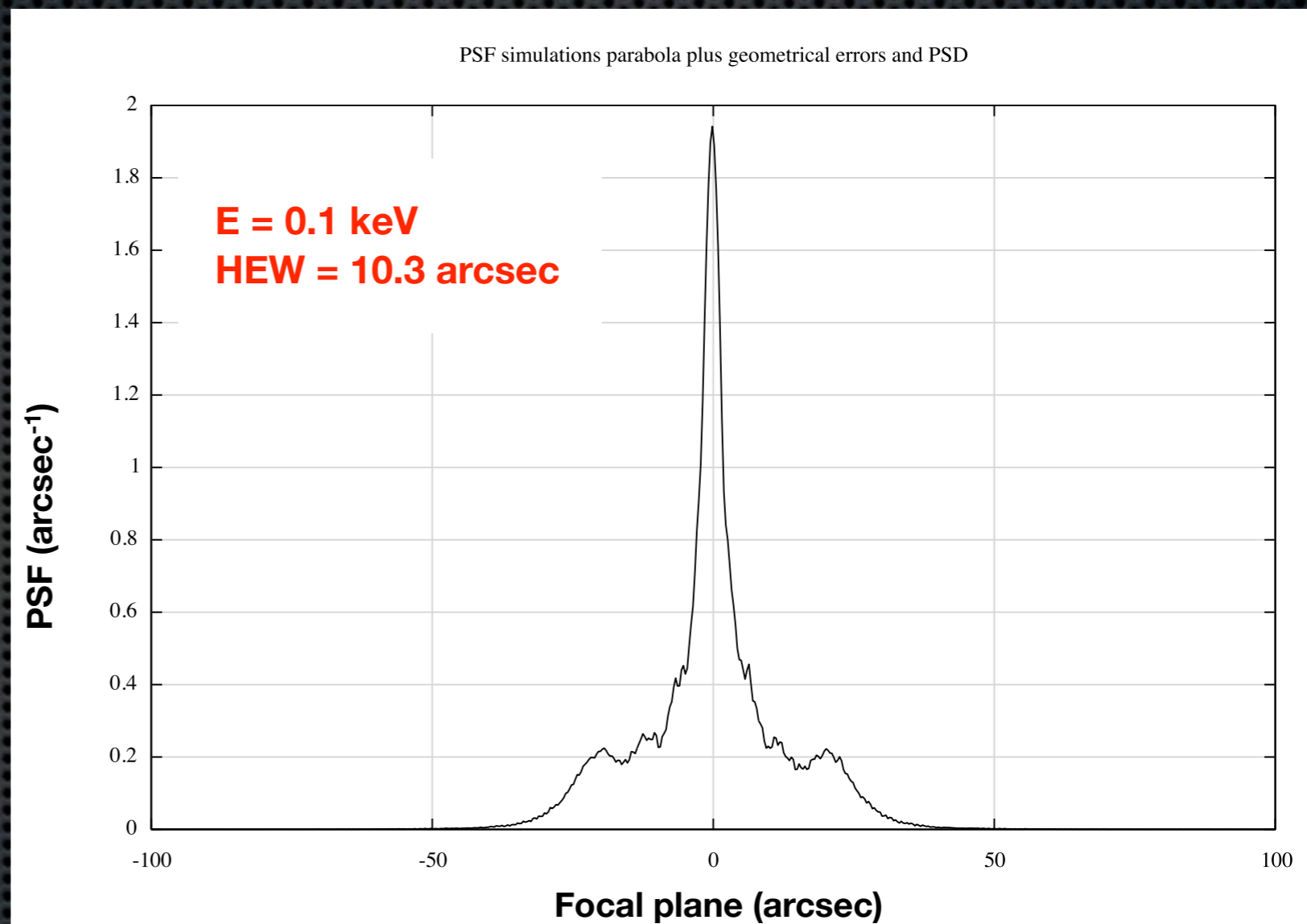
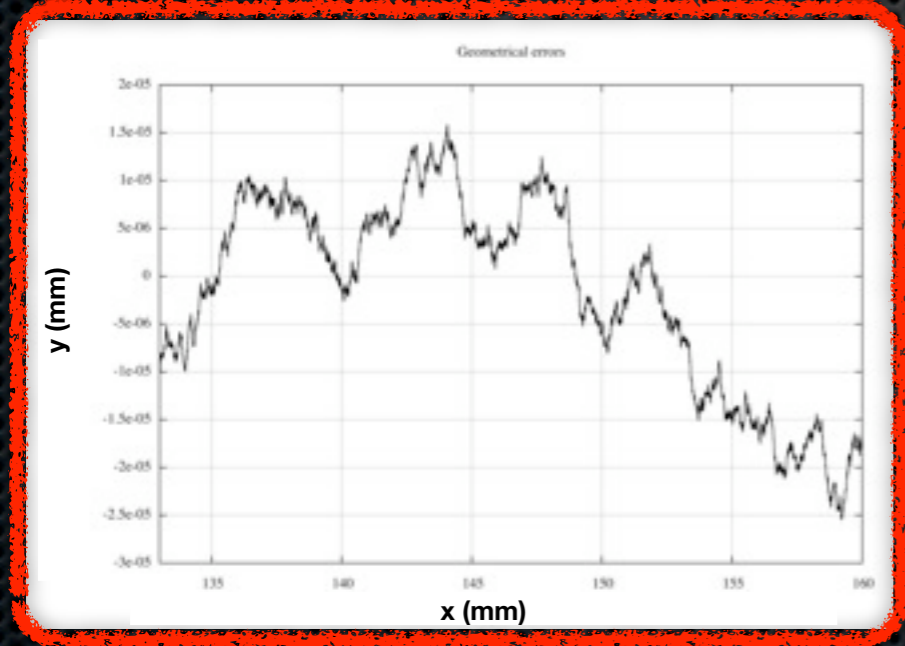
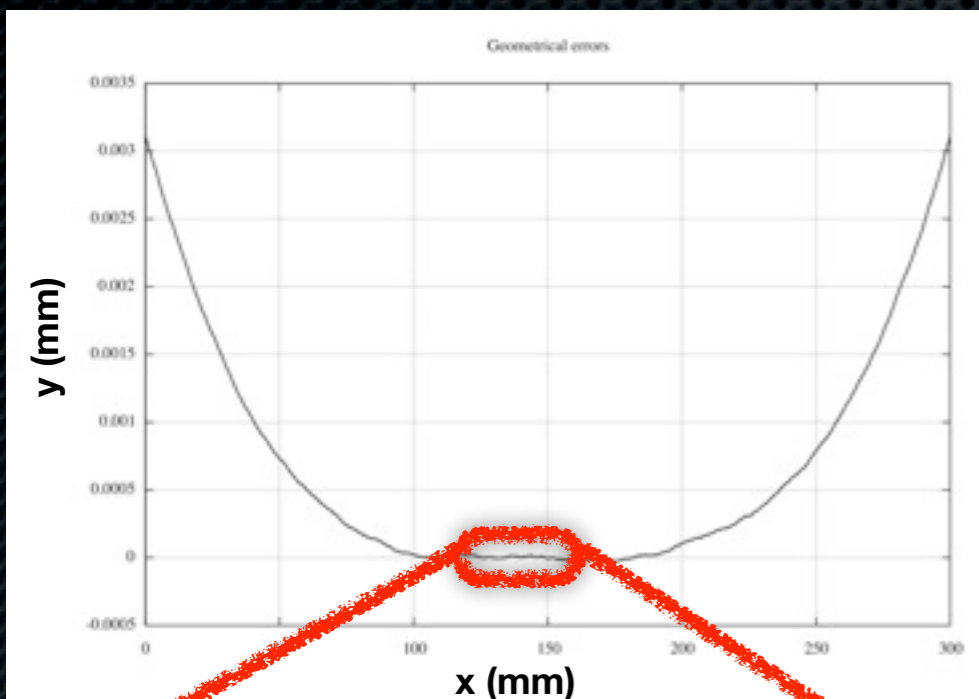
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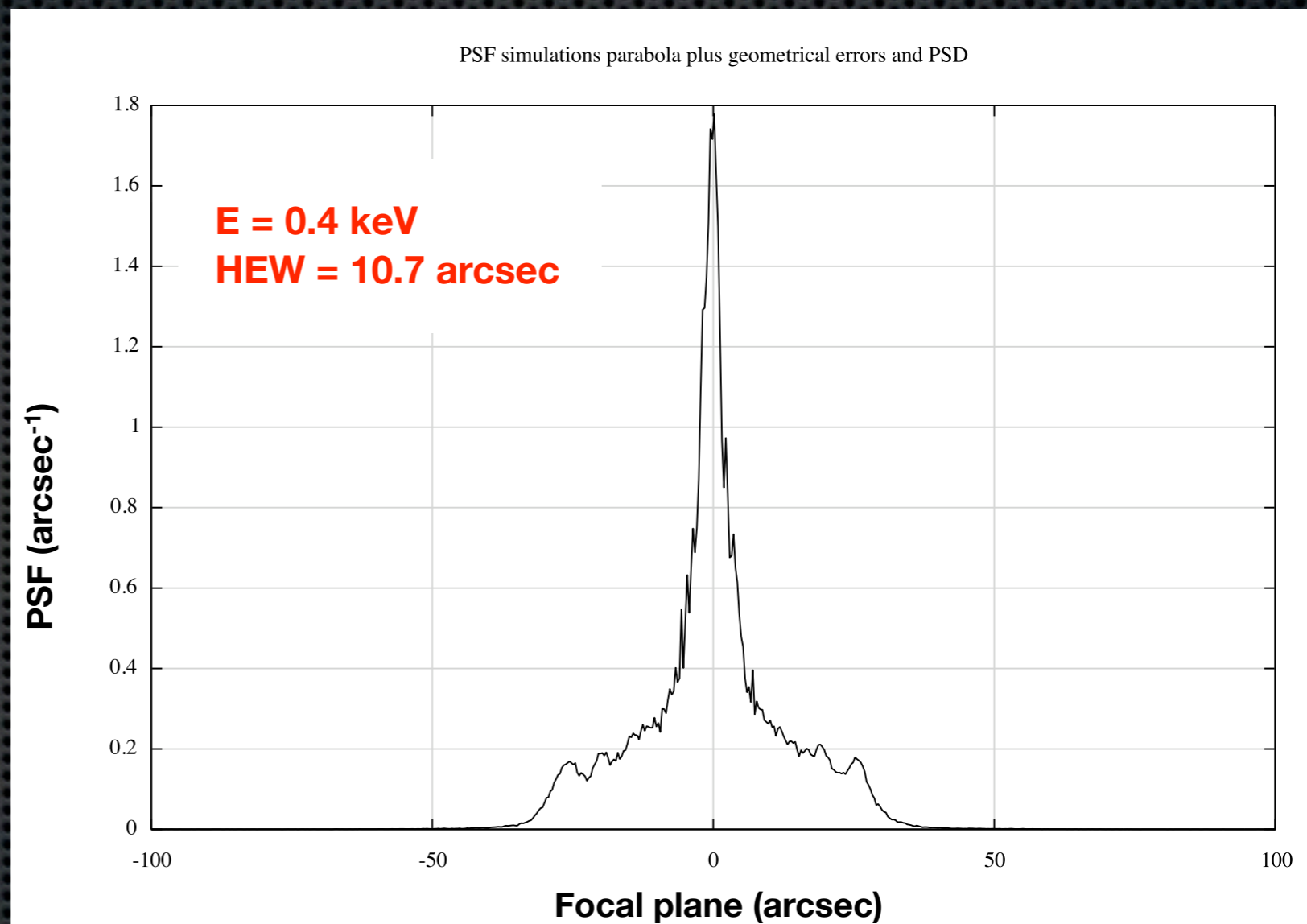
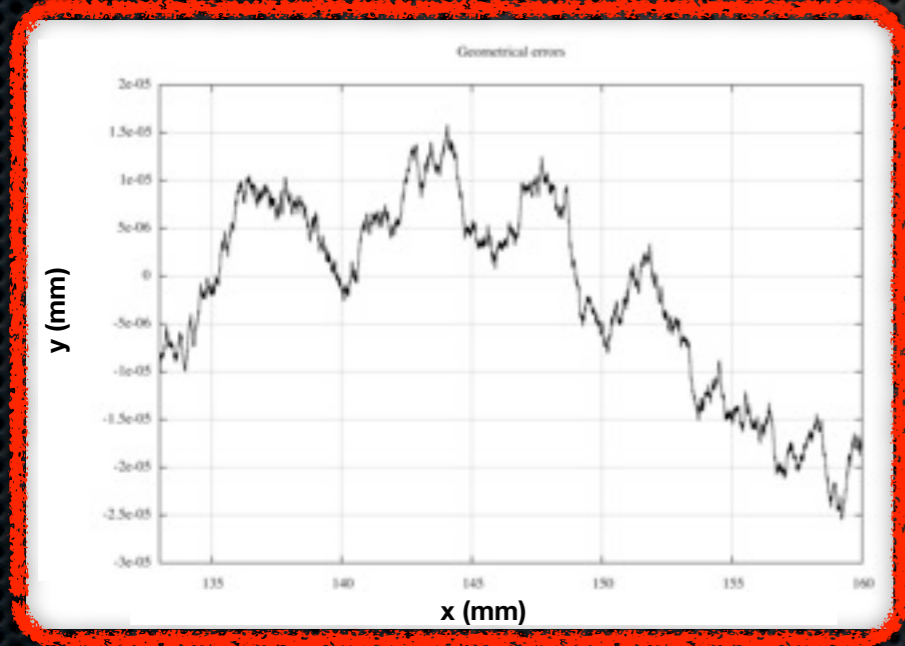
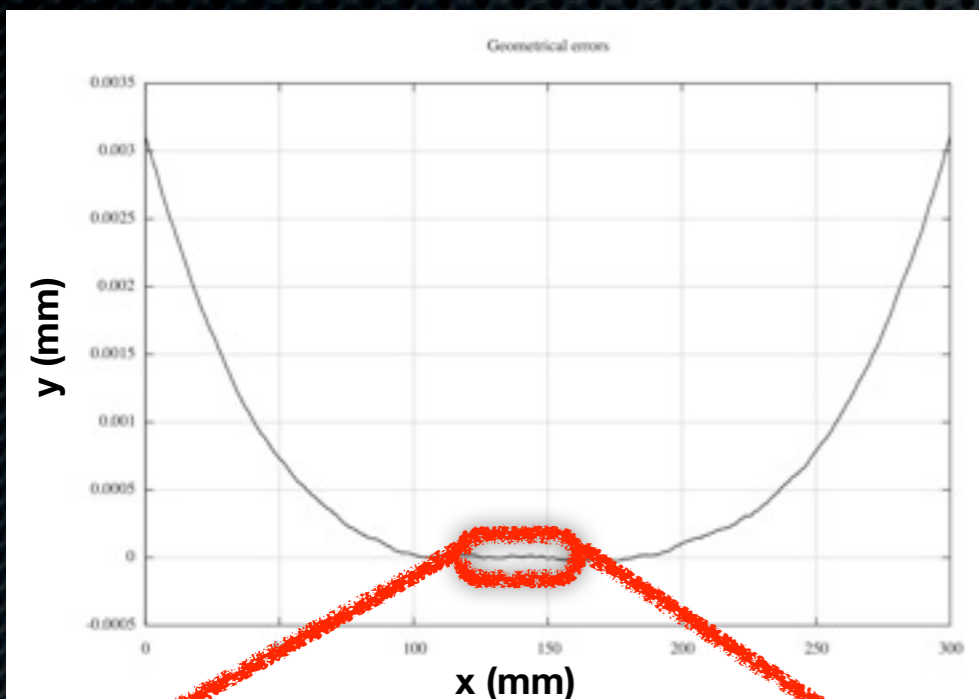
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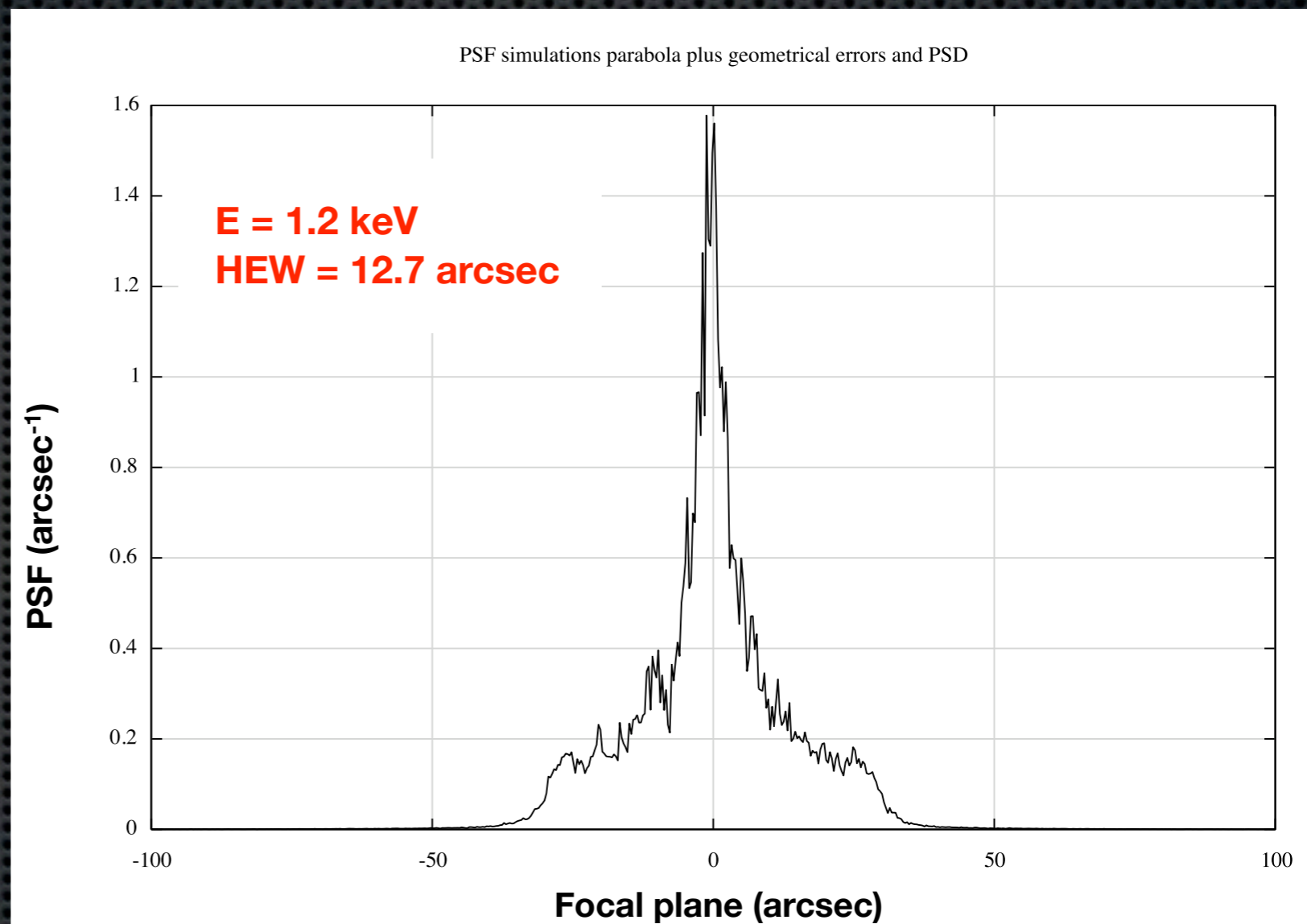
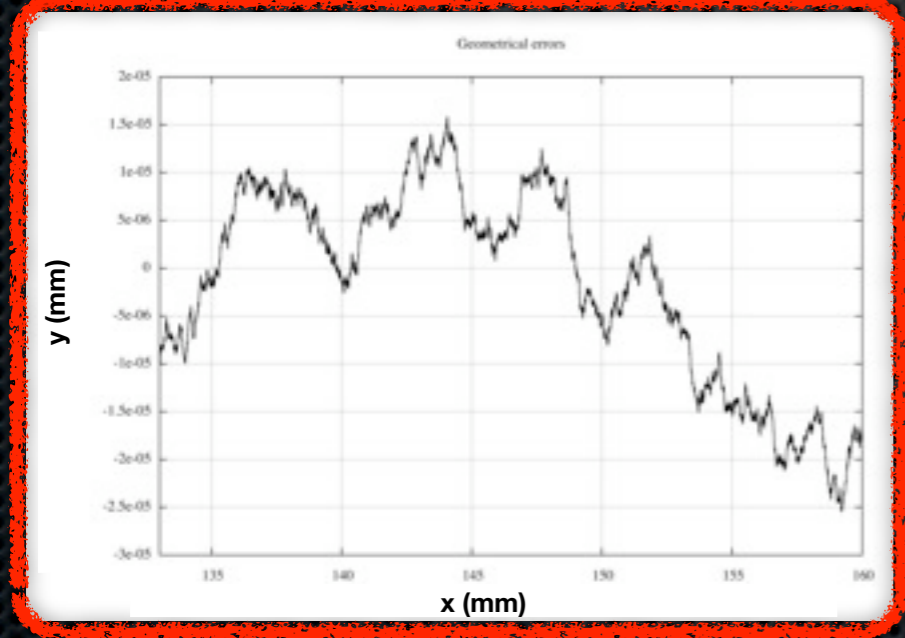
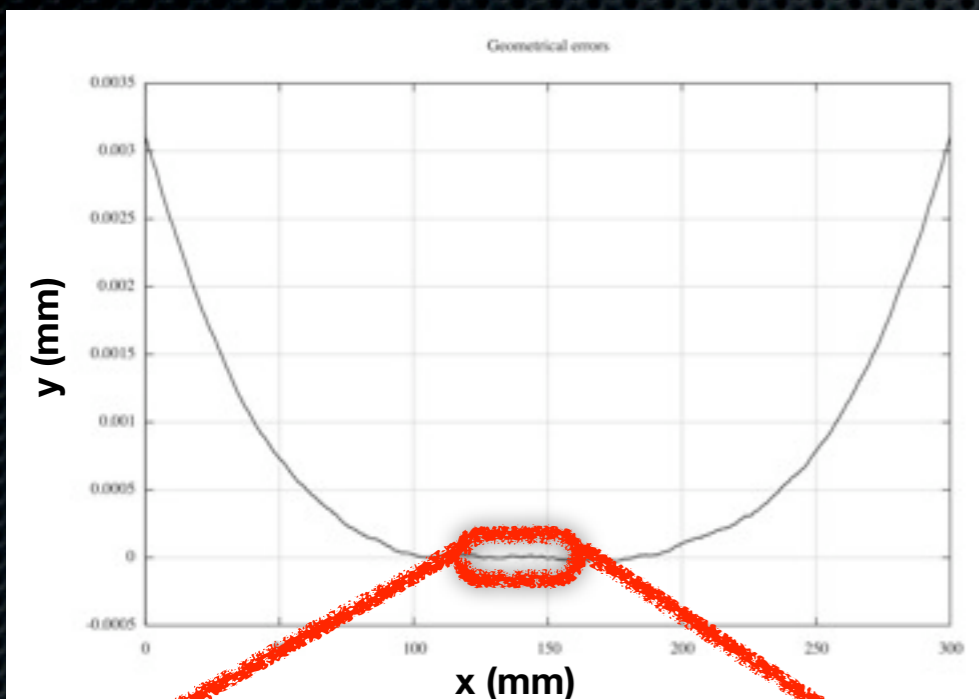
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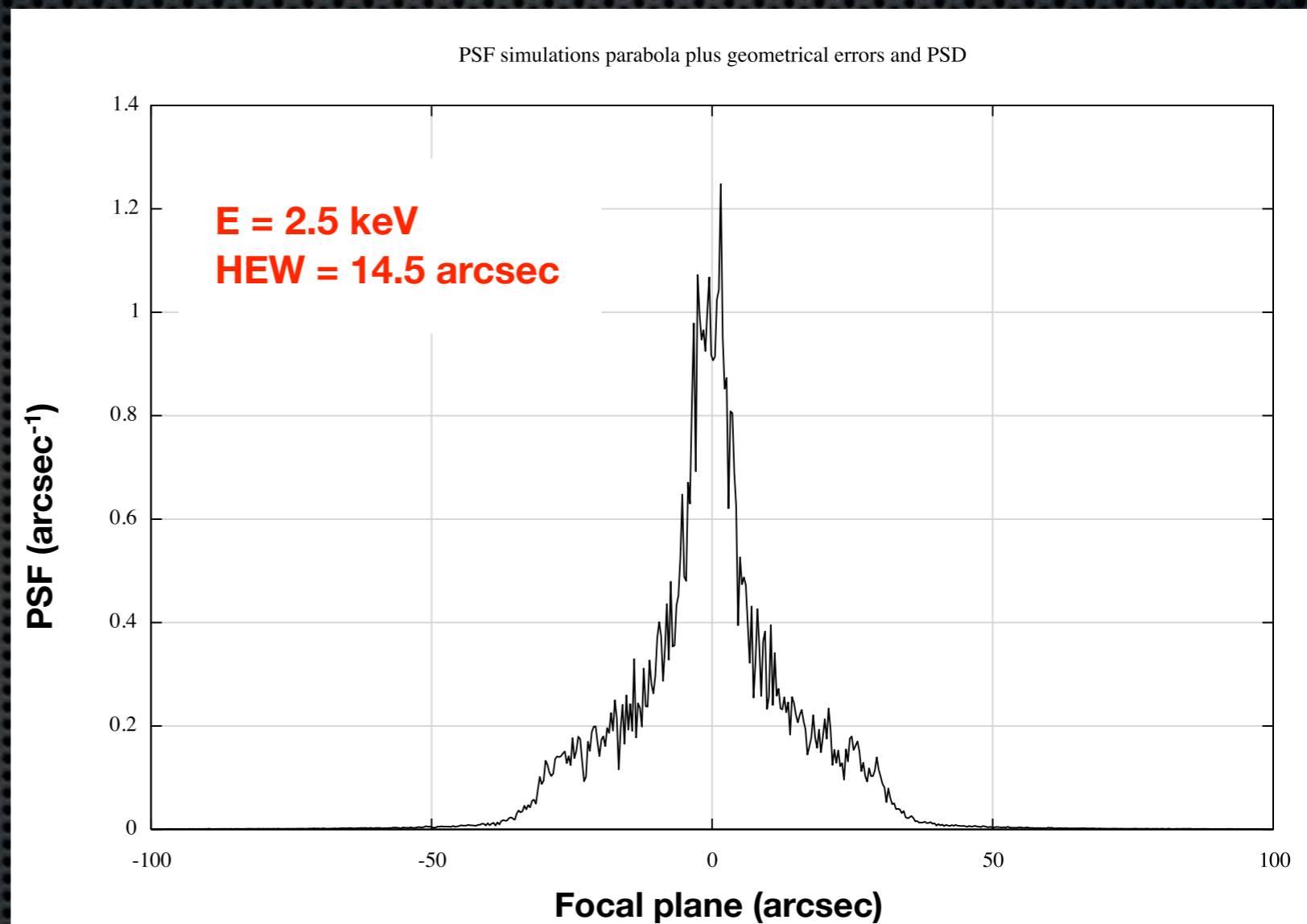
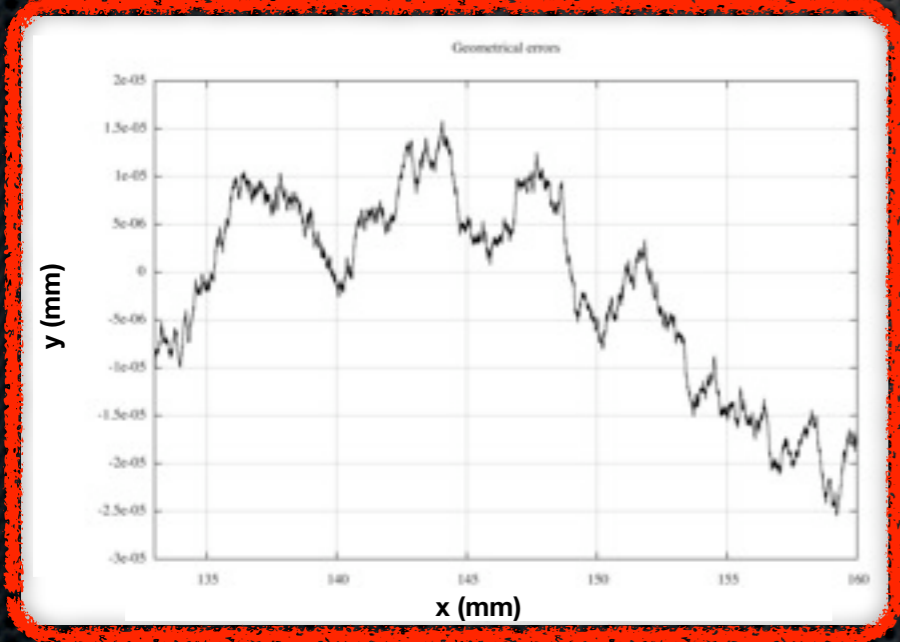
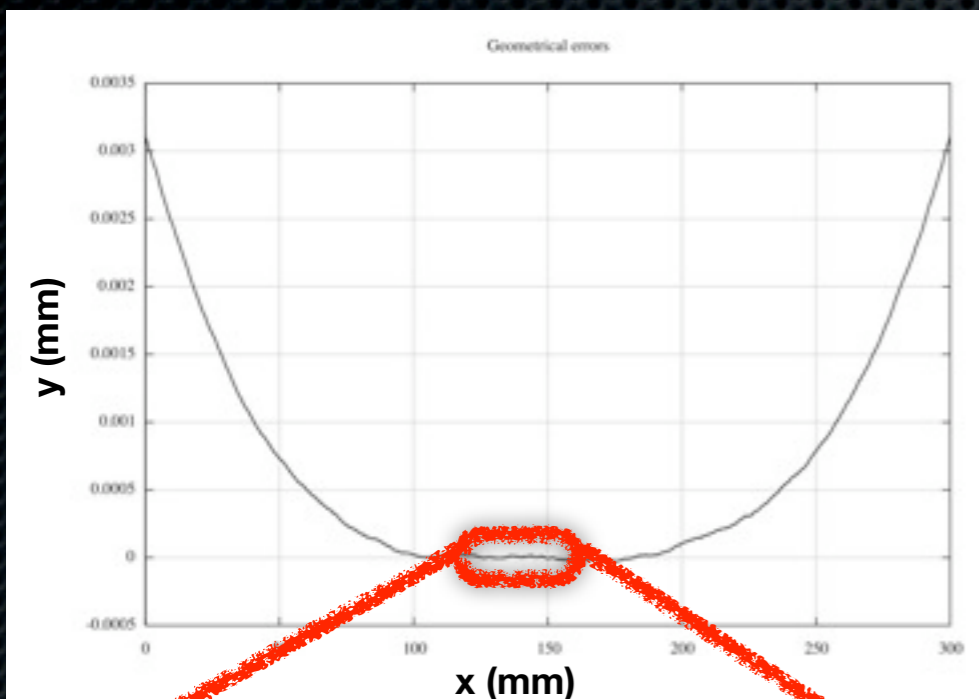
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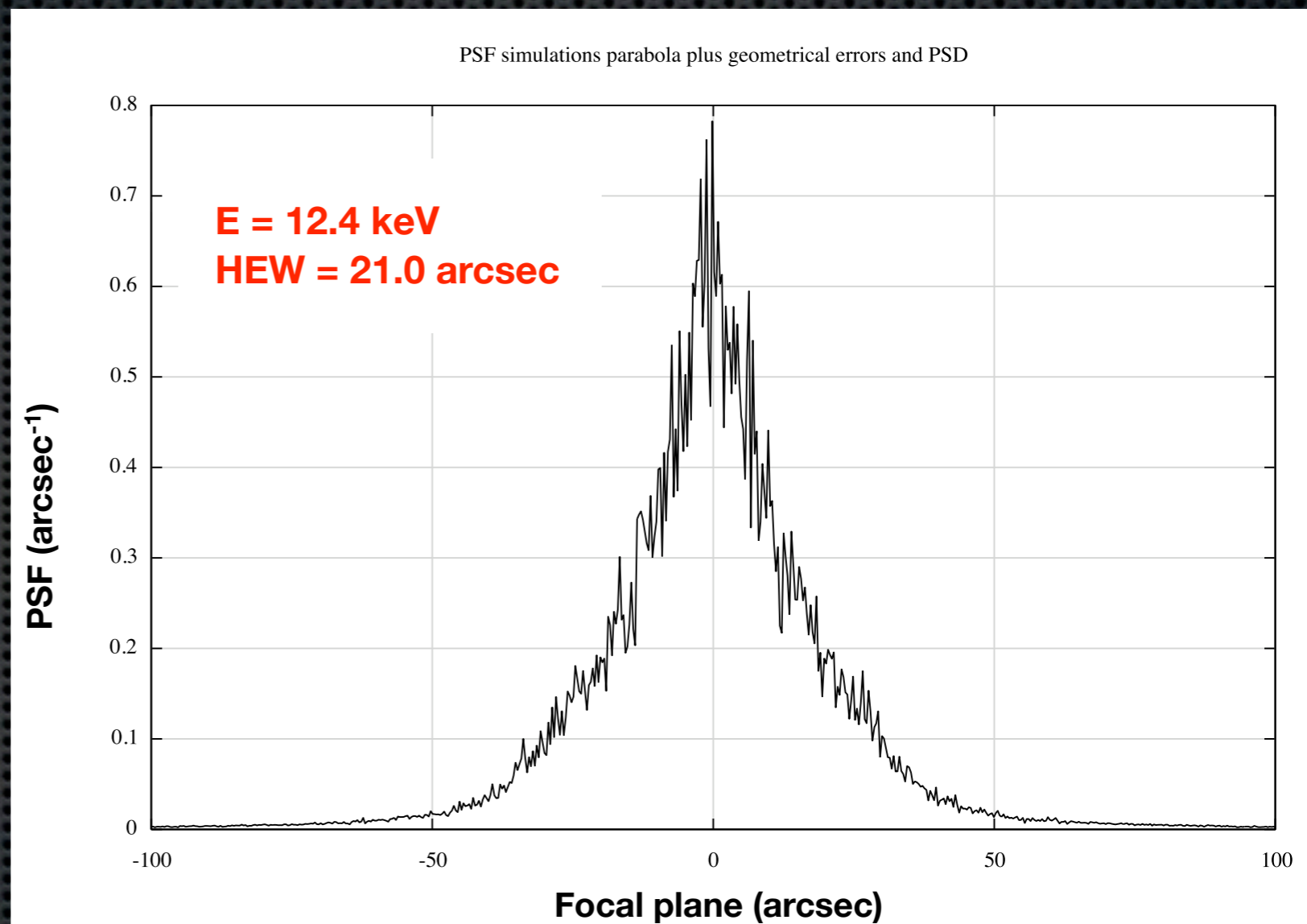
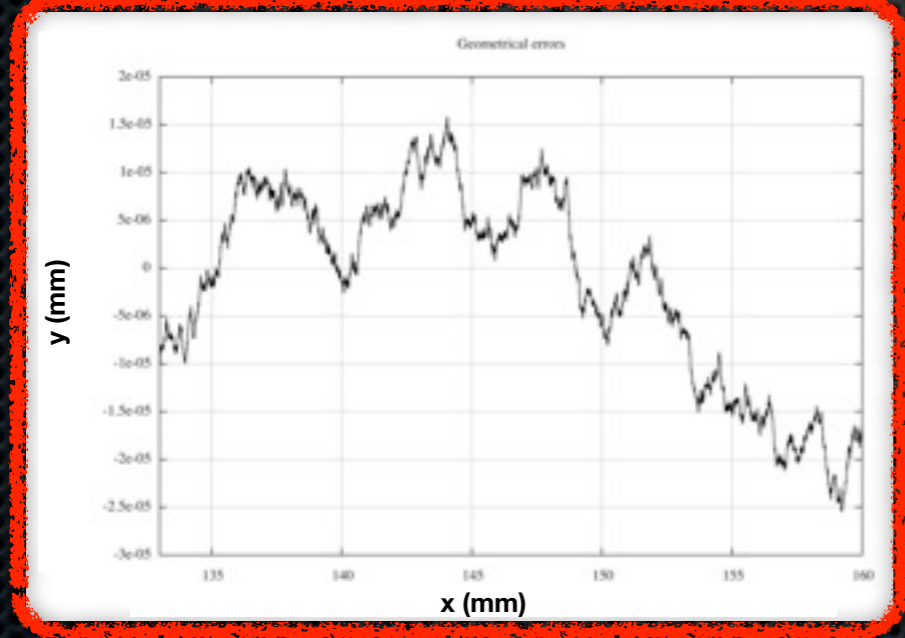
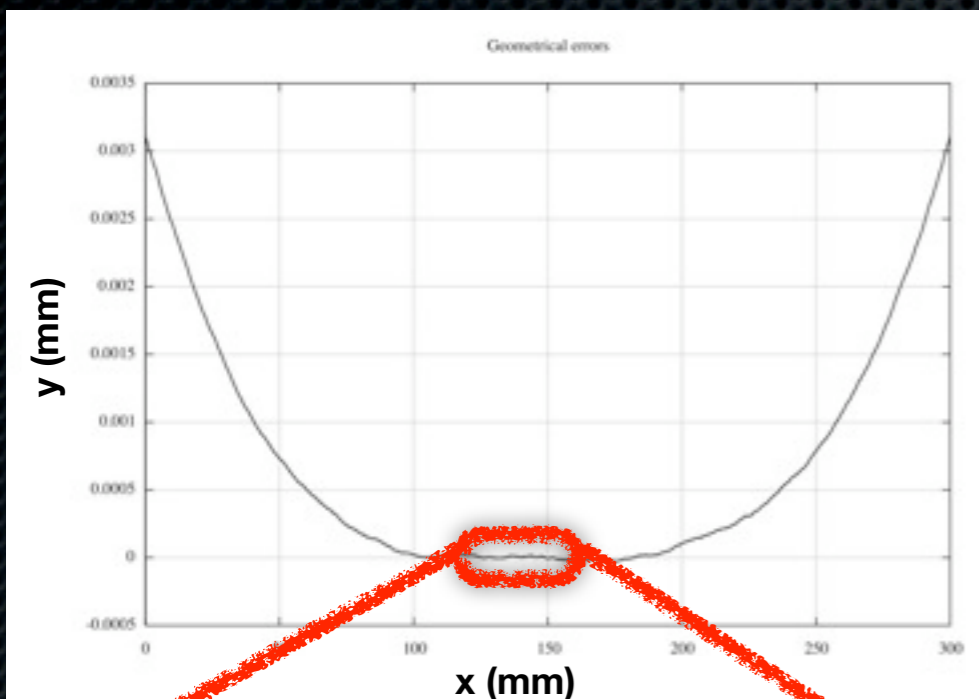
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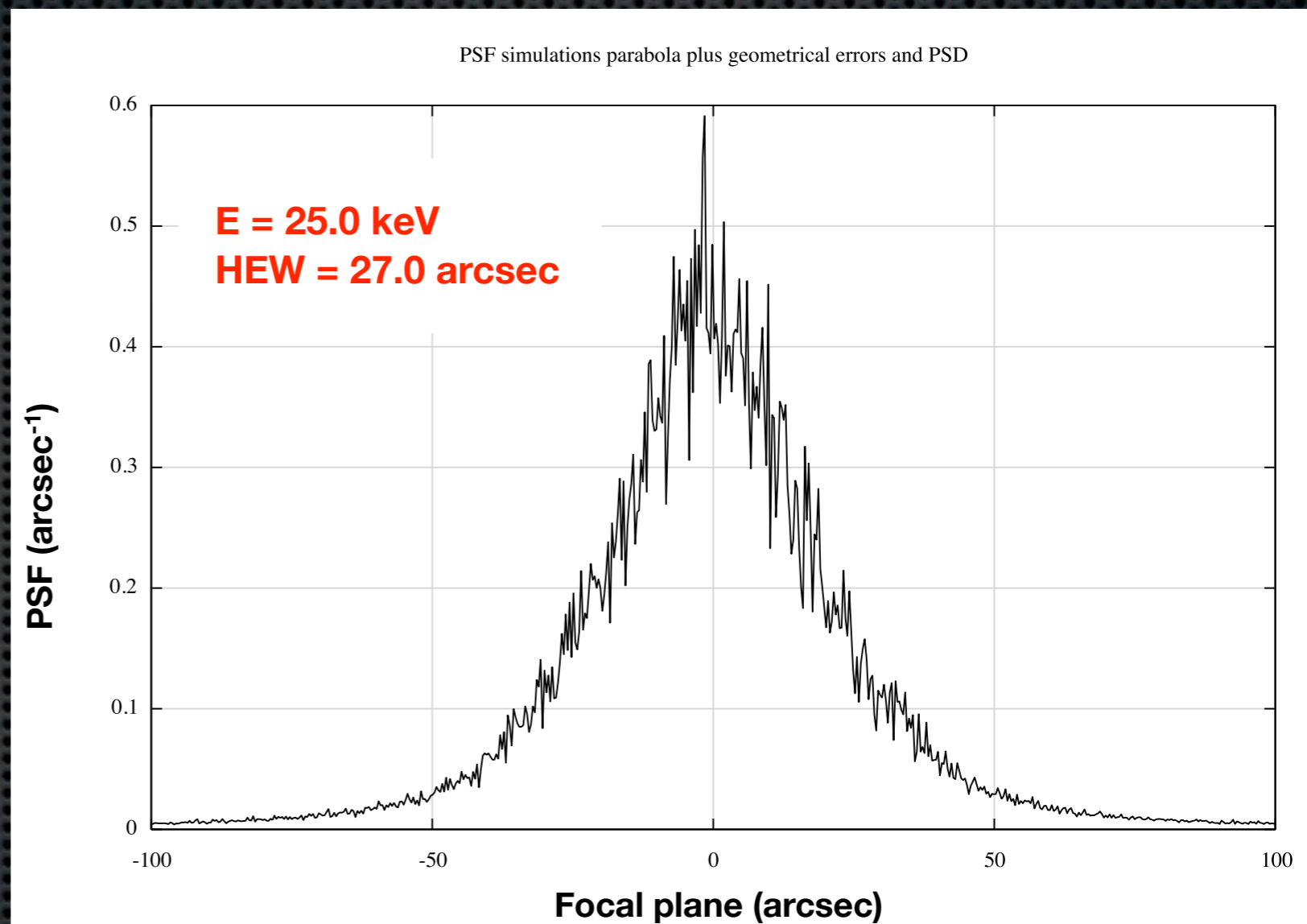
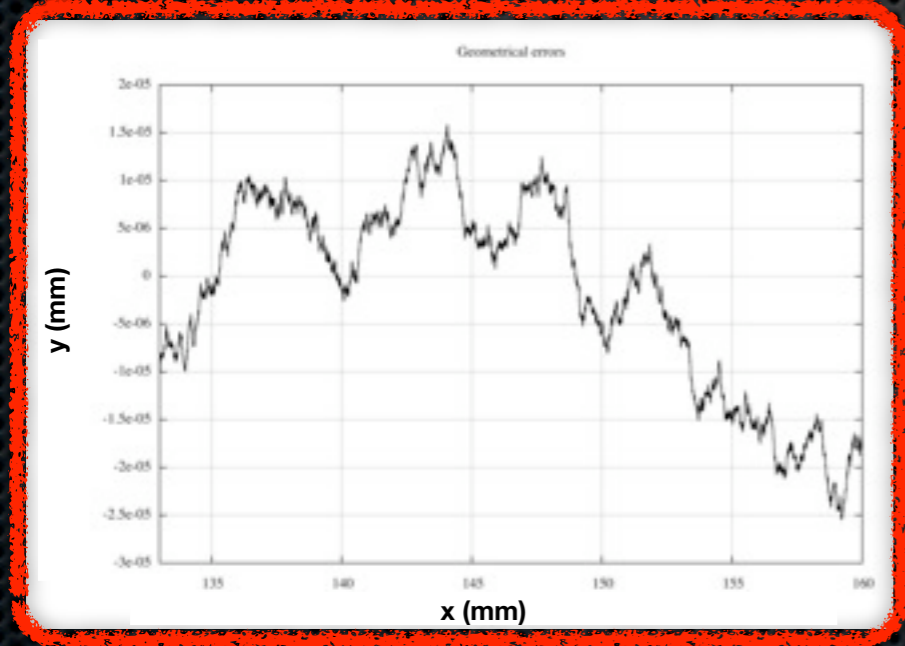
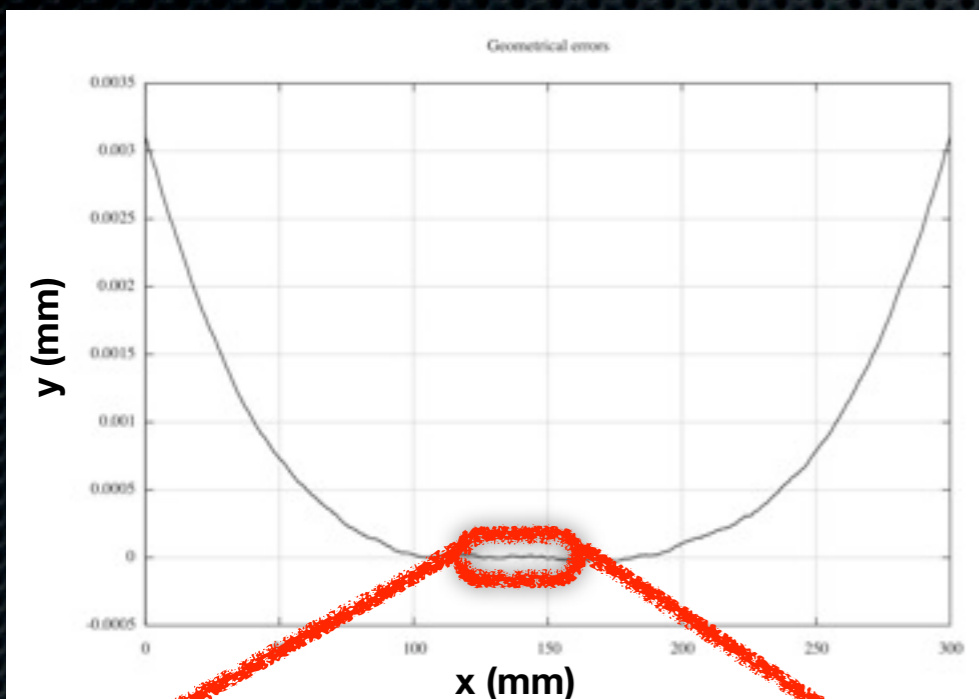
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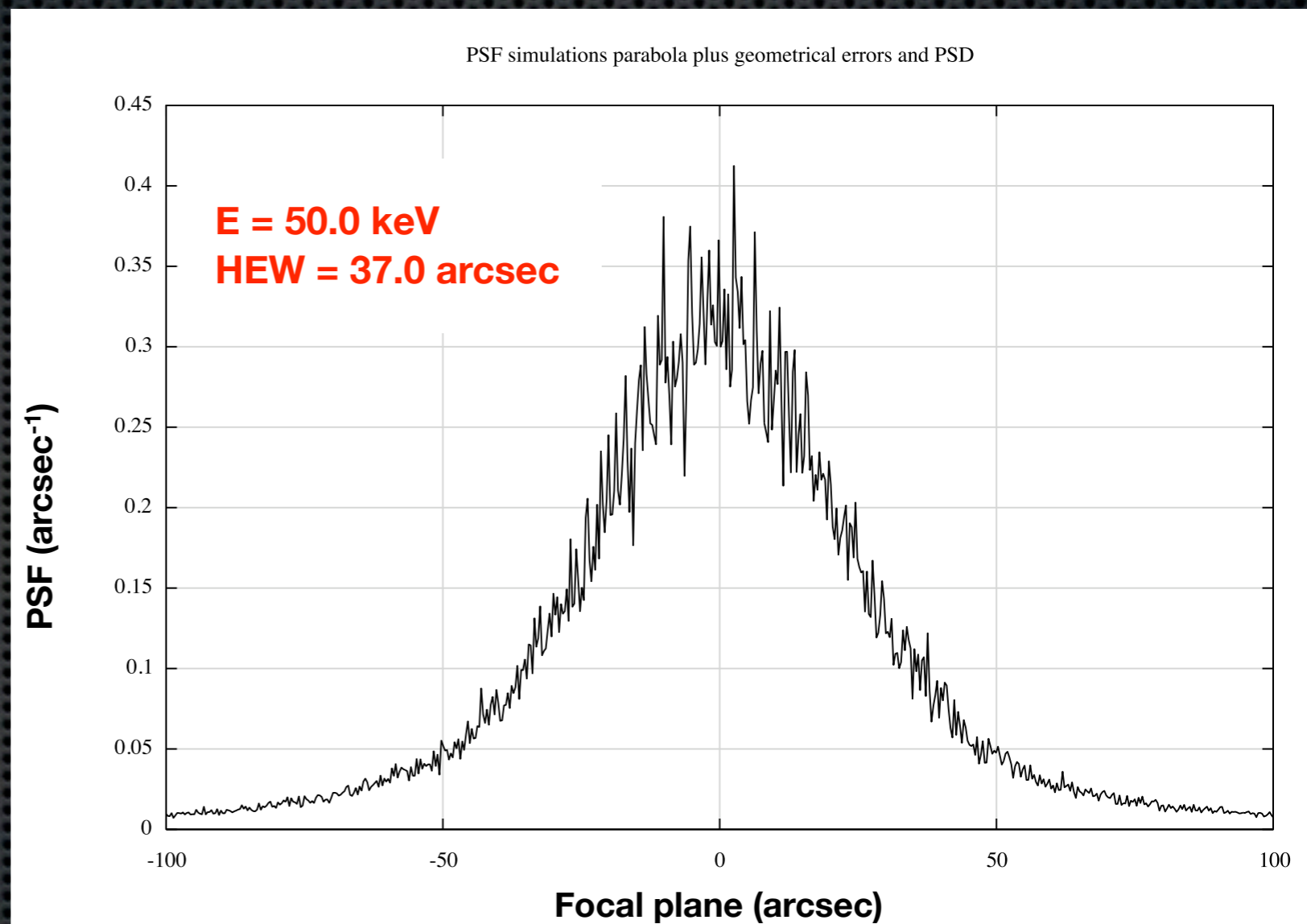
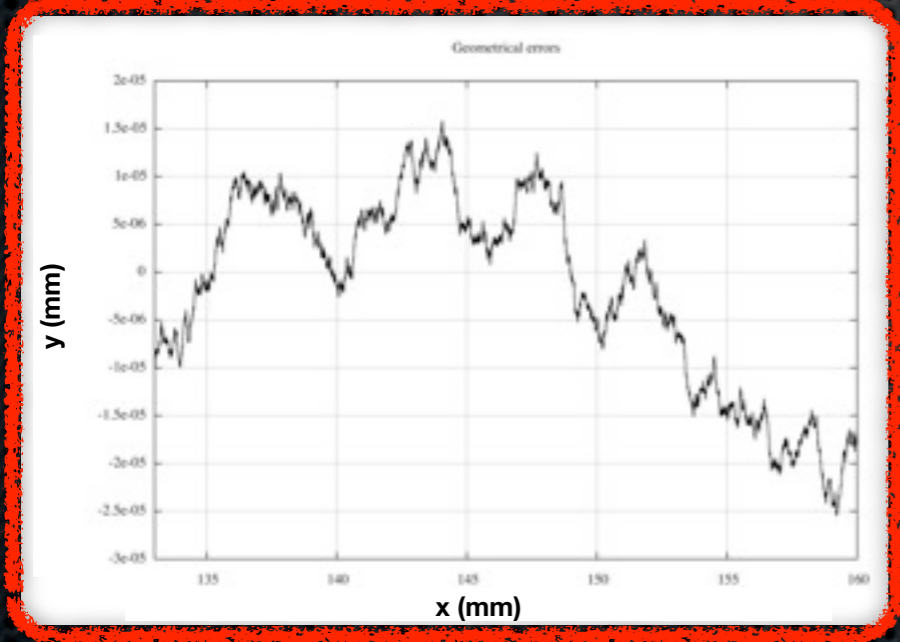
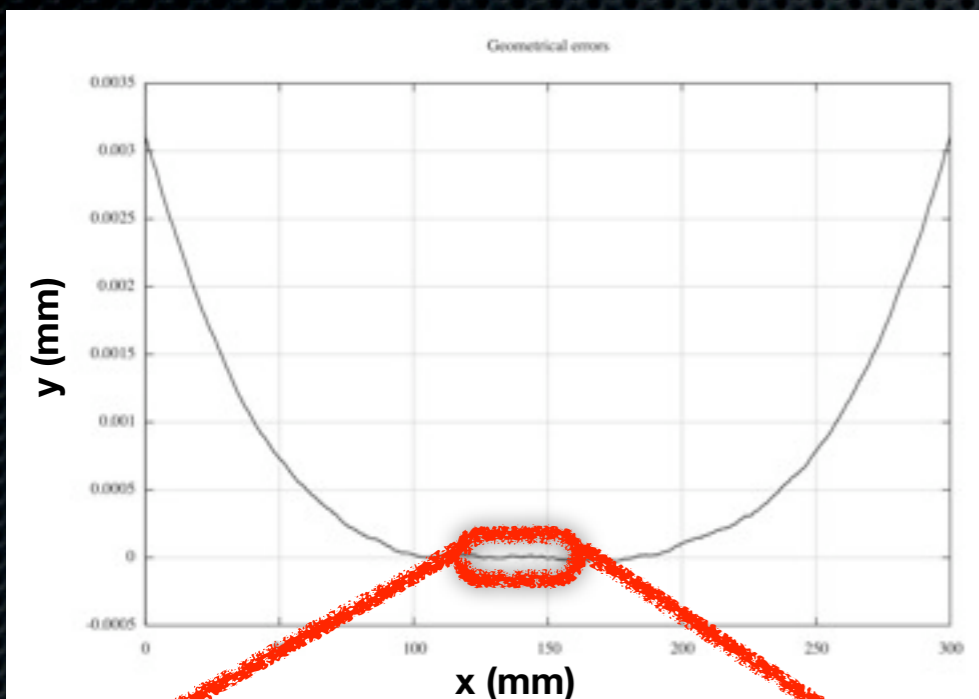
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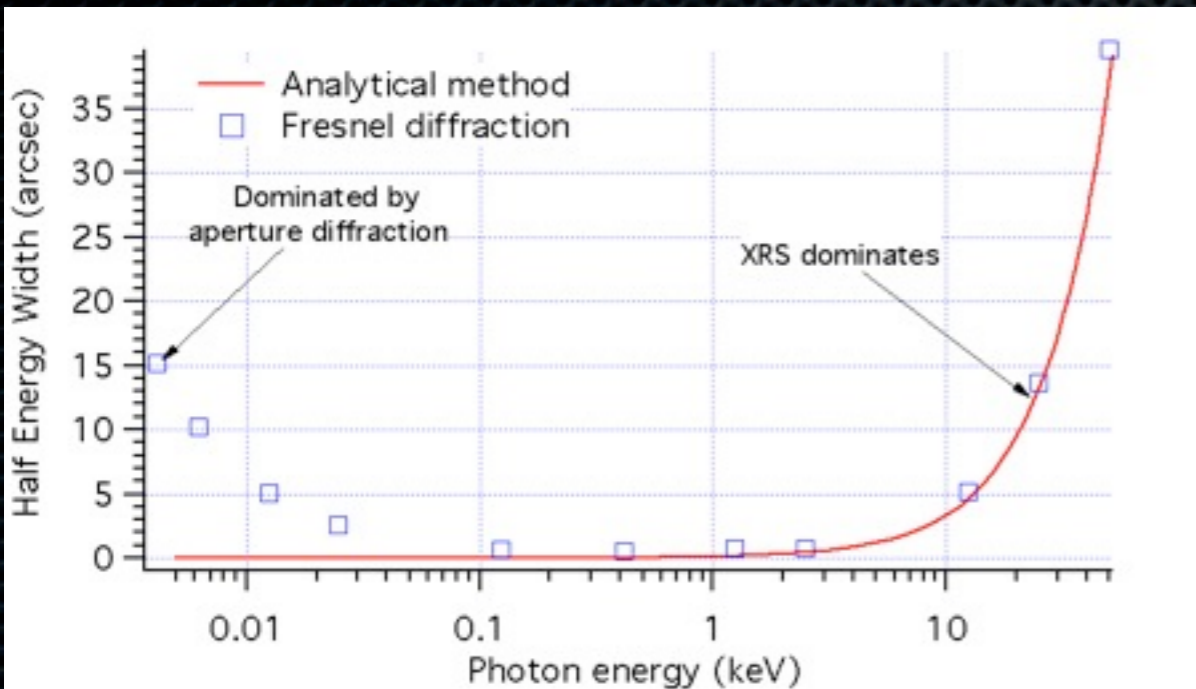


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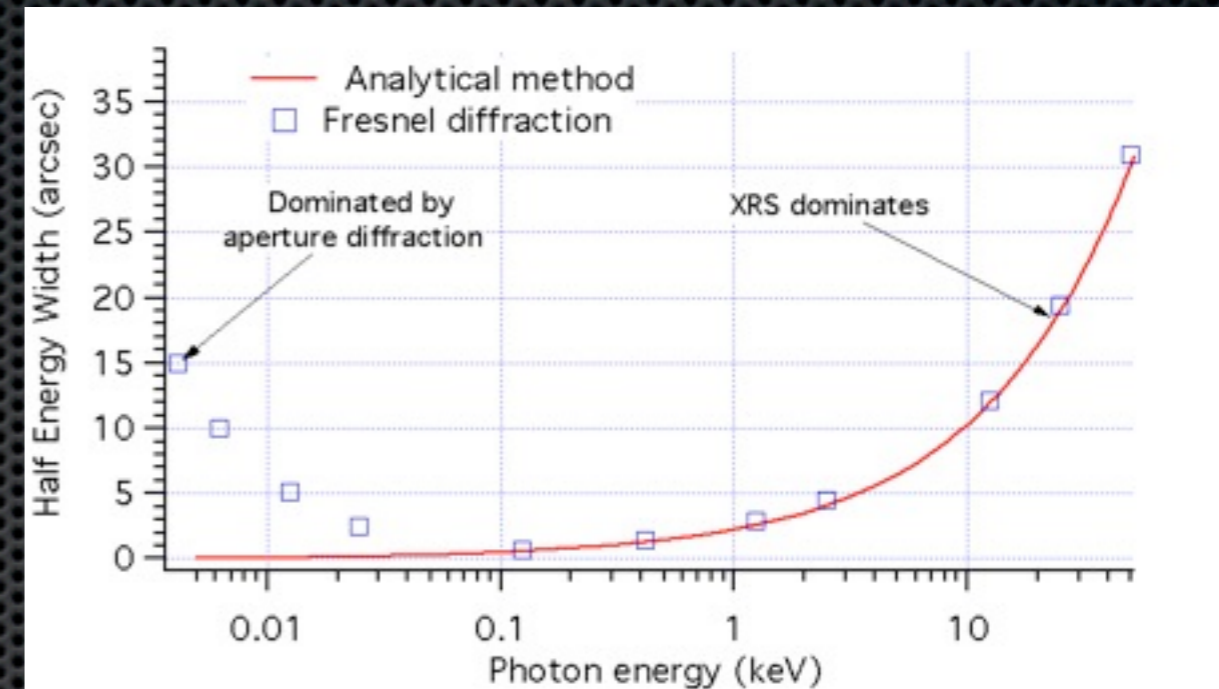


HEW VARIATION WITH ENERGY

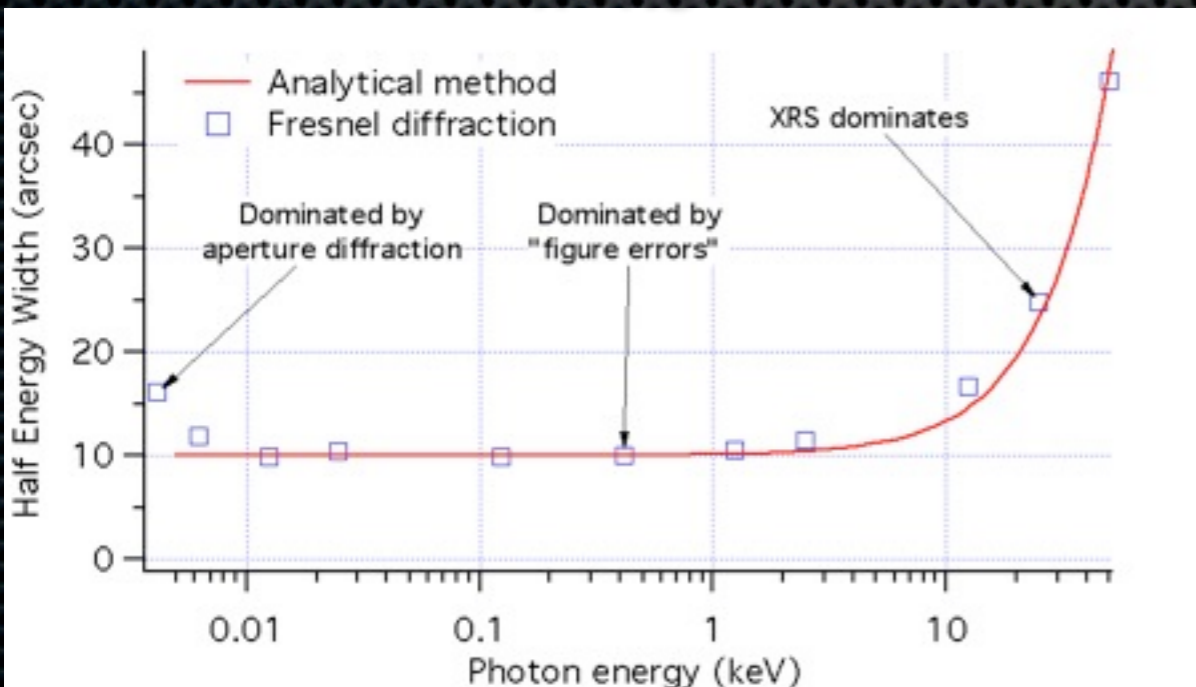
comparison with analytical method (Spiga 2007)



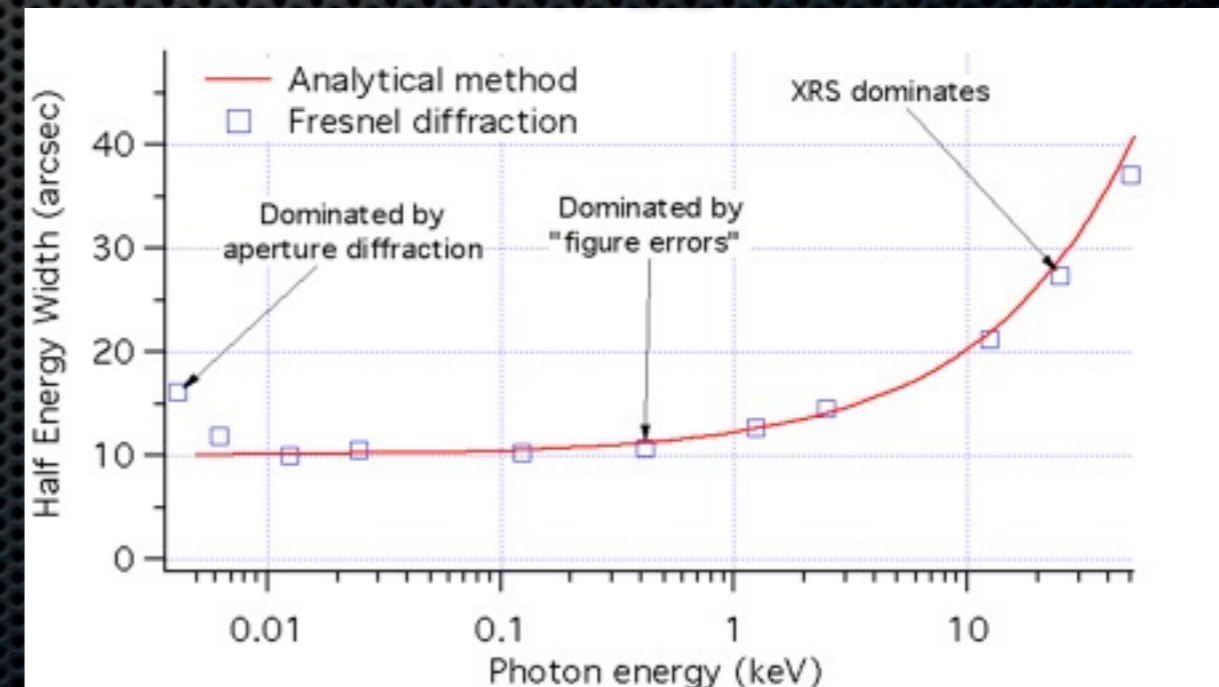
Perfect shape parabola plus PSD $Kn=2.2$
 $n=1.8$



Perfect shape parabola plus PSD $Kn=0.5$
 $n=2.2$



Parabola plus geometrical errors and
PSD $Kn=2.2$ $n=1.8$

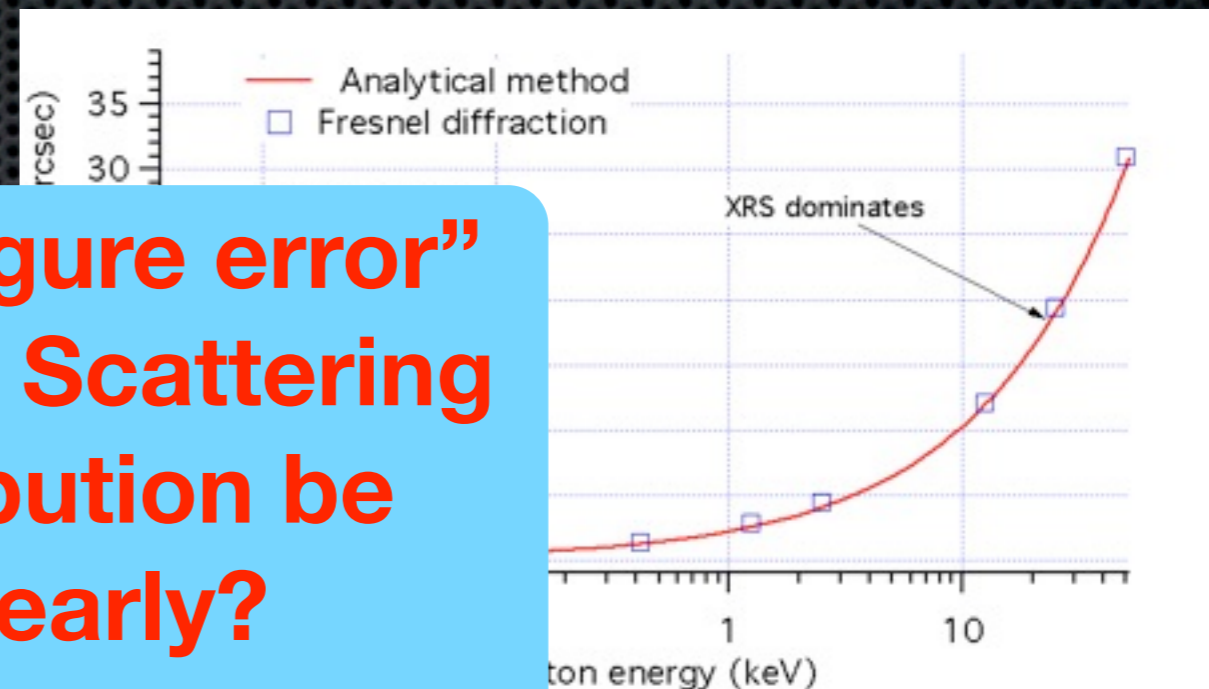
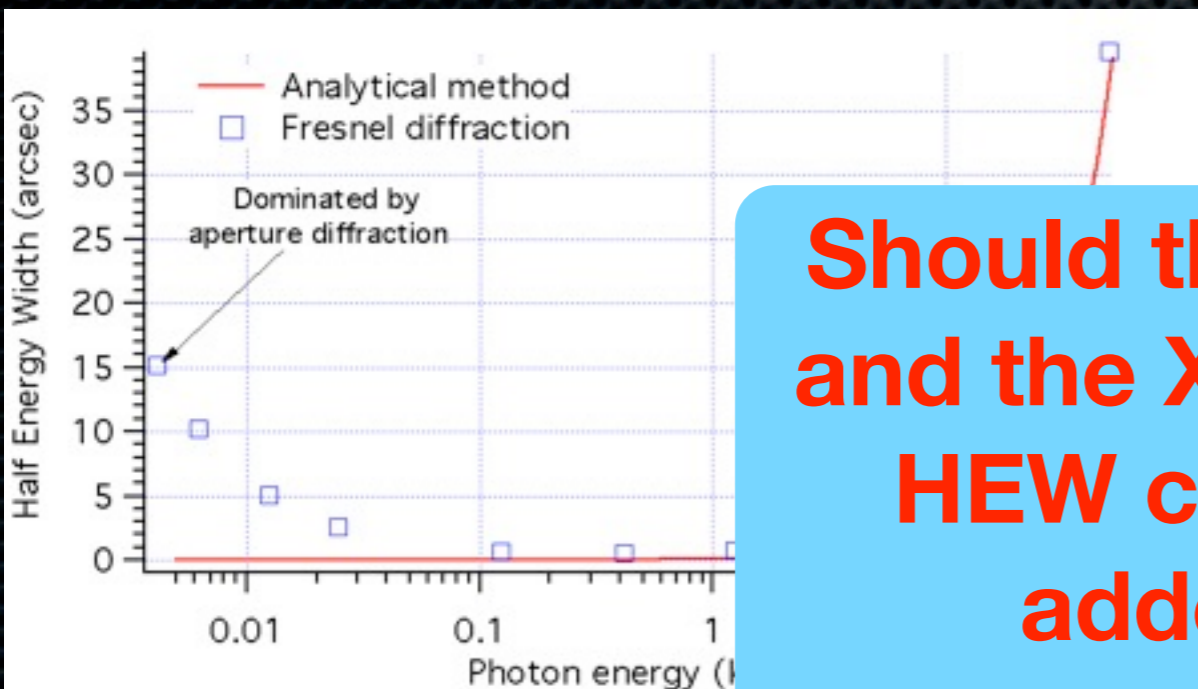


Parabola plus geometrical errors and
PSD $Kn=0.5$ $n=2.2$

HEW VARIATION WITH ENERGY

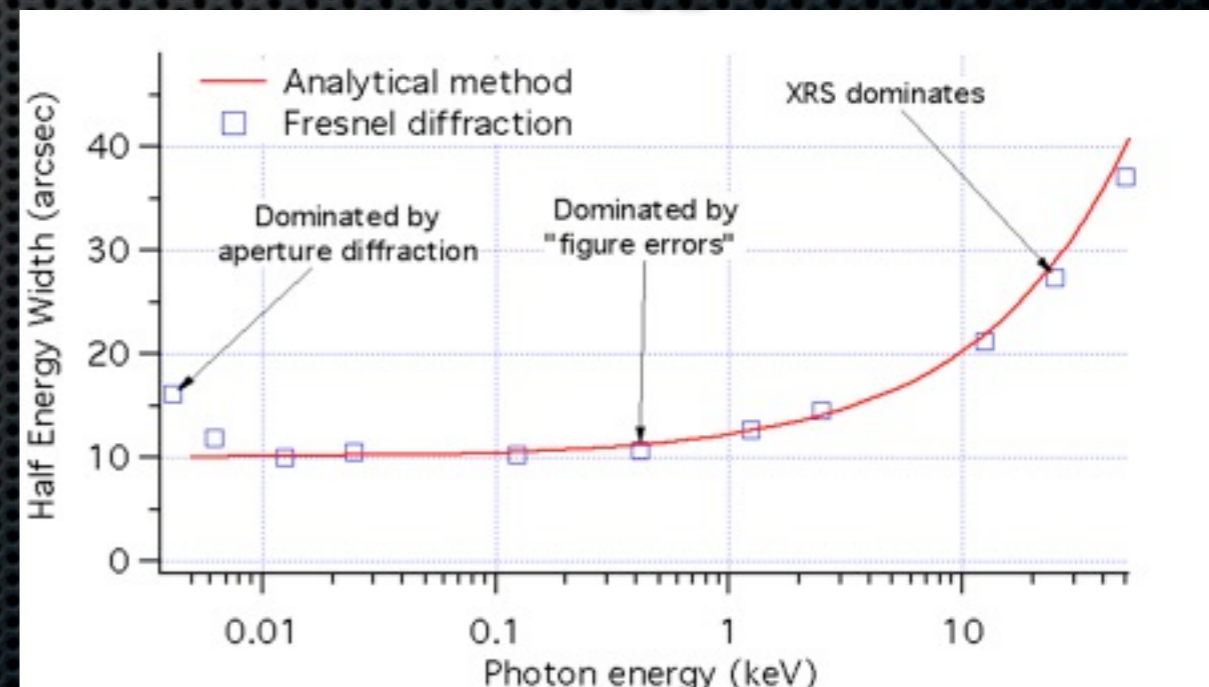
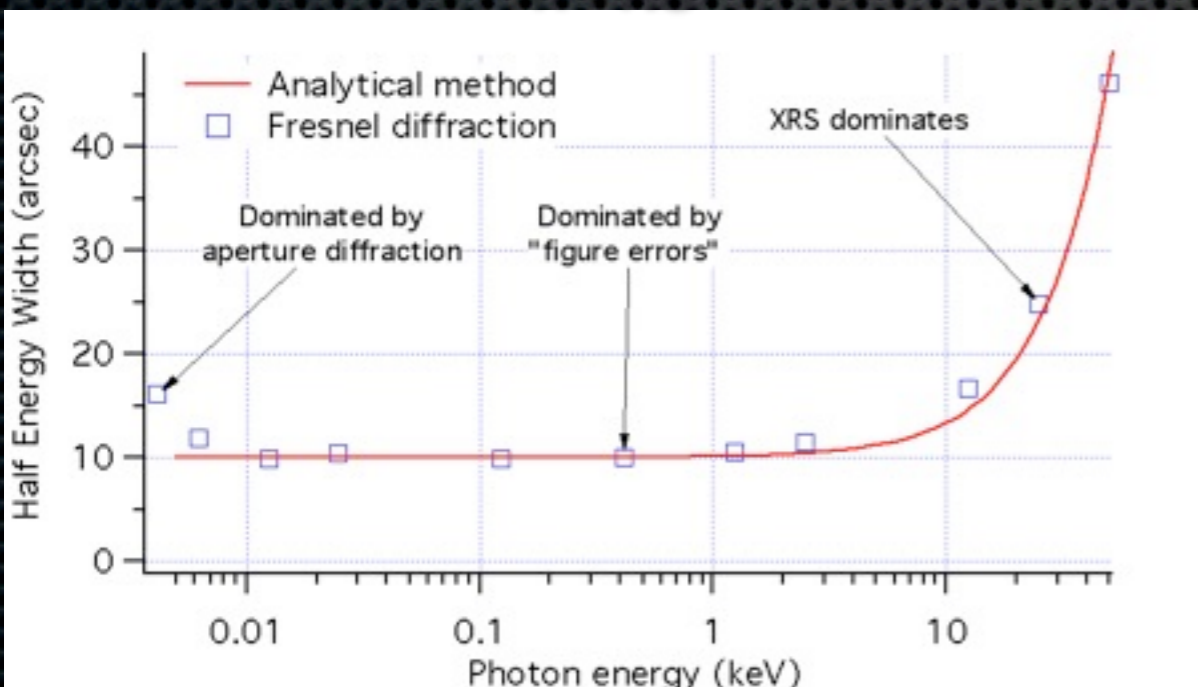
comparison with analytical method (Spiga 2007)

**Should the "figure error"
and the X-Ray Scattering
HEW contribution be
added linearly?**



Perfect shape parabola plus PSD $Kn=2.2$
 $n=1.8$

Perfect shape parabola plus PSD $Kn=0.5$
 $n=2.2$



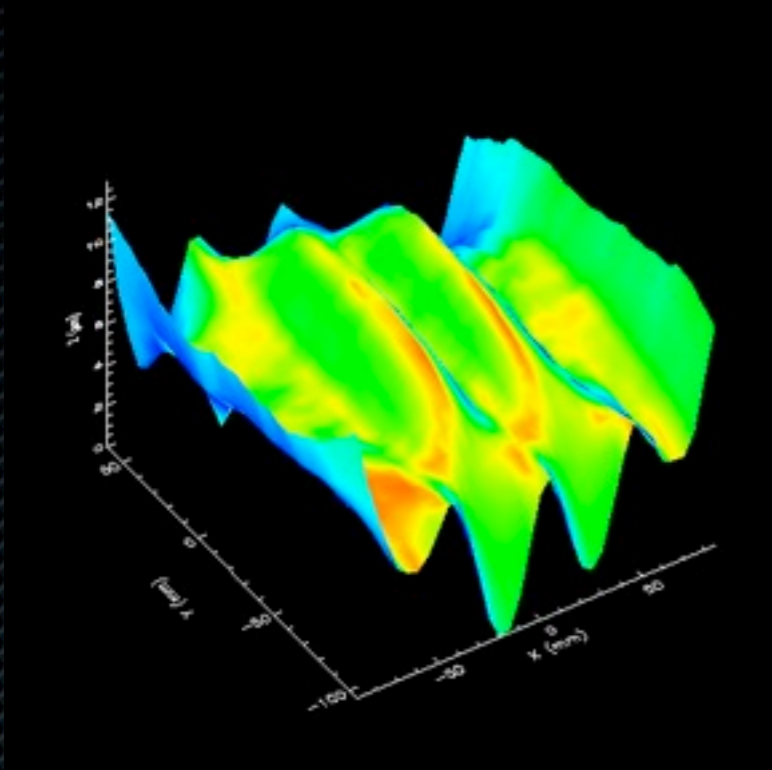
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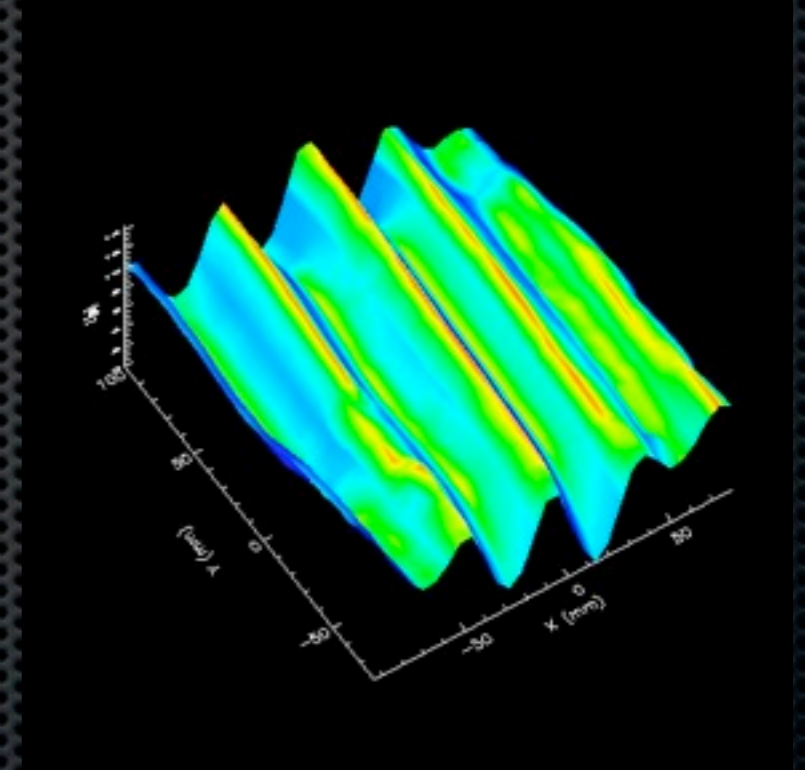
SLUMPED GLASSES PSF ANALYSIS SURFACE METROLOGY

G1 glass

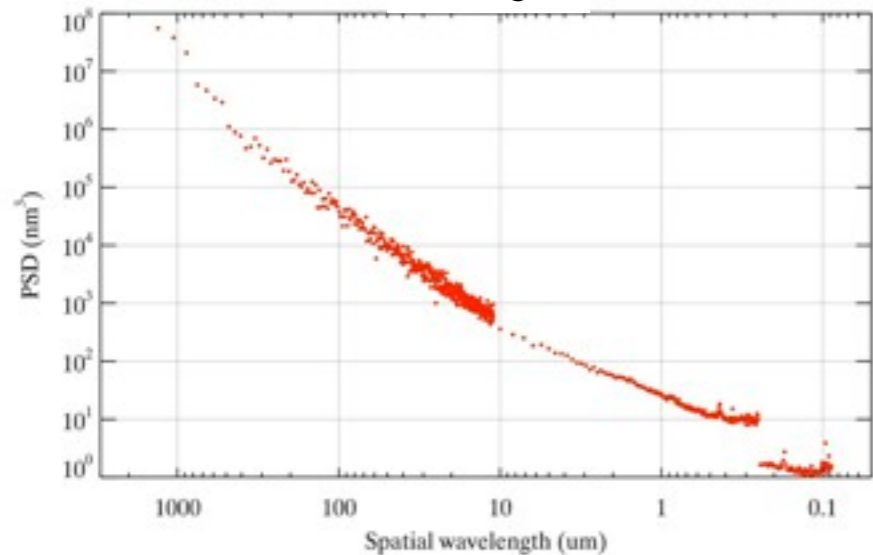
G2 glass



- PROFILES MEASURED WITH 3D PROFILOMETER 5-200 mm

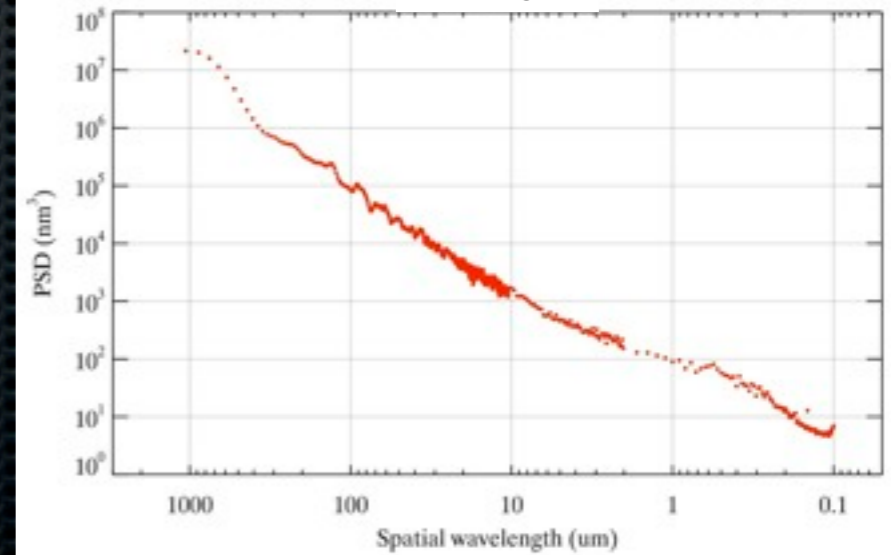


PSD G1 glass



- PSD ACHIEVED FROM AFM, OPTICAL INTERFEROMETER AND X-RAY DIFFRACTOMETER MEASURE 1 mm - 0.1 um

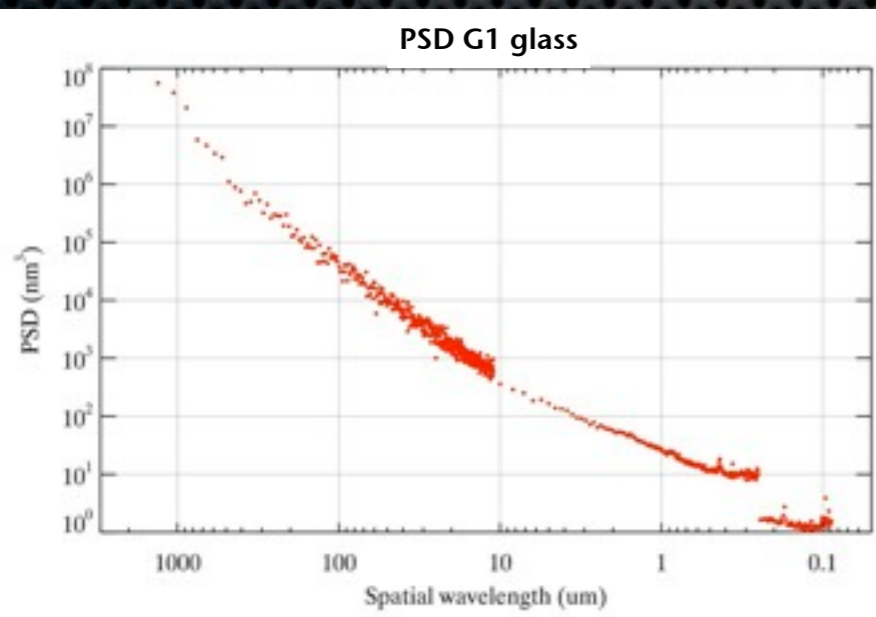
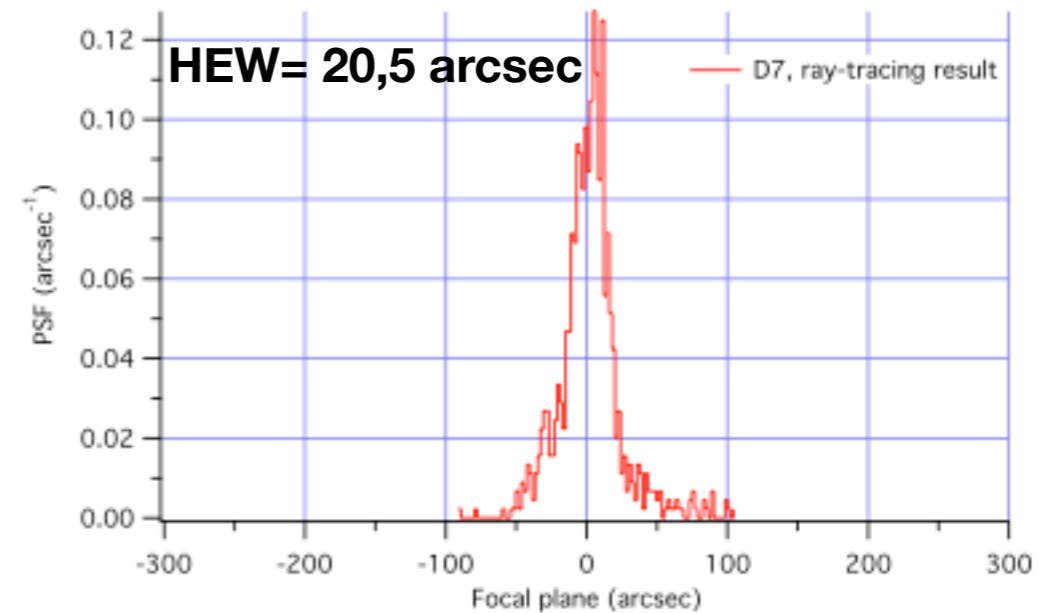
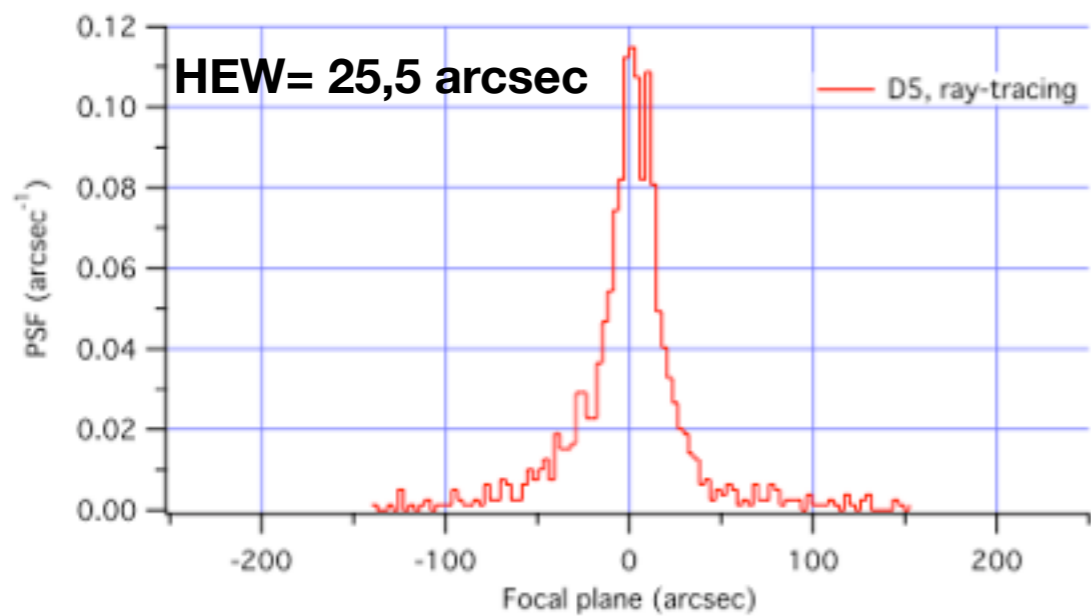
PSD G2 glass



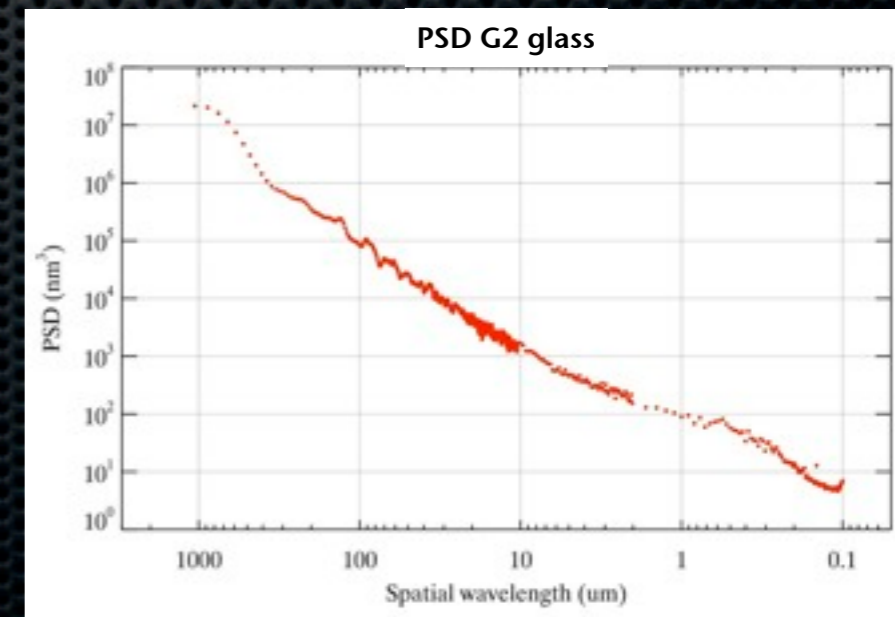
SLUMPED GLASSES PSF ANALYSIS SURFACE METROLOGY

G1 glass

G2 glass



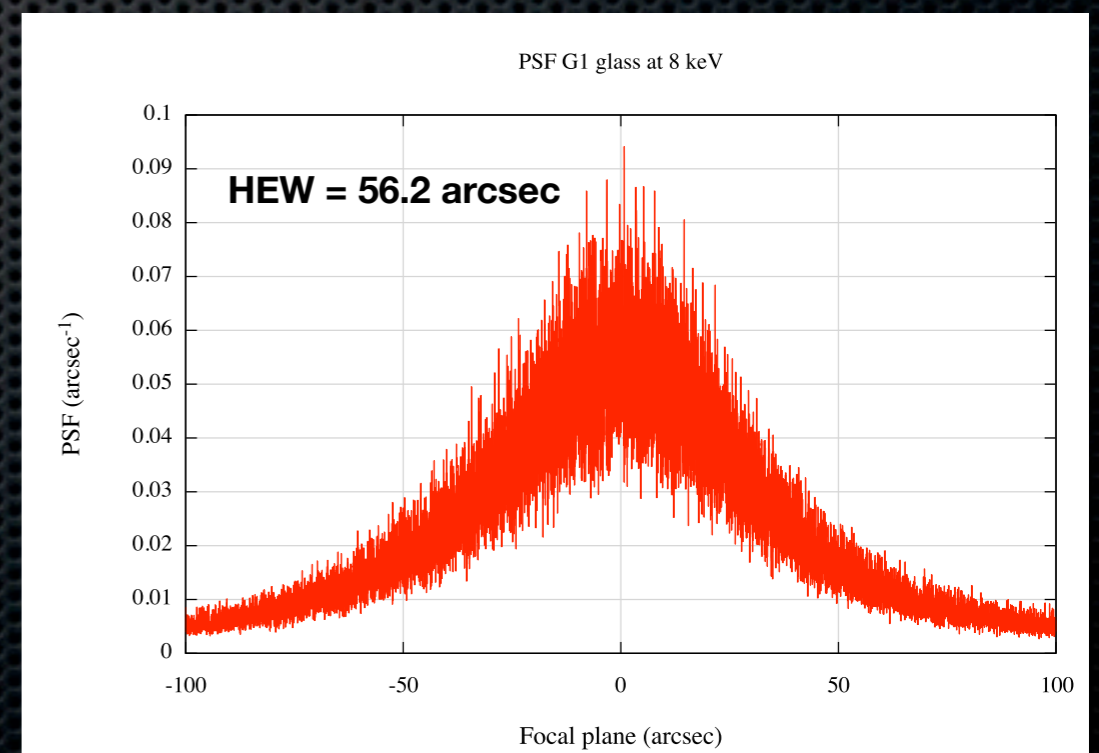
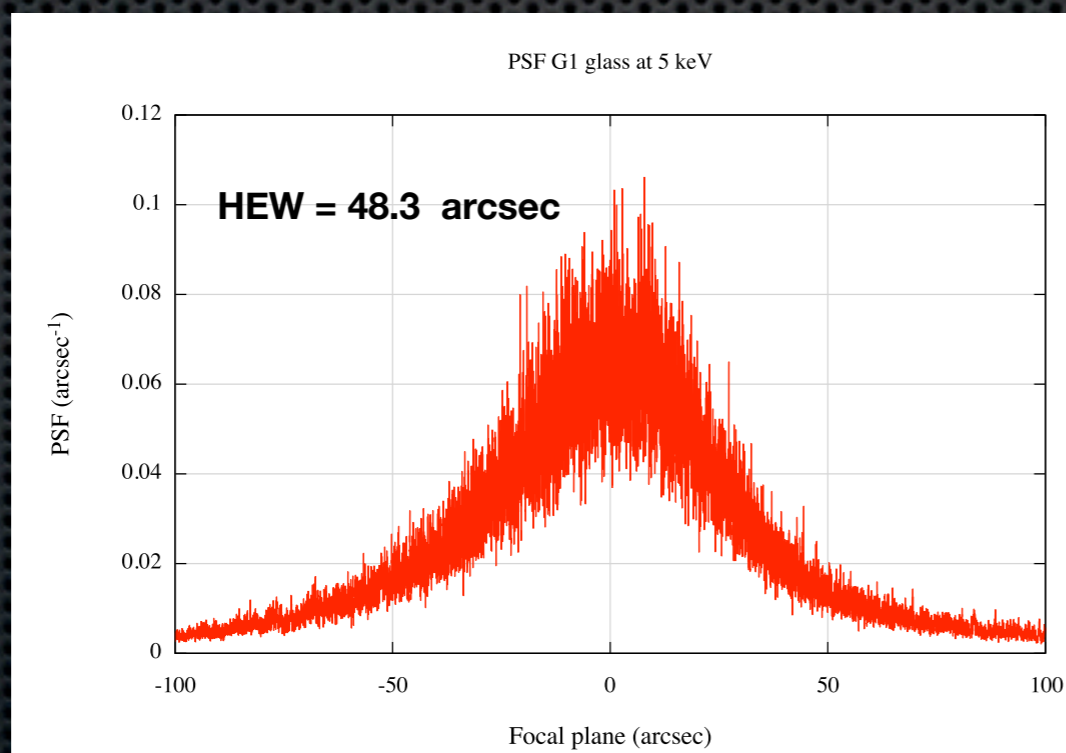
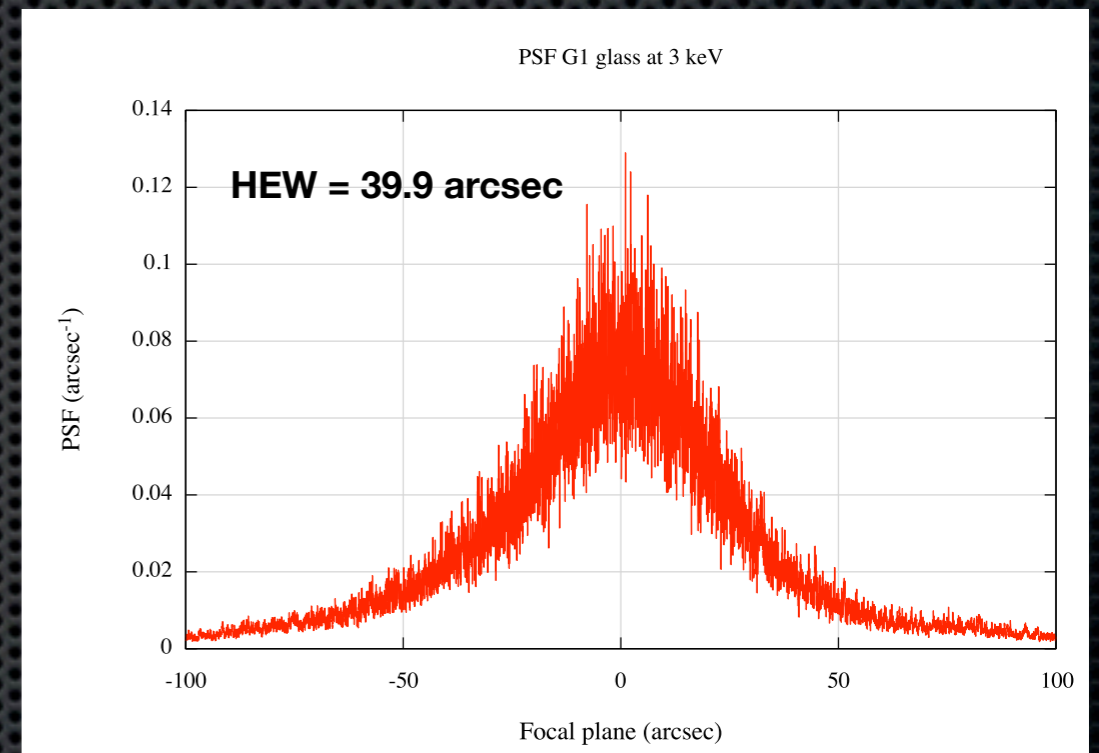
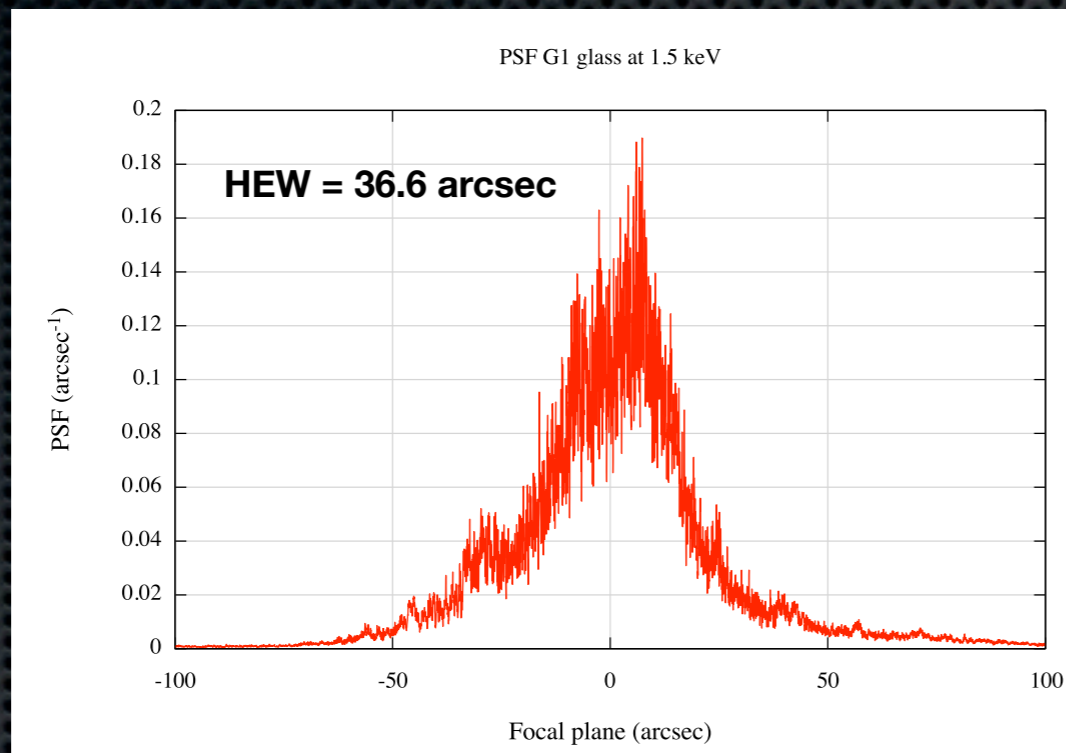
PSD ACHIEVED FROM
AFM, OPTICAL
INTERFEROMETER AND
X-RAY DIFFRACTOMETER
MEASURE
1 mm - 0.1 um



SLUMPED GLASSES PSF ANALYSIS

PSF COMPUTATION

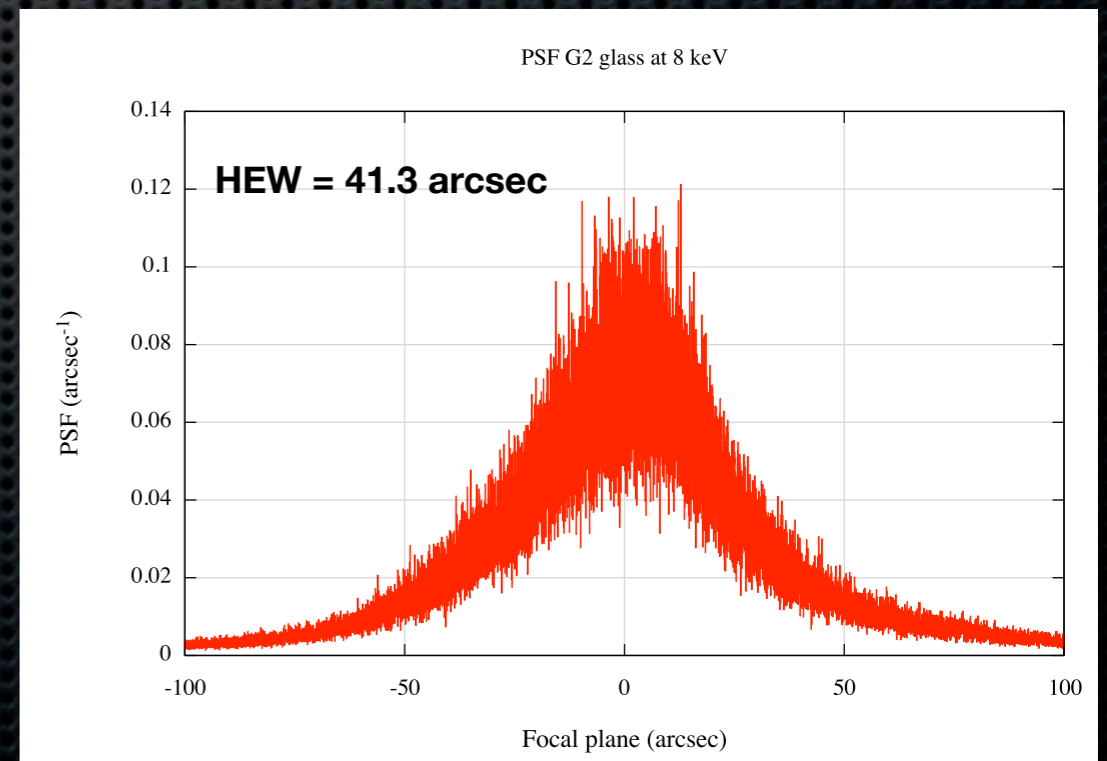
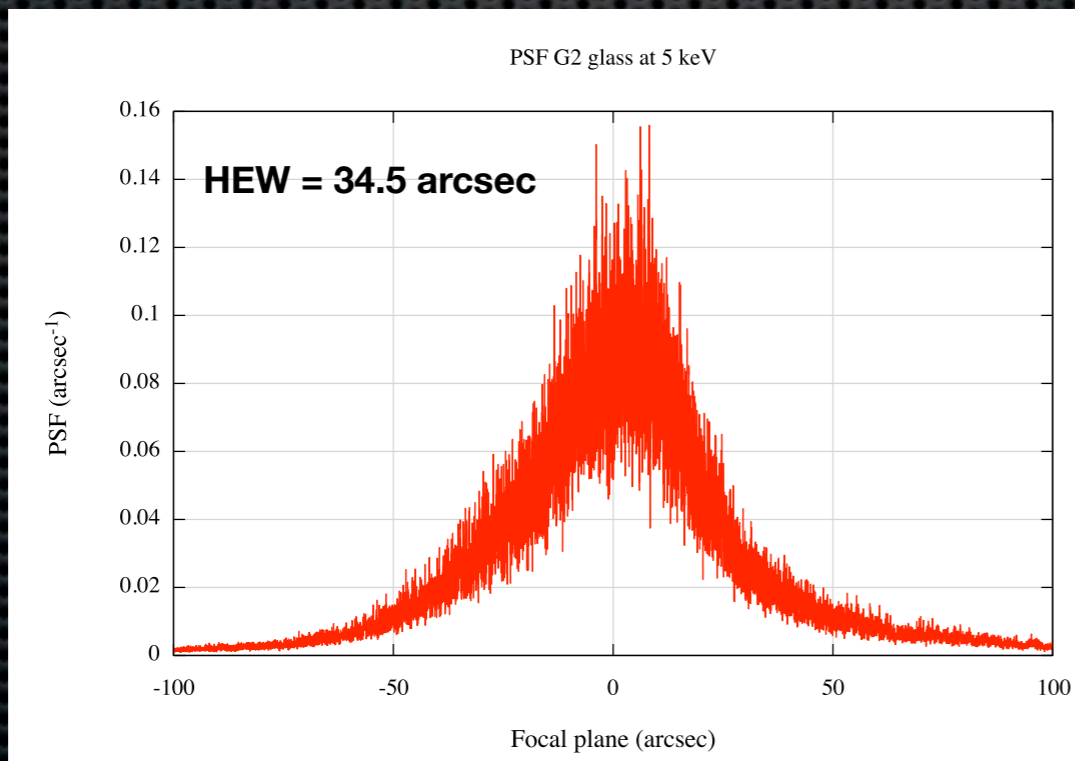
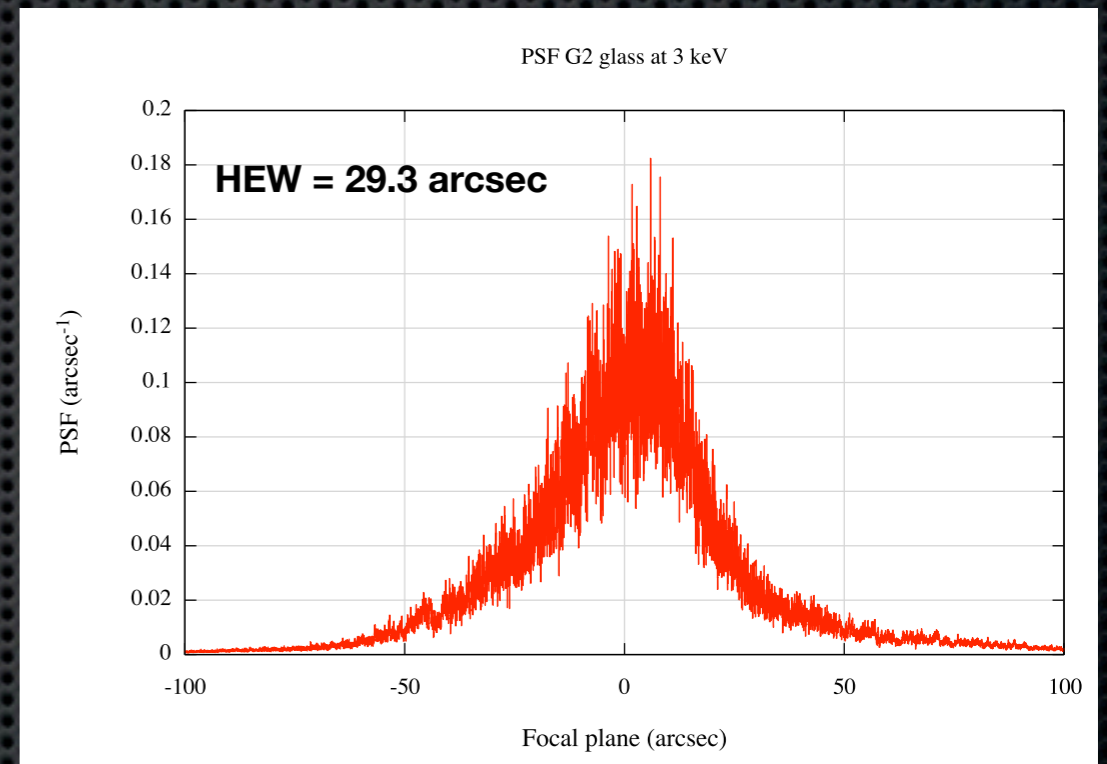
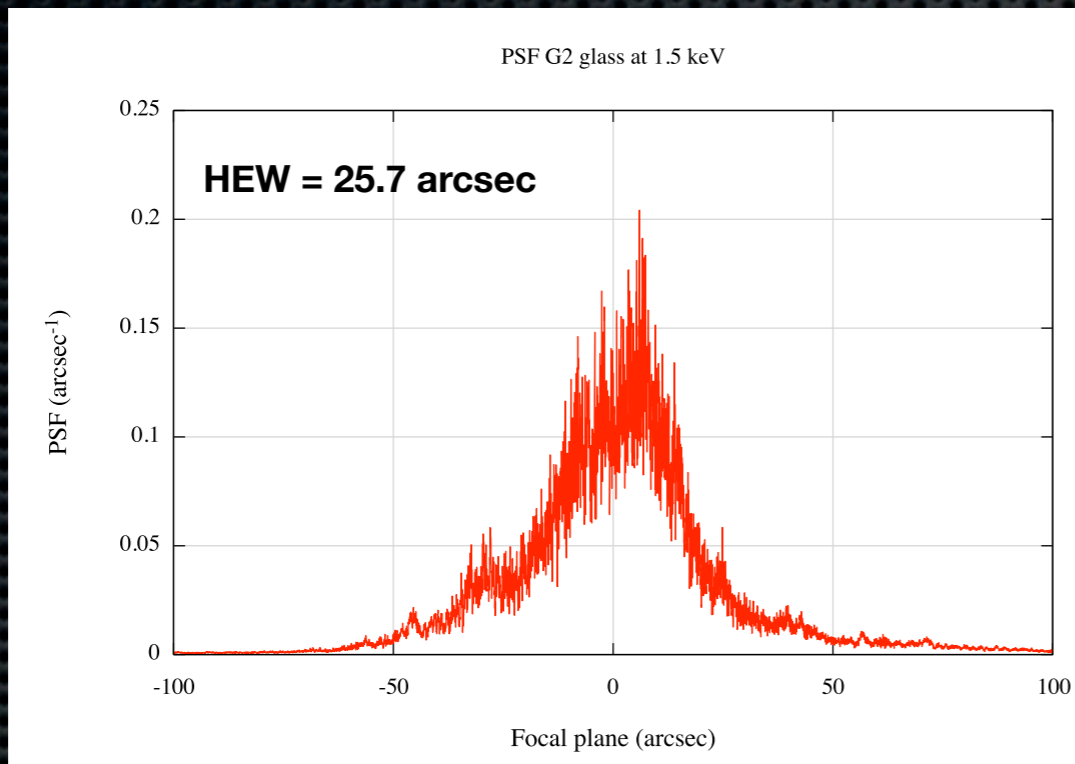
G1



SLUMPED GLASSES PSF ANALYSIS

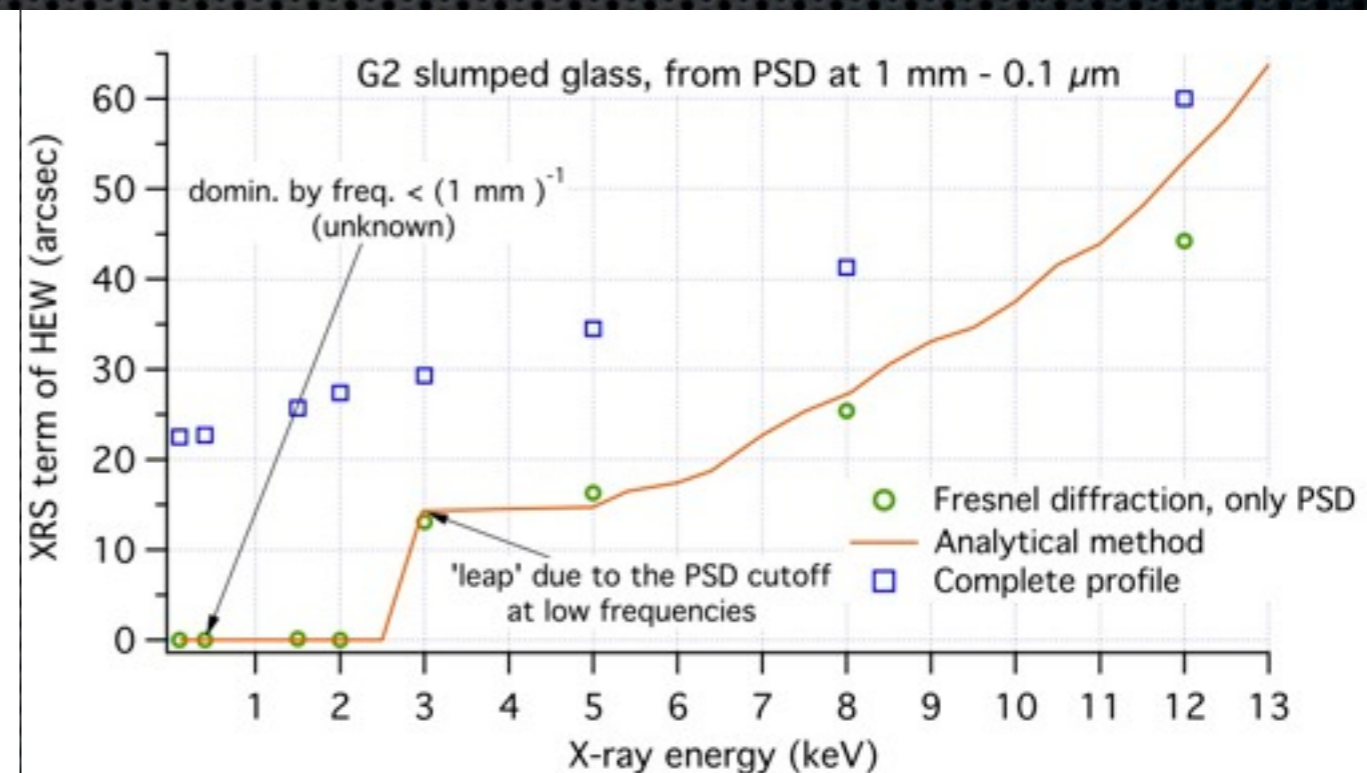
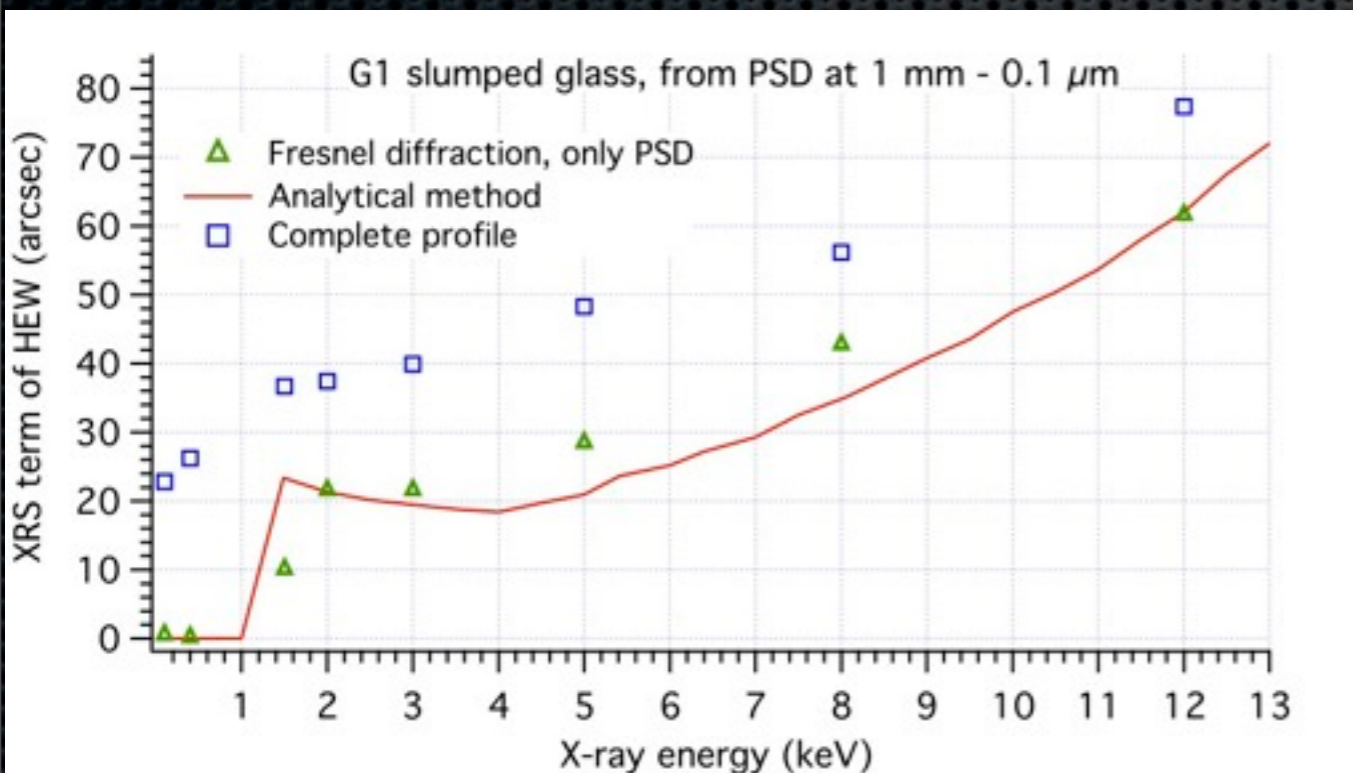
PSF COMPUTATION

G2



SLUMPED GLASSES PSF ANALYSIS

HEW BEHAVIOR WITH ENERGY

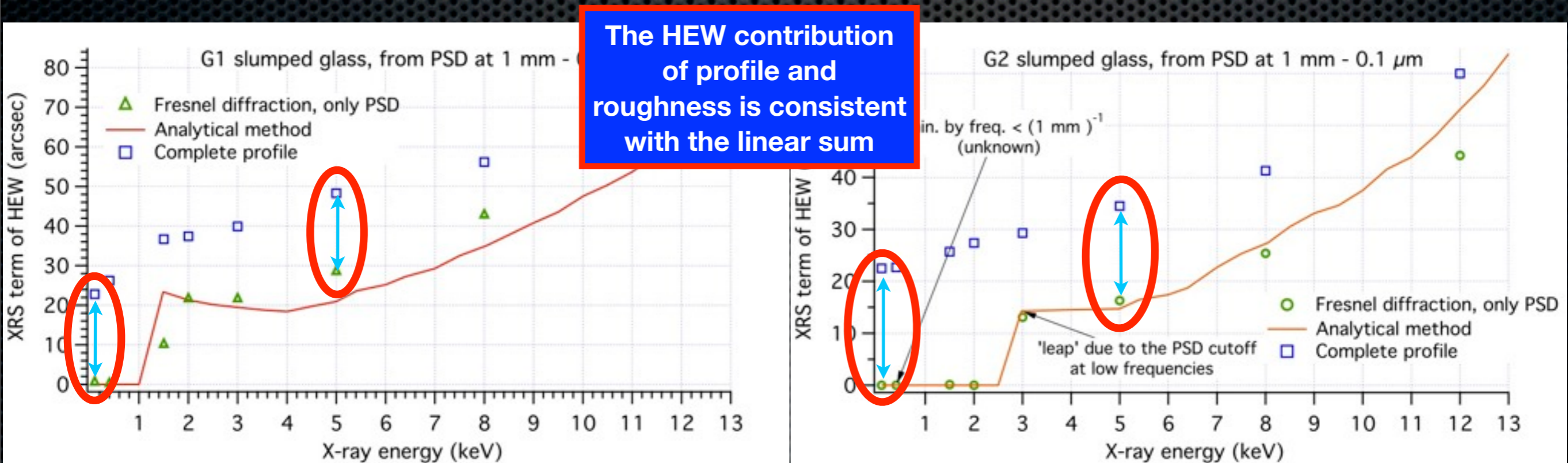


Behavior of HEW with Energy of G1-G2 mirrors:

comparison between the analytical method and the Fresnel diffraction simulations.

SLUMPED GLASSES PSF ANALYSIS

HEW BEHAVIOR WITH ENERGY



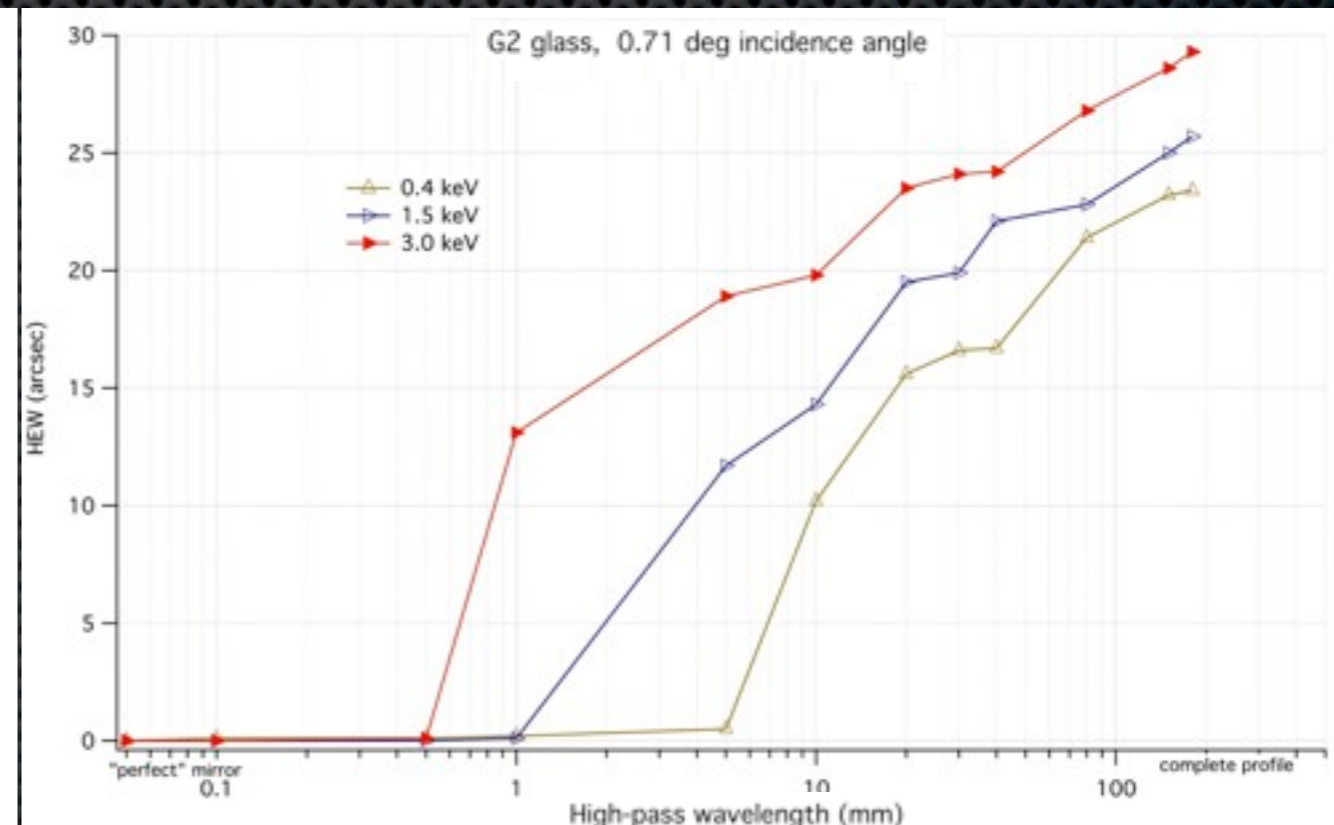
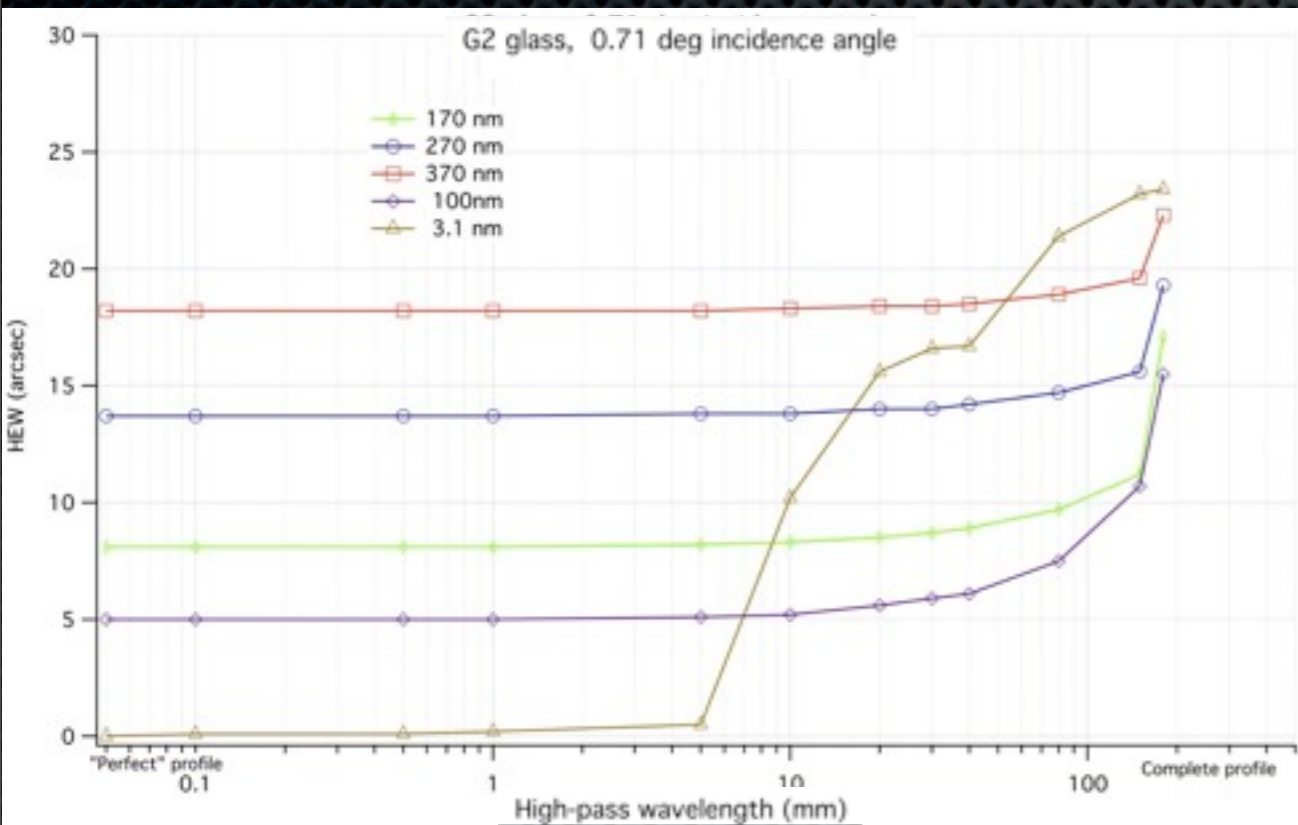
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SLUMPED GLASSES PSF ANALYSIS

HEW BEHAVIOR WITH ENERGY

Analysis of different spatial wavelength ranges impact on PSF degradation

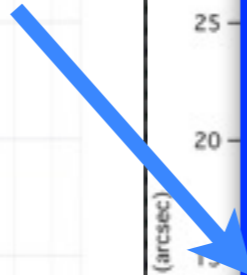
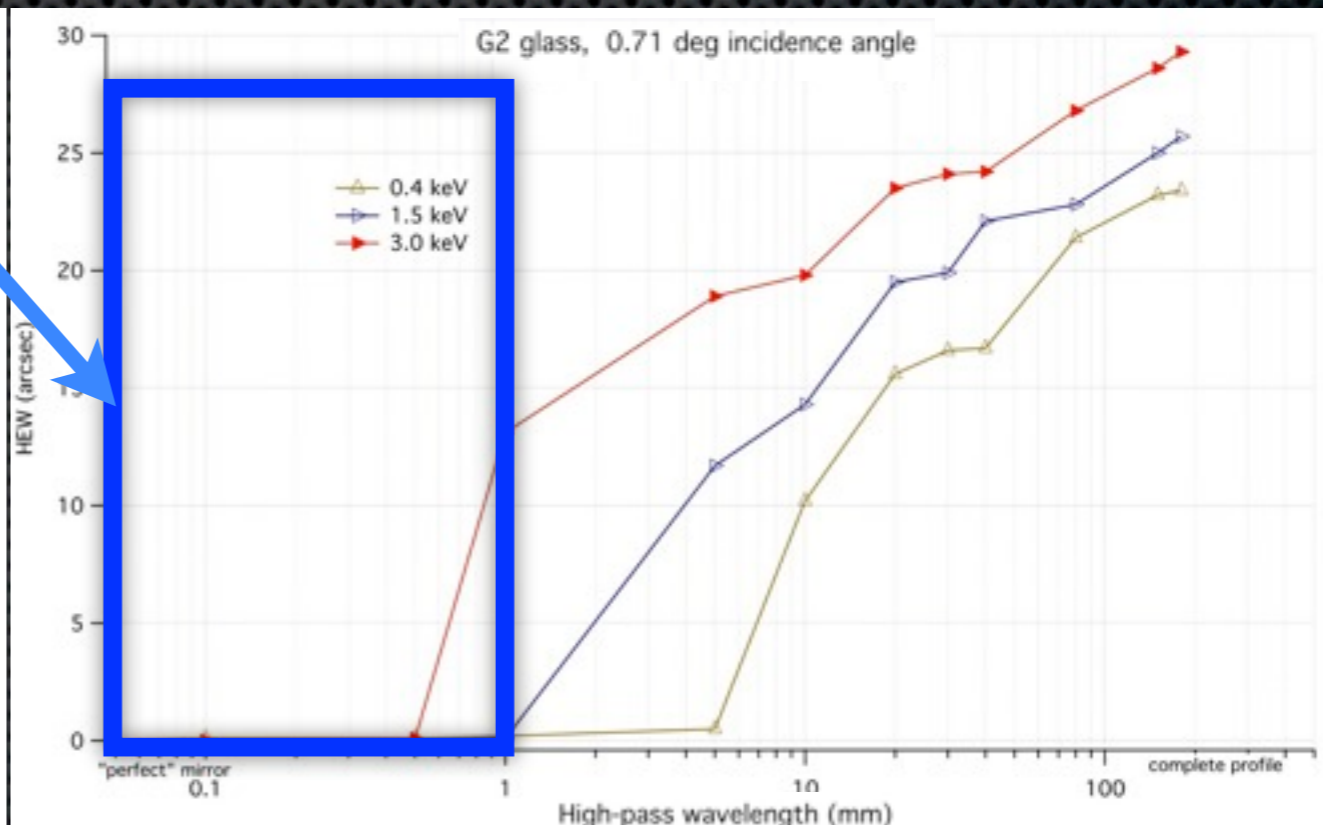
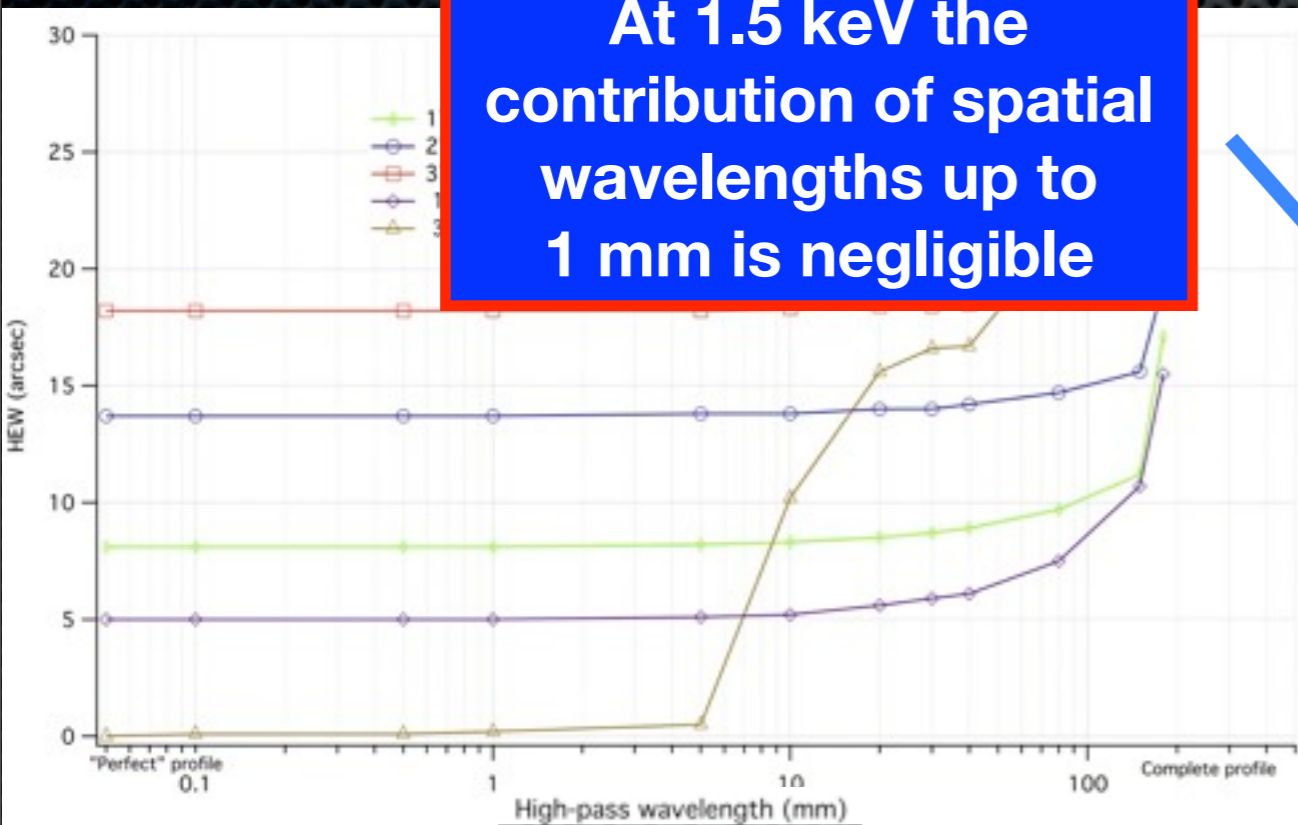


SLUMPED GLASSES PSF ANALYSIS

HEW BEHAVIOR WITH ENERGY

Analysis of different spatial wavelength ranges impact on PSF degradation

At 1.5 keV the contribution of spatial wavelengths up to 1 mm is negligible

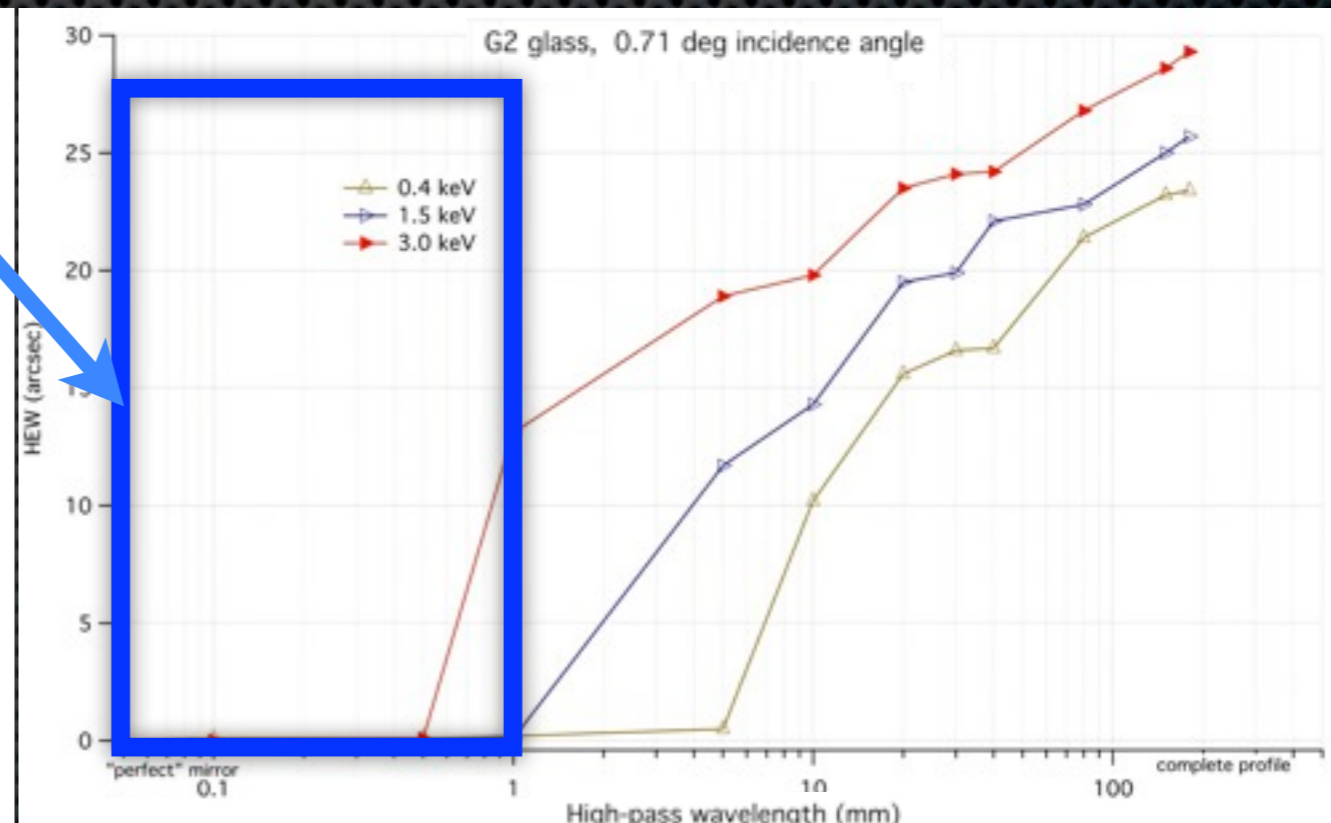
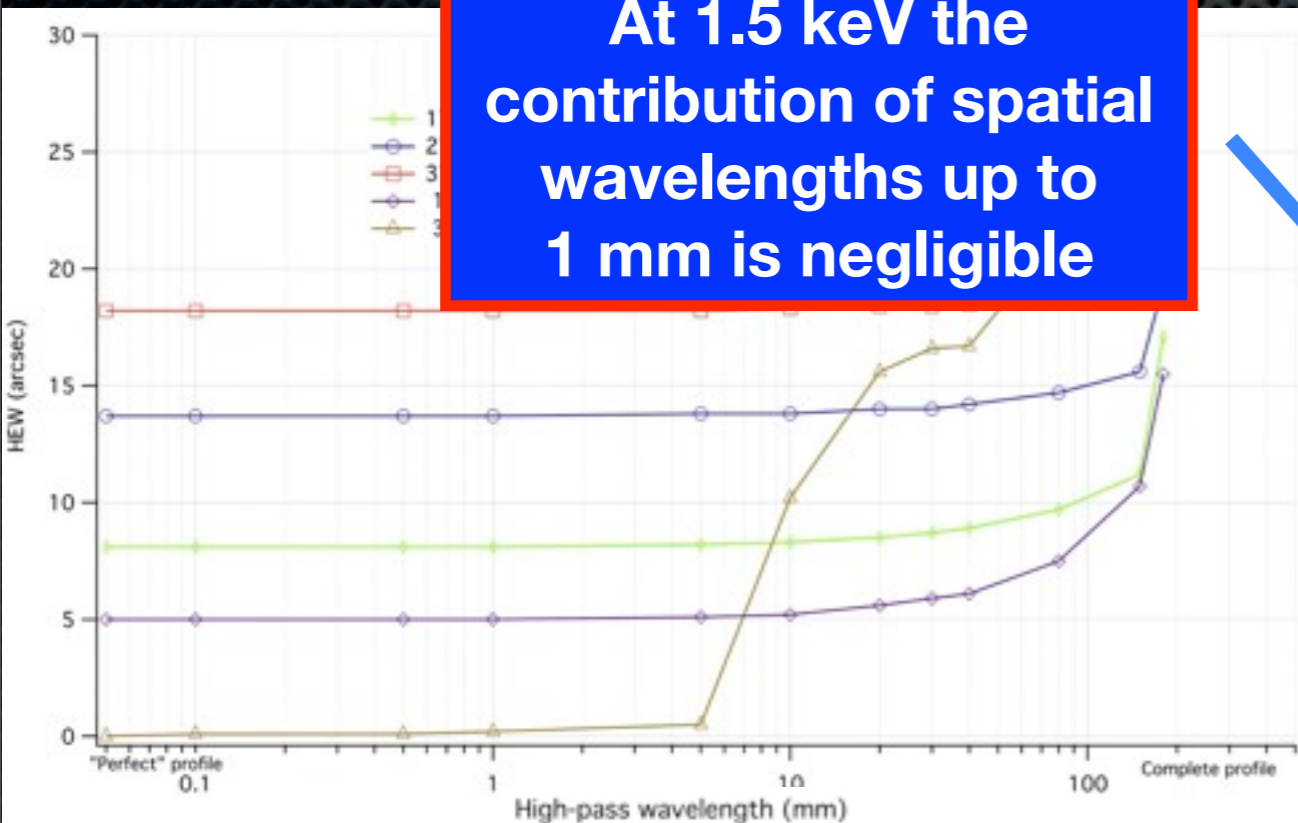


SLUMPED GLASSES PSF ANALYSIS

HEW BEHAVIOR WITH ENERGY

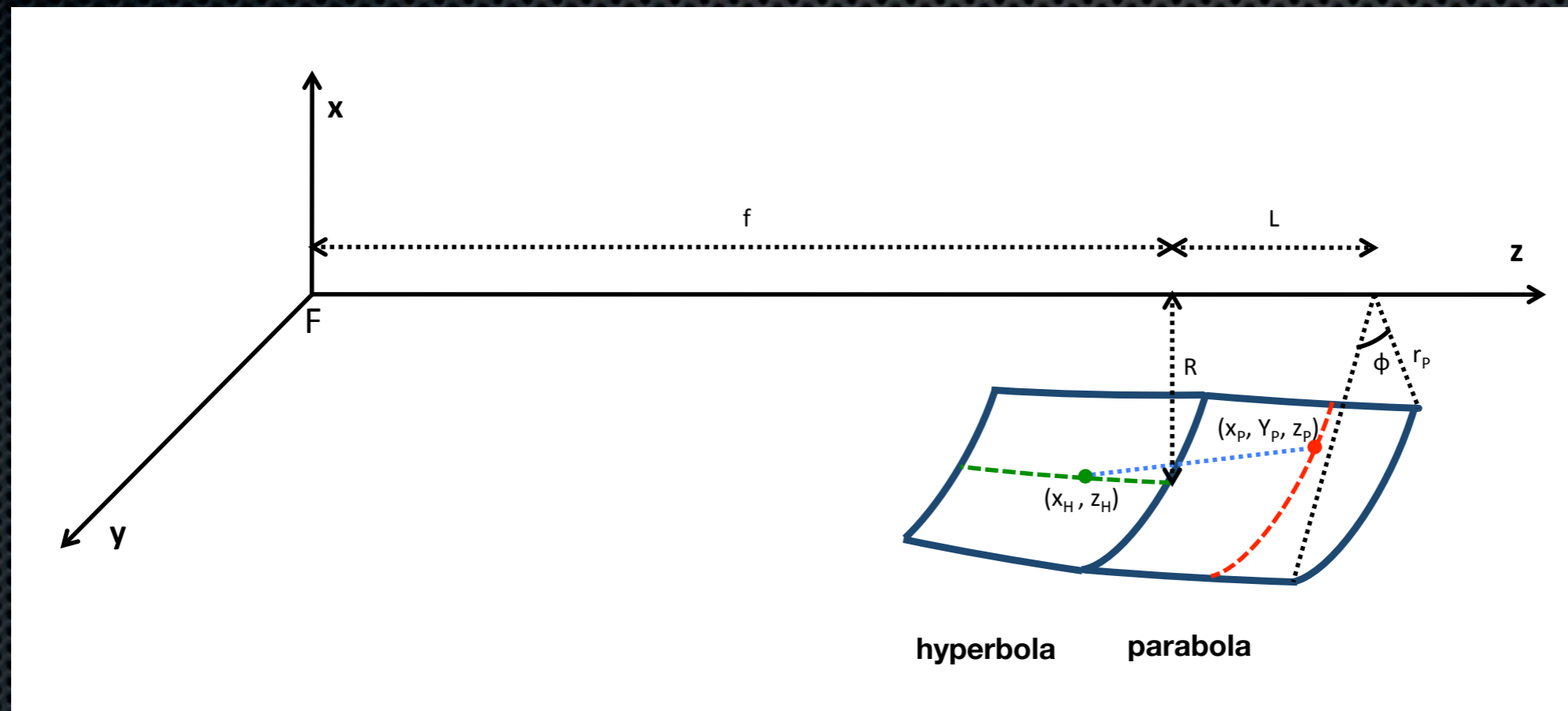
Analysis of different spatial wavelength ranges impact on PSF degradation

At 1.5 keV the contribution of spatial wavelengths up to 1 mm is negligible



This analysis should allow us to understand at which spatial wavelength scale an active X-ray optic system should operate to obtain the best efficiency

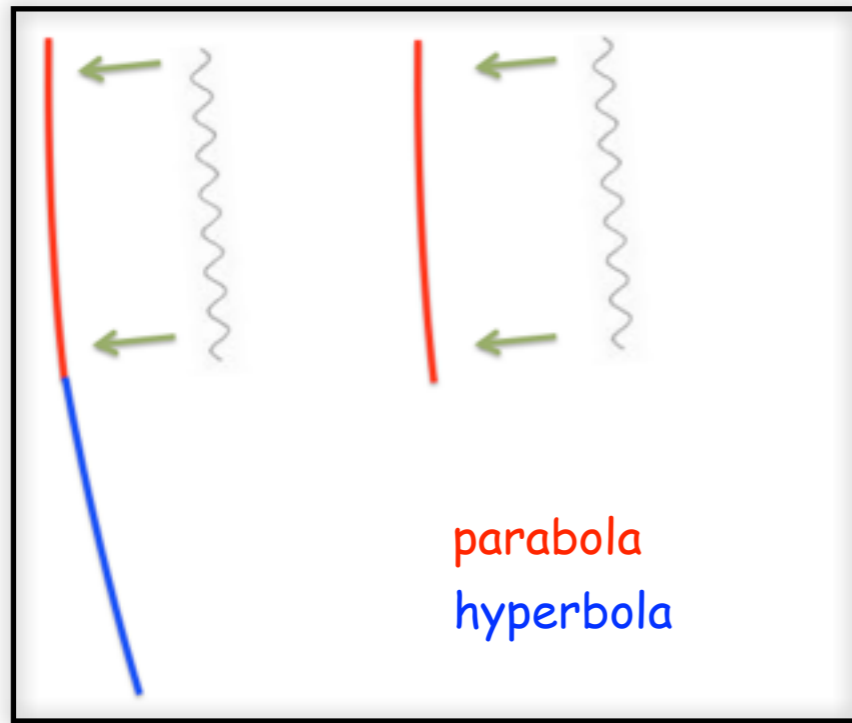
DOUBLE REFLECTION PSF COMPUTATION: WOLTER-I CONFIGURATION



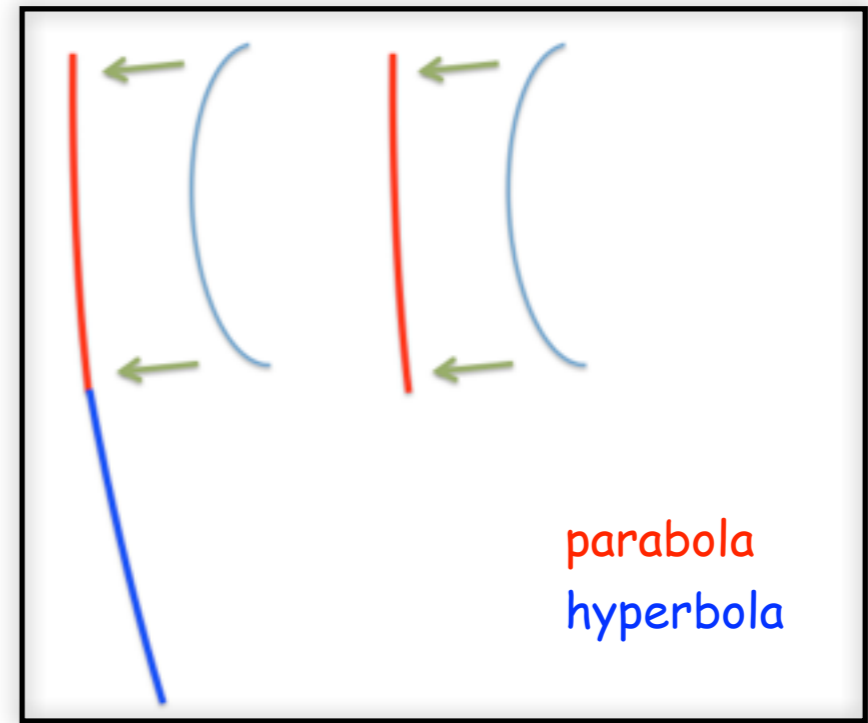
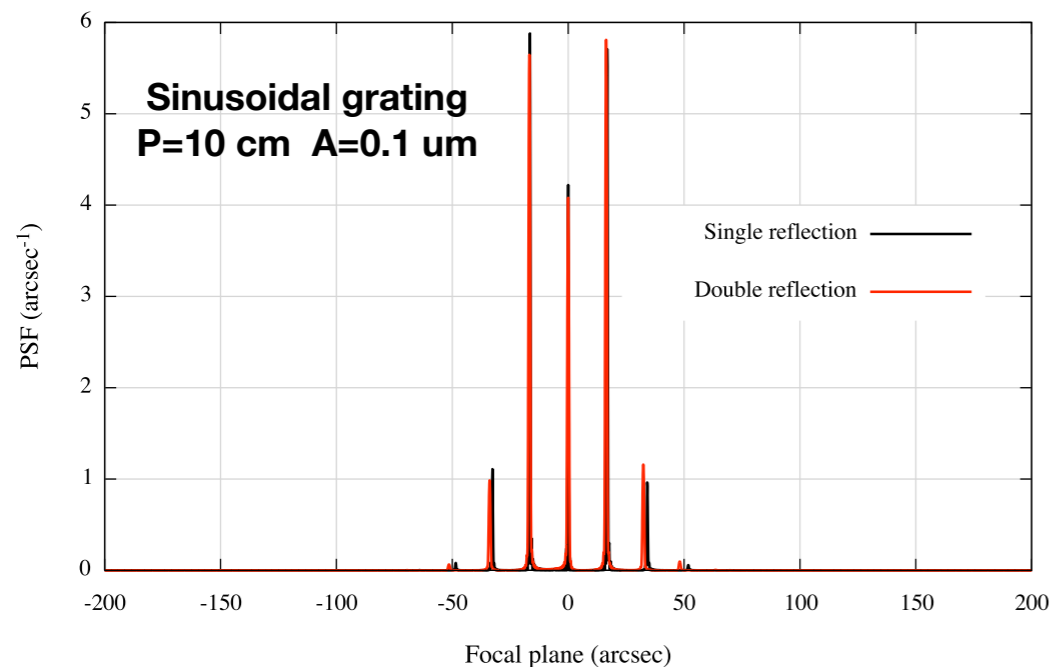
Wolter-I configuration

- reduction of the coma aberration
- to shorten the focal length

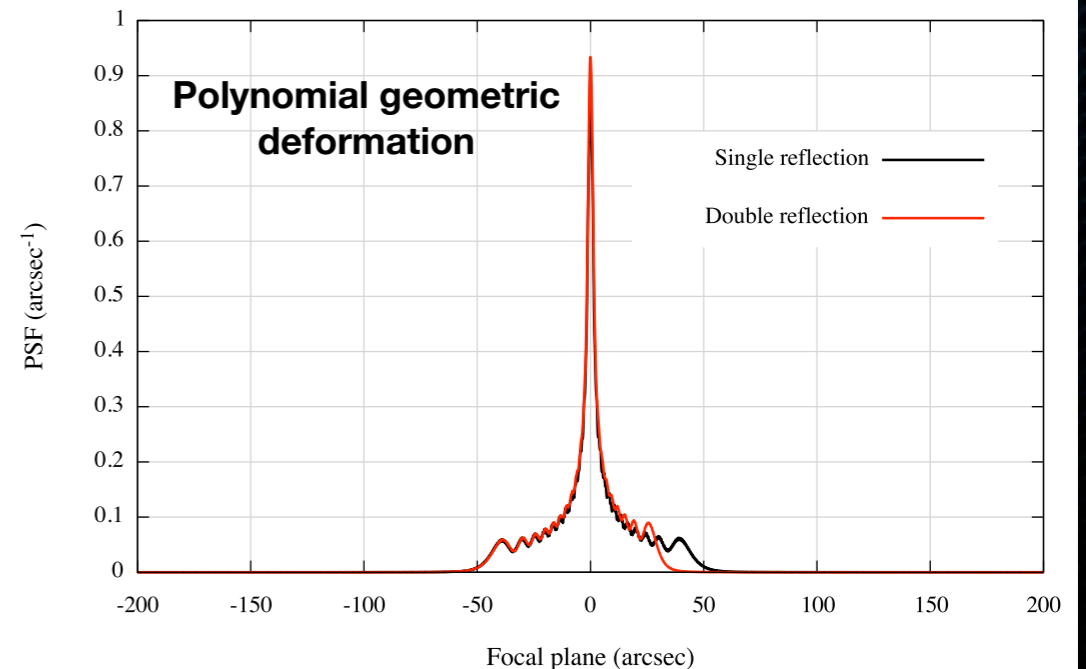
DOUBLE REFLECTION PSF COMPUTATION: WOLTER-I CONFIGURATION



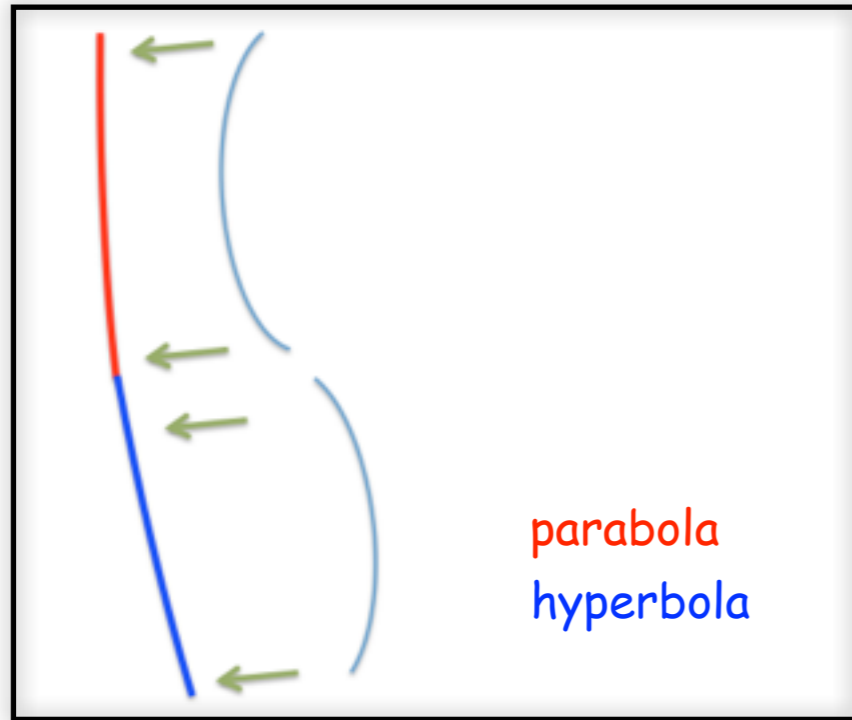
PSF Wolter-I and parabola comparison at 0.4 keV



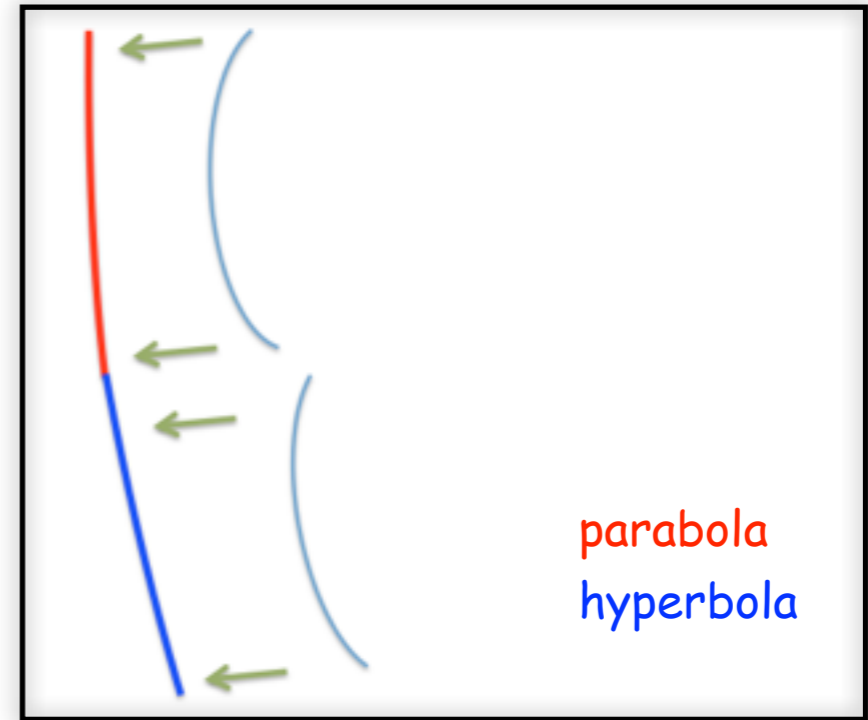
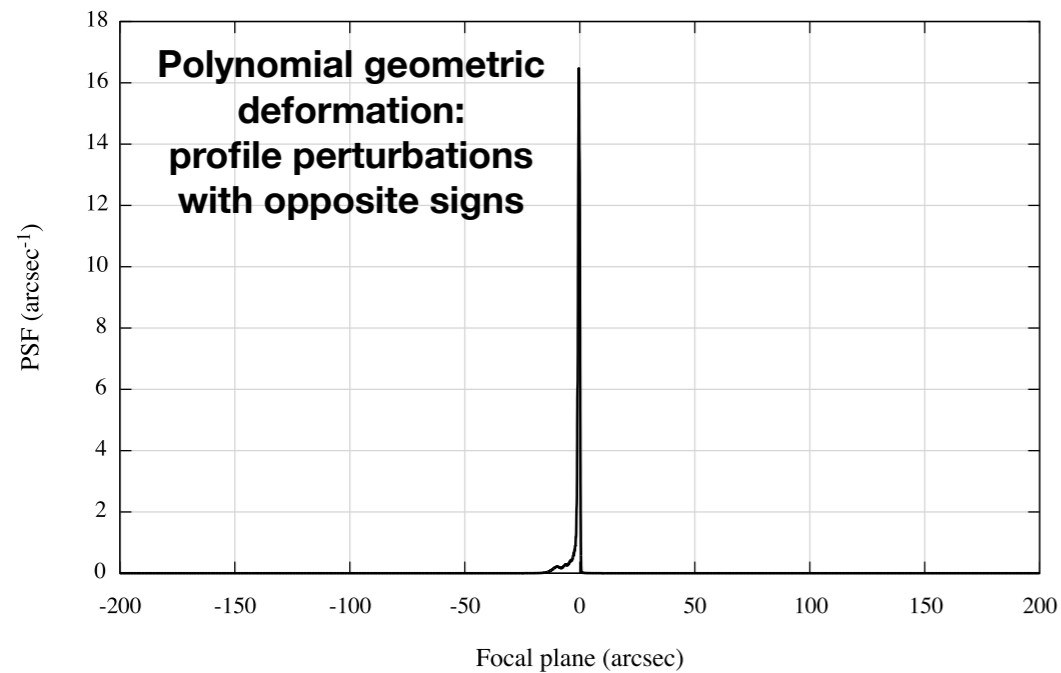
PSF Wolter-I and parabola comparison at 0.4 keV



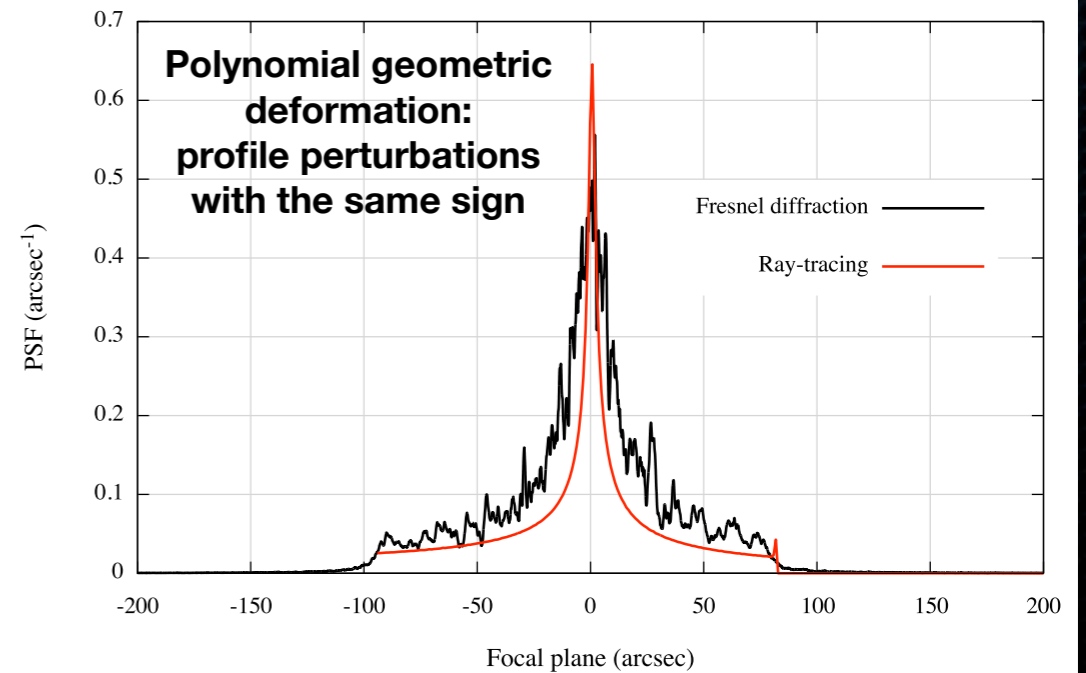
DOUBLE REFLECTION PSF COMPUTATION: WOLTER-I CONFIGURATION



PSF Wolter-I at 1 keV



PSF Wolter-I at 1 keV



CONCLUSIONS

- We have applied a self-consistent method to obtain the PSF from the X-ray mirror metrology data, at ANY energy, without setting any geometrical optics/roughness boundary
 - The method is consistent with the ray-tracing (at energies, where a posteriori, the geometrical optics can be applied) and with the behavior of the HEW increase obtained from the X-ray scattering analytical approach
 - The separate contributions to the HEW from the geometrical profile and from the microroughness, when summed, are close to the total HEW (TBC)
 - This approach allows to assess the impact of different spatial wavelengths on the mirror PSF and to understand at which spatial scale an active X-ray optic system should operate for the best efficiency, depending on λ .
 - This method is easily extendable to the double reflection case, widespread in X-ray telescopes.

THANKS